

The Static and Dynamic Characterization
of the MC68HC11A8's Analog to Digital Converter/

by

Jeffrey Charles Daniels

B.S, Kansas State University, 1984

A MASTER'S THESIS

submitted in partial fulfillment of the
requirements for the degree

MASTER OF SCIENCE

Department of Electrical and Computer Engineering

KANSAS STATE UNIVERSITY
Manhattan, Kansas


1988

Approved by:



Major Professor

Table of Contents

List of Figures		. iii
List of Tables vii
Acknowledgments	All210 359266	viii
1.0 Introduction		1
2.0 The Testing System		3
3.0 Theory of Operation of the HC11's A/D		9
Single Channel Operation		12
Multiple Channel Operation		13
Scan Control		13
Using the A/D		13
4.0 Static Testing of the HC11's A/D		15
Testing Procedure		15
Method 1		17
Method 2		18
Method 3		18
5.0 Static Testing Results		20
Method 1		20
Method 2		24
Method 3		25
Conclusion		47
6.0 Dynamic Testing of the HC11's A/D		48
Testing Procedure		50
Method 1		51
Method 2		53
7.0 Dynamic Testing Results of the HC11's A/D		57
Method 1		58
Method 2		67
Conclusion		73
8.0 Summary and Recommendations		74
Appendix A		A-1
Appendix B		B-1
Appendix C		C-1
References		R-1

LD
 2668
 .T4
 ECE
 1988
 D36
 c.2

List of Figures

Figure 2-1.	Static and Dynamic Testing Configuration .	4
Figure 2-2.	Interface Board Configuration	6
Figure 2-3.	Precision Voltage Reference Circuit . . .	8
Figure 3-1.	A/D Control/Status Register	11
Figure 4-1.	Static Testing System	16
Figure 5-1.	Transfer Functions of A/D in four conversion, single input, input channel 1. Checking state of CCF bit	21
Figure 5-2.	Transfer Functions of A/D in four conversion, single input, input channel 1. Checking state of CCF bit	22
Figure 5-3.	Transfer Functions of four HCLIs in four conversion, single input, input channel 1. Checking state of CCF .	23
Figure 5-4.	Transfer Functions of A/D in four conversion, single input, input channel 1. Executing long delay	26
Figure 5-5.	Transfer Functions of A/D in four conversion, single input, input channel 1. Executing long delay	27
Figure 5-6.	Total errors of the A/D using the four conversion, single input, input channel 1 mode	29
Figure 5-7.	Total errors of the A/D using the four conversion, multiple input mode . .	30
Figure 5-8.	Total errors of the A/D using the continuous conversion, single input, input channel 1 mode	31
Figure 5-9.	Total errors of the A/D using the continuous conversion, multiple mode . .	32
Figure 5-10.	Differential non-linearity errors of the A/D using the four conversion, single input, input channel 1 mode . . .	34

Figure 5-11.	Differential non-linearity errors of the A/D using the four conversion, multiple input mode	35
Figure 5-12.	Differential non-linearity errors of the A/D using the continuous conversion, single input, input channel 1 mode	36
Figure 5-13.	Differential non-linearity errors of the A/D using the continuous conversion, multiple mode	37
Figure 5-14.	Histogram integral non-linearity errors of the A/D using the four conversion, single input, input channel 1 mode	38
Figure 5-15.	Histogram integral non-linearity errors of the A/D using the four conversion, multiple input mode	39
Figure 5-16.	Histogram integral non-linearity errors of the A/D using the continuous conversion, single input, input channel 1 mode	40
Figure 5-17.	Histogram integral non-linearity errors of the A/D using the continuous conversion, multiple mode	41
Figure 5-18.	End Point integral non-linearity errors of the A/D using the four conversion, single input, input channel 1 mode	43
Figure 5-19.	End Point integral non-linearity errors of the A/D using the four conversion, multiple input mode	44
Figure 5-20.	End Point integral non-linearity errors of the A/D using the continuous conversion, single input, input channel 1 mode	45
Figure 5-21.	End Point integral non-linearity errors of the A/D using the continuous conversion, multiple mode	46
Figure 6-1.	Dynamic Testing System	49
Figure 6-2.	Harmonics of the DFT Window 1406.25 Hz sine wave sampled at 4000 Hz	55

Figure 6-3.	Spectrum for an ideal 8-bit A/D 1406.25 Hz sine wave sampled at 4000 Hz	57
Figure 7-1.	Histogram data and Differential non-linearity errors for A/D. Four conversion, single input, input channel 1. RC timer disabled	59
Figure 7-2.	Histogram data and Differential non-linearity errors for A/D. Four conversion, single input, input channel 1. RC timer enabled	60
Figure 7-3.	Histogram data and Differential non-linearity errors for A/D. Four conversion, multiple input. RC timer disabled	61
Figure 7-4.	Histogram data and Differential non-linearity errors for A/D. Four conversion, multiple input. RC timer enabled	62
Figure 7-5.	Histogram data and Differential non-linearity errors for A/D. Continuous-conversion, single input, input channel 1. RC timer disabled	63
Figure 7-6.	Histogram data and Differential non-linearity errors for A/D. Continuous-conversion, single input, input channel 1. RC timer enabled	64
Figure 7-7.	Histogram data and Differential non-linearity errors for A/D. Continuous-conversion, multiple input. RC timer disabled	65
Figure 7-8.	Histogram data and Differential non-linearity errors for A/D. Continuous-conversion, multiple input. RC timer enabled	66
Figure 7-9.	Fourier Transform Results of A/D. Four-conversion, single input, input channel 1	68
Figure 7-10.	Fourier Transform Results of A/D. Four-conversion, multiple input	69

Figure 7-11.	Fourier Transform Results of A/D. Continuous-conversion, single input, input channel 1	70
Figure 7-12.	Fourier Transform Results of A/D. Continuous-conversion, multiple input . .	71
Figure C-1.	Transfer function of an ideal 3-bit A/D	C-1

List of Tables

Table 3-1.	Analog to Digital Channel Assignments . . .	12
Table 6-1.	Location of Harmonics in the Frequency window	54

Acknowledgments

My gratitude goes to Motorola Semiconductor Group for funding this project and to the Department of Electrical and Computer Engineering for their patience and understanding to help the completion of this project come to an end. Special thanks goes to Dr. Lenhart for his guidance and prodding to get the spoken words down on paper in an understandable form. Most of all, I would like to thank my parents for their teachings which gave me the will to make it though graduate school, my wife who gave me the reason why, and finally my son whose learning mind gave hope and promise for all good things to come.

1.0 Introduction

Automated test equipment for integrated circuit (IC) manufacturing in mass production applications is expensive to purchase and to maintain. This expense contributes to the proportionality between the cost of an IC and its testing time. As ICs become more complex, as with the case of microprocessors, it soon becomes cost prohibitive to test all combinations of inputs, outputs, and functions available.

Motorola has developed a fast, low power microcomputer, the MC68HC11A8 (HC11), which has an elaborate timer system, two serial communications interfaces, parallel input/output (I/O) configurations, and a unique feature of an onboard 8 bit, successive approximation analog to digital converter (A/D) with sample and hold.¹ The HC11 has endless possibilities for control applications using its timer system, serial communication interfaces, I/O configurations, and its eight bit A/D. One control application and a more in-depth description of the HC11 is outlined in Draving⁴ where the HC11 is used as a controller for low power, precision A/D converters.

For an A/D used in a critical application, extensive testing is necessary to ensure conversion results to be within the manufacturer's specifications. As stated by Doerfler², testing of even low resolution A/Ds can take

several hours to complete. This presents a problem for Motorola. To keep the HC11 at a competitive price, testing time must be kept to a minimum thus eliminating the possibility of extensive testing its A/D. The purpose of this thesis is to statically and dynamically characterize the HC11's A/D and to present the testing procedures used in this characterization.

2.0 The Testing System

In order to test the HC11's A/D, a test system was developed consisting of a M68HC11EVB evaluation board (EVB), an interface board, a Hewlett Packard (HP) 9845B computer with a parallel interface, an IBM PCXT equipped with a modified (pull up resistors on inputs and outputs) 24 bit Parallel Digital I/O Interface Model PIO12 Metabyte board, an HP 3878A digital voltage meter (DVM), an HP 3325A function generator, and an eighteen bit digital to analog converter (DAC) as shown in figure 2-1.

The EVB is a small, compact, low cost tool for development of HC11 based target system equipment.⁵ This board provides host computer down loading capabilities which allows the use of a cross assembler running on an IBM PCXT, eight kilobytes (8k) of user RAM, 8k of EPROM, and a monitor/debugging program called BUFFALO (Bit Users Fast Friendly Aid to Logical Operations). The EVB provides access to all 52 pins of its HC11 via a 60 conductor flat ribbon cable.

The EVB is well suited for the testing system in figure 2-1 except for the lack of a bypass capacitor on the HC11's power and ground pins. This problem was corrected by the installation of a 10uF, tantalum capacitor across the HC11's V_{DD} and V_{SS} pins on the underside of the EVB board.

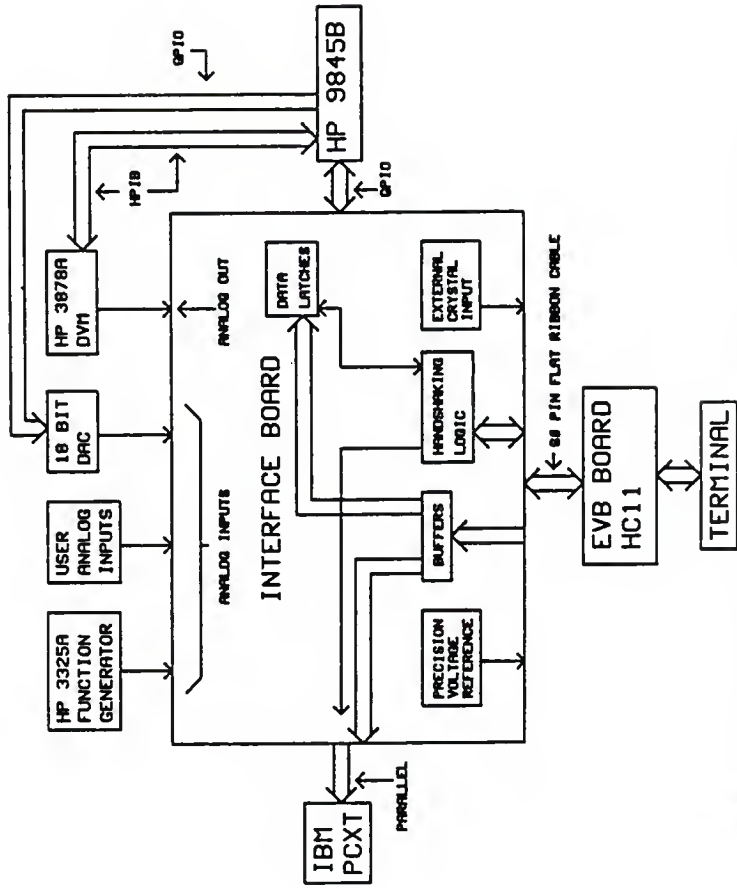
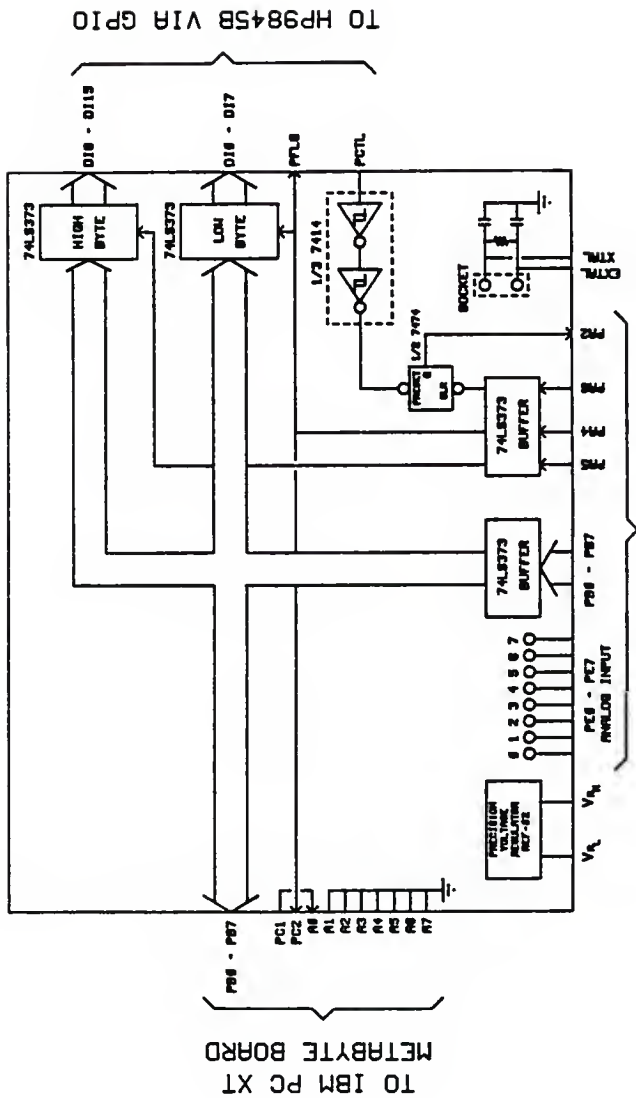


Figure 2-1. Static and Dynamic Testing Configuration

The interface board of the test system, shown in figure 2-2, provides buffering for the HC11's inputs and outputs, data latches, handshaking logic to the HP 9845B, a stable voltage reference for the V_{RH} input, and a circuit to provide an external source for the HC11's EXTAL and XTAL pins to allow the user to lower the standard operating frequency of the EVB.

The buffers are used to protect the HC11 from being overdriven thus causing possible damage. 74HC373 uni-directional 8 bit data latches were chosen for the buffers and also the data latches on the interface board. Used as buffers, the 74HC373s were operated in transparent mode to allow the outputs to follow the inputs with no need for a clock input. The 74HC373s used as data latches on the interface board used a pulse output from a pin (PA4) on the HC11's PORTA to set and hold the data to be read by the HP 9845B or IBM PCXT. Figure 2-2 shows high and low byte data latches although the only use for the high byte is to establish 0's on the top eight data lines on the GPIO interface.

The handshaking logic between the HC11 and HP 9845B is a 7474 D flip flop with preset and clear inputs. The HC11 waits until the flip flop is set before sending data to the HP 9845B by latching the data into the data latches with a pulse on PA4 and clearing the D flip flop with a pulse on PA6. When a conversion result is latched into



TO MC68HC11 EVB BOARD

Figure 2-2. Interface Board Configuration

the latches, PA4 also pulses the HP 9845B to indicate valid data. When the HP 9845B wants data, it sets the flip flop and then waits for a pulse on its PFLG pin to accept the available data.

The handshaking method used with the IBM PCXT and the HC11 is simpler than that used with the HP 9845B. When the HC11 has data available, the conversion result is latched with a pulse being sent, via PA4, to the IBM PCXT. For the IBM PCXT to receive data, it waits for a pulse from the HC11, takes the data and then waits for another pulse.

The HP 3878A DVM is controlled by the HP 9845B via an HPIB interface and is used to measure voltages and return the results to the HP 9845B for the analysis of testing results. The HP 3325A function generator is controlled manually by the user to provide a precision sine wave used as one of the analog inputs to the HC11's A/D. Also, an 18 bit DAC, built and tested to 16 bit linearity by Holdeman⁶, provides a ramp input to the HC11's A/D. A precision voltage reference shown in figure 2-3, provides a stable voltage of +5 volts to be used as the input of V_{RH} pin on the HC11. Finally, the clock frequency of the EVB can be changed by changing a jumper on the EVB and placing a suitable crystal on the interface board.

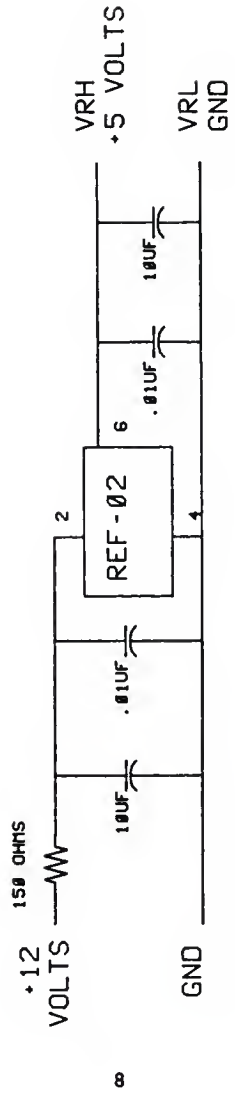


Figure 2-3. Precision Voltage Reference Circuit

3.0 Theory of Operation of the HC11's A/D¹

The A/D provides ten inputs to the user, of which, eight are analog inputs (AN0 - AN7) with two being dedicated for use as reference voltages (V_{RL} and V_{RH}). The voltage range for V_{RL} and V_{RH} is zero and five volts respectively. Motorola documentation states that the A/D is ratiometric. This implies that an analog input equal to V_{RH} converts to \$FF (full scale) and an input equal to V_{RL} converts to \$00, with no over or under flow indication.

The A/D is clocked by one of two sources, the HC11's E clock or an internal RC oscillator. With the E clock rate greater than 1 MHz, each A/D conversion is accomplished in thirty two E clock cycles. For E clock rates less than 1 MHz, the A/D is designed to be clocked by the internal RC oscillator enabled by setting a bit (CSEL) in the OPTION register. The RC timer, when enabled, operates at about 1.5 MHz.

In a small period of time, 128 E clock cycles, the A/D can perform four conversions on user specified analog inputs, either AN0 - AN3 or AN4 - AN7. The four conversion results are placed in four A/D Result Registers, ADRL through ADR4. The first conversion is placed in ADRL, the second in ADR2 and so on. The A/D conversion process is initiated by a write to the A/D Control/Status Register (ADCTL) with valid results in ADRL in 32 E clock cycles,

ADR2 in 64, ADR3 in 96, and ADR4 in 128. Each time a conversion is initiated, the A/D system performs four conversions and then stops or continues depending upon its configuration.

Control of the inputs to the A/D is determined by the configuration of the A/D Control/Status Register (ADCTL). Figure 3-1 displays the ADCTL and its description.

B7	B6	B5	B4	B3	B2	B1	B0
CCF	-	SCAN	MULT	CD	CC	CB	CA

- Bit 7, CCF Conversion Complete Flag - This bit is a read only status indicator that becomes set when all Result Registers contain valid results. When a conversion is initiated, by a write to ADCTL, this bit is cleared automatically and then becomes set when valid results are found in the Result Registers.
- Bit 6, Not implemented. Reads as zero.
- Bit 5, SCAN Continuous Scan Control - With this bit cleared, the A/D performs four conversions and places the results in the Result Registers. When this bit is set, the A/D performs conversions in a round robin fashion with the Result Registers being updated as data becomes available.
- Bit 4, MULT Multiple Channel/Single Channel Control When this bit is cleared, the A/D is configured to perform four consecutive conversions on a single input channel as specified by the four channel bits in the ADCTL, CA through CD (bits 0-3). When this bit is set, the A/D is configured to perform a conversion on each of four channels with each Result Register corresponding to one channel.
- Bit 3, CD Channel Select D
- Bit 2, CC Channel Select C
- Bit 1, CB Channel Select B
- Bit 0, CA Channel Select A - These four bits select one of sixteen possible analog inputs to the A/D. Of these sixteen, only eight are available to the user for external inputs. When the multiple input mode is selected, Bit 4, MULT is set, the two least significant bits, CB and CA have no meaning because a group of four channels are each converted once with their results placed in the Result Registers. Table 3-1 summarizes the input channels selected by the channel select bits.

Figure 3-1. A/D Control/Status Register (ADCTL)

CD	CC	CB	CA	Channel Signal	Result in ADRx if MULT = 1
0	0	0	0	AN0	ADR1
0	0	0	1	AN1	ADR2
0	0	1	0	AN2	ADR3
0	0	1	1	AN3	ADR4
0	1	0	0	AN4	ADR1
0	1	0	1	AN5	ADR2
0	1	1	0	AN6	ADR3
0	1	1	1	AN7	ADR4
1	0	0	0	Reserved	ADR1
1	0	0	1	Reserved	ADR2
1	0	1	0	Reserved	ADR3
1	0	1	1	Reserved	ADR4
1	1	0	0	V _{RH} Pin	ADR1
1	1	0	1	V _{RL} Pin	ADR2
1	1	1	0	V _{RH} /2	ADR3
1	1	1	1	Reserved	ADR4

Table 3-1. Analog to Digital Channel Assignments

By analyzing Table 3-1, it appears that the A/D system has sixteen inputs with four control lines. Actually, the A/D does have sixteen analog inputs of which only eight are user inputs. The last four shown in Table 3-1 are internal reference points with the prior four being reserved for future use.

Single Channel Operation

Single channel operation is accomplished by clearing bit 4 of the ADCTL. This configuration causes the A/D to perform four conversions of a single input channel selected by the four Channel Select bits (CD - CA) and place the results in the four Results Registers.

Multiple Channel Operation

Multiple channel operation is accomplished by setting bit 4 of the ADCTL. This configuration causes the A/D to perform four conversions of the group of four input channels selected by the Channel Select bits CD and CC. In this configuration the Channel Select bits CB and CA have no meaning.

Scan Control

The Scan configuration refers to how many A/D conversions are performed after a write to the ADCTL. By clearing bit 5 of the ADCTL, the A/D is configured to perform four conversions and then stop all activity. With bit 5 set, the A/D performs conversions continually with new conversion results being placed in the Result Registers as they become available.

Using the A/D

To use the A/D converter, it must be supplied power. This power up procedure is accomplished by setting bit 7 of the OPTION Register. To set up a mode of operation for the A/D and to initiate a conversion, a write to the ADCTL is necessary. After a period of time, two methods are possible to ensure that valid results are found in the Result Registers. If E clock frequencies are greater than 1 MHz and the RC oscillator is not enabled, the user can just execute a delay loop until 128 E clock cycles have passed. This, according to Motorola specifications, is

the time required for all Result Registers to contain valid results. Also, once the conversion is initiated, a loop that checks the CCF bit and exits on its high state will ensure valid conversion results exist. If the A/D is clocked by the RC oscillator, regardless of E clock frequency, the method for checking for valid results is the bit test of the CCF or with a very long delay loop (> 128 microseconds).

4.0 Static Testing of the HC11's A/D

The system configuration used to test the HC11's A/D with static inputs is shown in figure 4-1. The basic procedure for most static testing methods has the HP9845B tell the 18 bit DAC to setup a constant output voltage to the interface board, have the DVM measure the voltage and return the result, and finally tell the HC11 to perform an A/D conversion and return the result. This loop continues until the amount of data desired is collected. Finally, the calculation of errors is performed on the HP9845B and then plotted if desired. The software for all three static testing methods for the HP9845B and HC11 are shown in Appendix A.

Testing Procedure

Three preliminary testing methods for static analog input conditions were developed and used in obtaining data presented in this thesis. These procedures were repeated in different operational modes of the HC11's A/D and at different E clock frequencies.

A mode of operation is defined as the byte, in Hex, which is written to the ADCTL to initiate an A/D conversion. Four mode combinations were used in collecting data for this thesis. The modes are:

- four-conversion, single input, input channel 1 (01),
- four-conversion, multiple input (10),
- continuous-conversion, single input, input channel 1 (21),
- continuous-conversion, multiple input (31).

For example, a four-conversion, single input, input

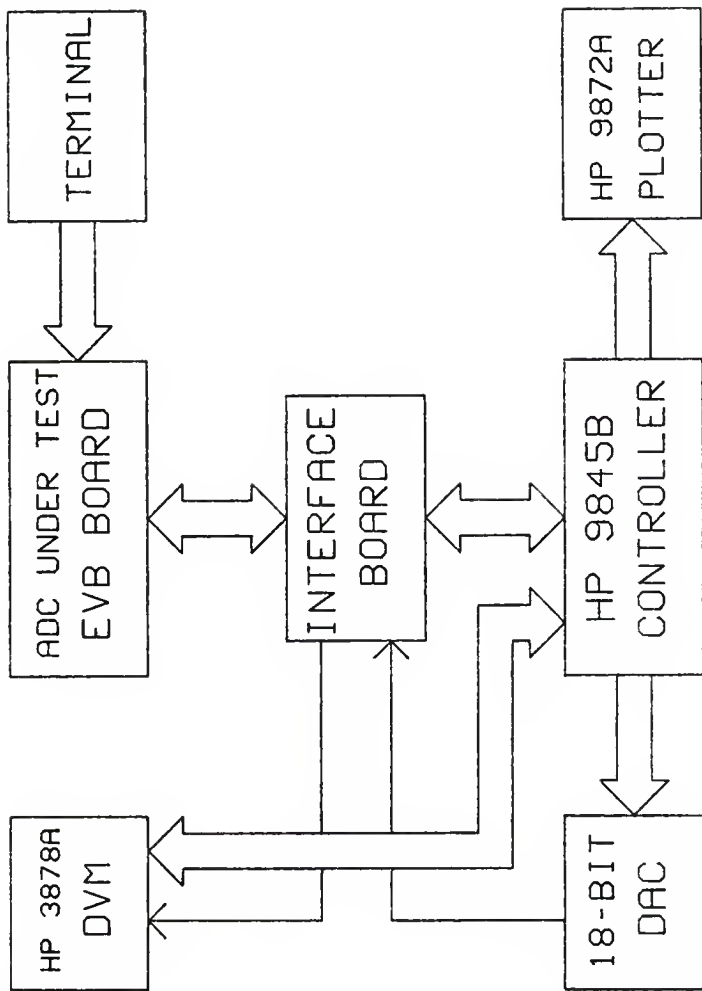


Figure 4-1. Static Testing System

channel 1 (01) mode, configures the A/D system to convert the analog signal found at AN1 four times and place the results in the Result Registers (ADR1 - ADR4). With four-conversion, multiple input (10), as the mode, the A/D system converts the analog signal at AN0 with the result being placed in ADR1, the conversion of AN1 in ADR2, AN2 in ADR3, and AN3 in ADR4. The two other modes used in testing, continuous-conversion, single input, input channel 1 (21) and continuous-conversion, multiple input (31), are similar to the 01 and 10 modes except that the A/D is configured to perform continuous conversions. Note that when multiple inputs are configured, the input channel is not specified in the description. These different modes are each used in the three methods used in static testing the A/D.

Method 1

This method uses a user specified mode for the HC11's A/D. The HC11 receives a signal from the HP, starts a conversion, waits until the CCF bit is set and then outputs the four Result Registers through the interface board to the HP for display purposes. The input signal used for this test was V_{RH} , +5 volts. The HP reads the DVM, signals the HC11, and then reads in four conversion results which are then displayed on the screen along with the DVM reading. This test continues until the user aborts it.

Method 2

This method is very similar to Method 1, except for the testing of the CCF. This method executes a long delay loop after a conversion is initiated. When the delay loop is completed, the HC11 transfers the contents of the Result Registers to the HP for screen display.

Method 3

This method consists of using a static histogram testing procedure developed by Doerfler.² This method uses the HP9845B to control an 18 bit Digital to Analog Converter (DAC), a precision digital voltage meter (DVM) along with receiving data from the HC11. The basic theory of this method is to increment the 18 bit DAC by one fourth of an HC11 least significant bit (LSB). Which is:

$$\text{LSB} = (V_{RH} - V_{RL}) / 2^{**}\text{Resolution}$$

where: V_{RH} is the high reference voltage
 V_{RL} is the low reference voltage
Resolution is the number of bits of the A/D converter.

For testing methods used in collecting data, an LSB for the HC11 equals 19.53 mV.

At each step of the 18 bit DAC, ten A/D conversions are performed with the conversion results used to construct a histogram. From this histogram, differential and integral non-linearity errors are estimated. Along with the histogram data, DVM readings are taken at each step to be used to calculate total errors. Offset and gain errors are calculated by a method that uses end point

transitions.³ These transitions are used to calculate the slope of the transfer function of the A/D. Also, this slope is used to adjust the DVM readings to remove gain and offset errors. Using the adjusted DVM readings, integral non-linearity errors are then calculated at the transition points of the A/D. Further explanation of this end point transition method is provided in Appendix C. Finally, a search of the data files is performed to find missing codes and non-monotonic behavior.

Of the two possible methods for checking for valid data in the Results Registers, checking the CCF bit and executing a sufficiently long delay, the data produced for this thesis for method 3 uses the check of the CCF bit to indicate when a conversion is complete.

5.0 Static Testing Results

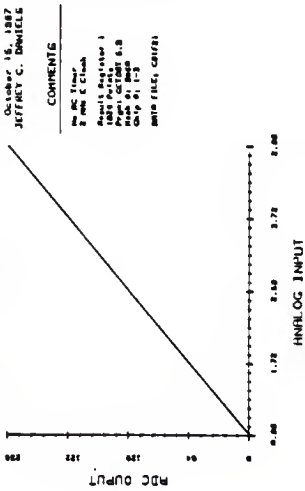
Exhaustive static testing of all the HC11s acquired has not been completed at this time, but several HC11s from different lots, from the mask B96D, have undergone the tests previously described. In the analysis that follows, errors of the HC11's A/D will usually be described in terms of an LSB.

Method 1

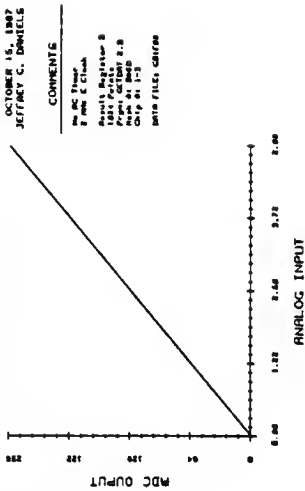
This method has the HC11 initiate an A/D conversion, checks for the high state of the CCF bit, and then outputs the contents of the Result Registers to the HP for display. The E clock frequency for this method was 2 MHz and the input voltage was V_{RH} , +5 volts. Four HC11s, provided by Motorola, were tested, and each produced similar results.

With the RC timer disabled, using the two, four-conversion modes (01 and 10), Result Register three showed errors in the range of 20 to 60 LSBs with the other Result Registers having the expected result of 255. The transfer functions of the A/D reading from the four Result Registers of the four-conversion, single input, input channel 1 (01) mode are shown in Figure 5-1 for a 2 MHz E clock and Figure 5-2 for a 500 kHz E clock. Readings from Result Register 3 from four other HC11s are shown in Figure 5-3. These figures clearly show the error in Result Register 3 in the form of a D.C. offset in the

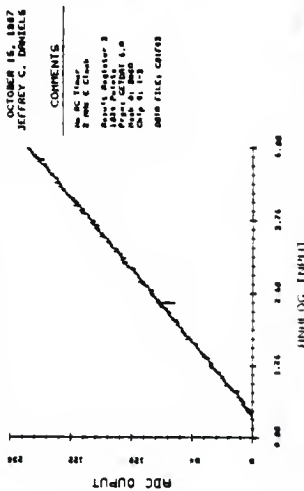
TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC

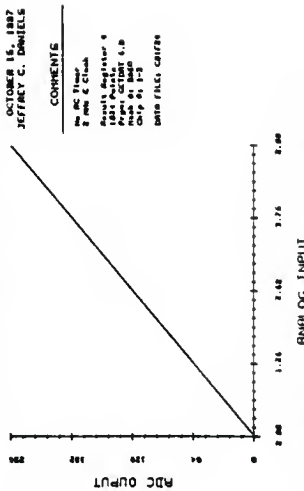
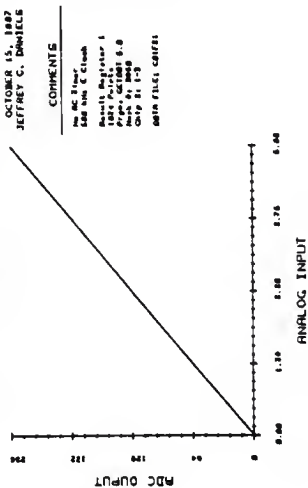
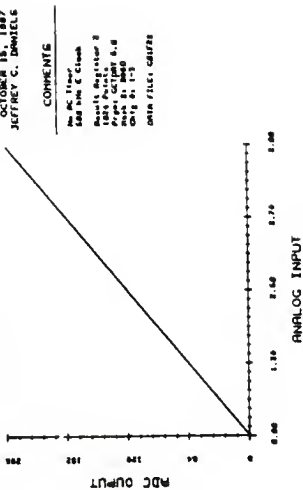


Figure 5-1. Transfer Functions of A/D in four conversion, single input, input channel 1. Checking state of CCP bit

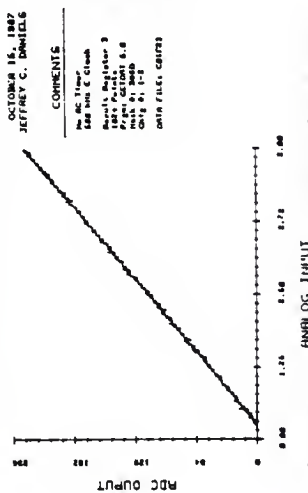
TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC

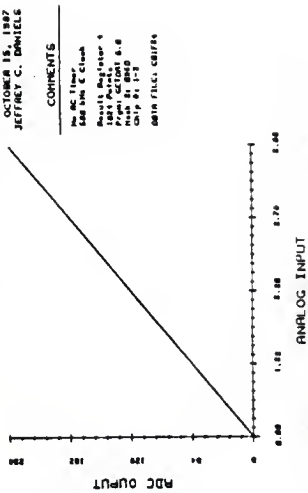
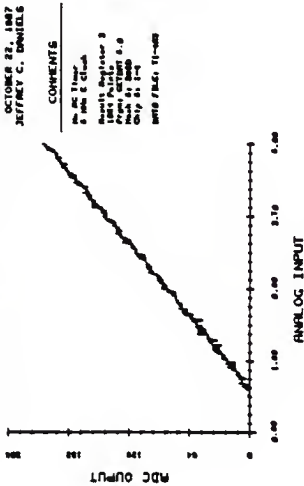
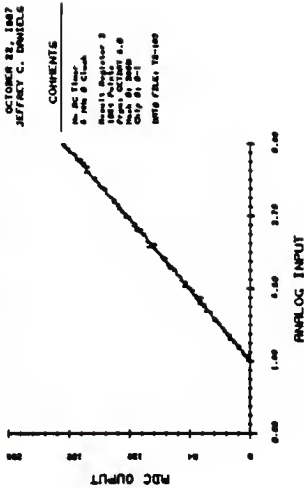


Figure 5-2. Transfer Functions of A/D in four conversion, single Input input channel 1. Checking state of CCF bit

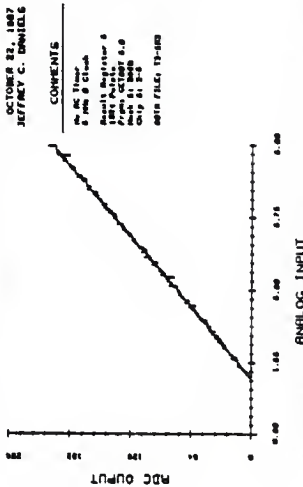
TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC

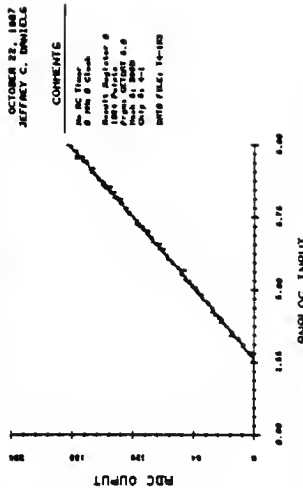


Figure 5-3. Transfer Functions of four HC11s in four conversion, single input, input channel 1. Checking state of CCC

input channel when the analog input is sampled for the conversion for Result Register 3 which varies for different HC11s. Also, as seen from comparing Figures 5-1 and 5-2, the D.C. offset becomes slightly smaller for lower E clock frequencies.

Continuous-conversion modes (21 and 31), had a solid 255 for Result Registers 1 and 3 but 2 and 4 displayed an erratic nature between 255 and a result ranging from 33 to 55 LSBs lower depending on which chip was tested. Also, there appeared to be no correlation in the errors between 2 and 4.

With the RC timer enabled, every mode tested displayed at least 1 or 2 LSBs of noise on all Result Registers. Large noise spikes were present but occurred only every few seconds. The Result Registers with the large noise spikes varied with different HC11s.

Method 2

This method, similar to method 1, executes a long delay after a conversion is started and then outputs four conversion results to the HP. The length used for the delay was 450 clock cycles. This length, according to specifications is over 3.5 times the length needed for Result Registers to contain valid results. For this method the E clock frequency was 2 MHz and 500 kHz with testing performed on several HC11s.

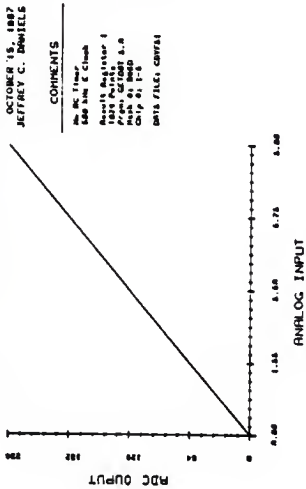
When the RC timer is disabled, the two, four-conversion modes (01 and 10), produced errors in Result Register 2 ranging from 12 to 72 LSBs depending on which chip was tested with the other Result Registers having the desired result of 255. The transfer functions of the A/D reading from the four Result Registers of the four-conversion, single input, input channel 1 (01) mode are shown in Figure 5-4 for a 2 MHz E clock and a 500 kHz E clock in Figure 5-5. These figures clearly show the error in Result Register 2 in the form of a D.C. offset that decreases slightly with E clock rates in the input channel when the analog input is sampled for the conversion for Result Register 2. In continuous-conversion modes (21 and 31), Result Registers 2 and 4 displayed a toggling action between 255 and a value between 183 and 236 with each HC11 being a different value.

With the RC timer enabled, noise was apparent on all outputs of at least 1 LSB with large noise spikes of up to 80 LSBs occurring occasionally in all modes with each HC11 having different characteristics.

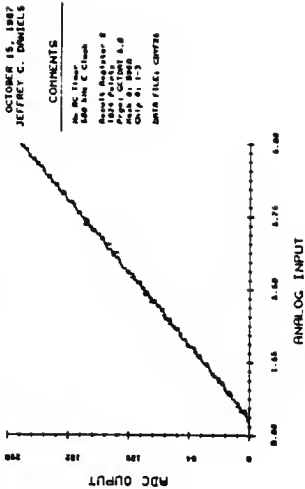
Method 3

This method determines total errors using a ramp input, differential and integral non-linearity errors using a histogram procedure², integral non-linearity errors, gain, and offset errors using an end point procedure³ and also the number of missing codes and occur-

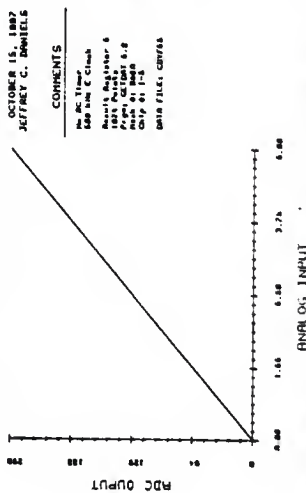
TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC



TRANSFER FUNCTION OF HC11 ADC

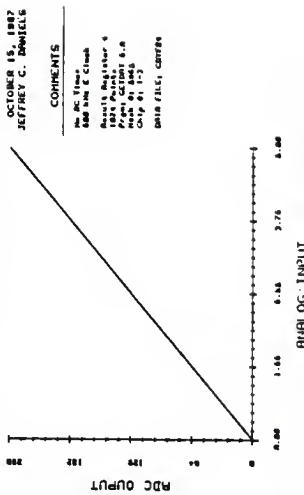


Figure 5-5. Transfer Functions of A/D in four conversions, single input, input channel 1. Executing long delay

rences of non-monotonic behavior. This method was tested on one HC11 with an E clock frequency of 2 MHz and 500 kHz with the RC timer enabled and disabled. Four A/D mode combinations used to test the A/D and produce the plots in Figures 5-6 through 5-21 were:

four-conversion, single input, input channel 1 (01),
four-conversion, multiple input (10),
continuous-conversion, single input, input channel 1 (21),
and continuous-conversion, multiple input (31).

Each figure contains plots of a single A/D mode configuration with the left plots corresponding to 2 MHz E clock rates and the right a frequency of 500 kHz. The only difference in the A/D configuration for top and bottom plots in each figure, is the RC timer is enabled in bottom plots and disabled in top plots.

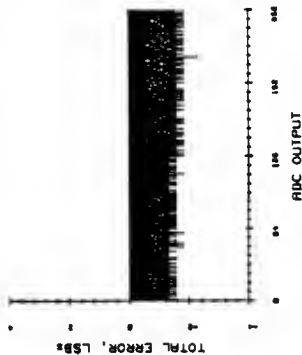
Total errors for the output of the A/D are shown in figures 5-6, 5-7, 5-8, and 5-9. The top plots (RC timer disabled) in these figures are all very similar in showing an offset of approximately -1 LSBs. The bottom plots (RC timer enabled) show an extreme presence of conversion result errors caused by the RC timer. These errors have magnitudes in excess of + or - 4 LSBs in some instances. The left plots, an E clock rate of 2 MHz, display larger total errors than the right plots, an E clock rate of 500 kHz. These factors imply that the magnitude of total errors has a strong correlation with increasing E clock rates and also whether the RC timer is enabled.

STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. SMITHS

COMMENTS

DC Input
5 Volts @ 100K
Resistor Register 1
256 Points
Mode 01 0000 0,0
Rate 01 0000 0,0
Ch10 01 1,0
Data File: mmg_0109

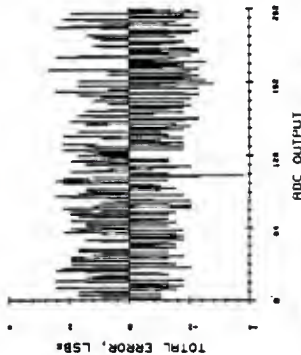


STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. SMITHS

COMMENTS

DC Input Grounded
5 Volts @ 100K
Resistor Register 1
256 Points
Mode 01 0000 0,0
Rate 01 0000 0,0
Ch10 01 1,0
Data File: mmg_0109

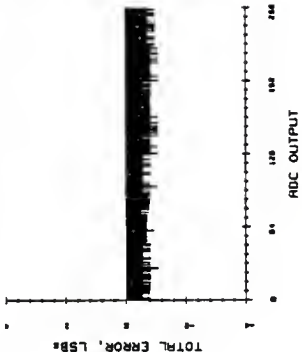


STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. SMITHS

COMMENTS

DC Input 5 Volts
5 Volts @ 100K
Resistor Register 1
256 Points
Mode 01 0000 0,0
Rate 01 0000 0,0
Ch10 01 1,0
Data File: mmg_0109



STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. SMITHS

COMMENTS

DC Input 5 Volts
5 Volts @ 100K
Resistor Register 1
256 Points
Mode 01 0000 0,0
Rate 01 0000 0,0
Ch10 01 1,0
Data File: mmg_0109

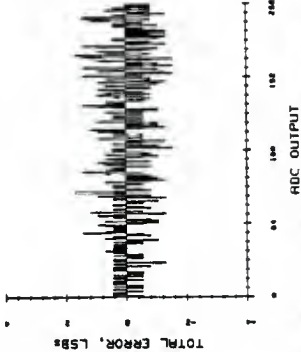
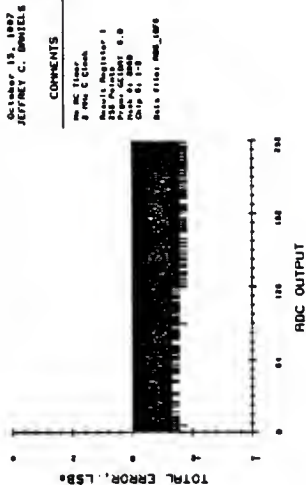
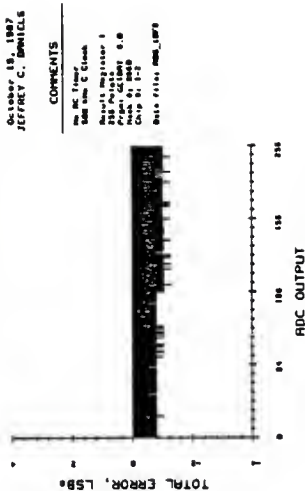


Figure 5-6. Total errors of the A/D using the four conversion, single input, input channel 1 mode.

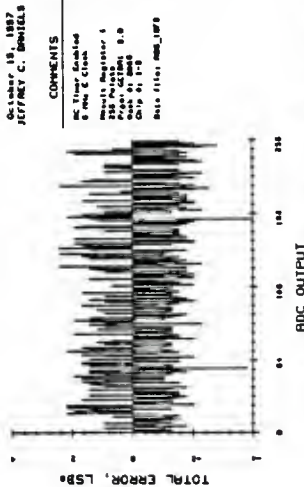
STATIC TEST OF HC11 RDC



STATIC TEST OF HC11 RDC



STATIC TEST OF HC11 RDC



STATIC TEST OF HC11 RDC

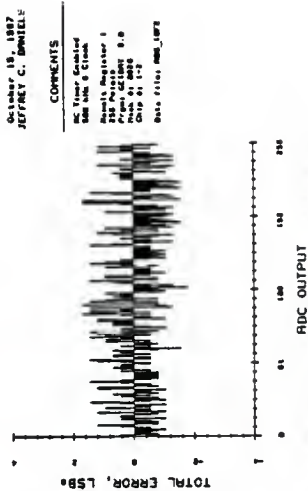
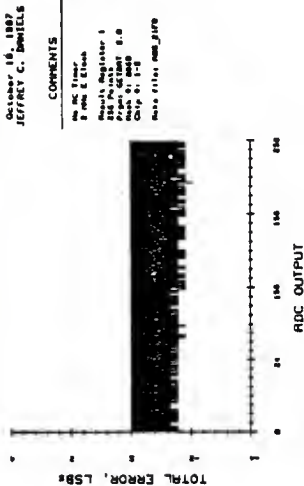
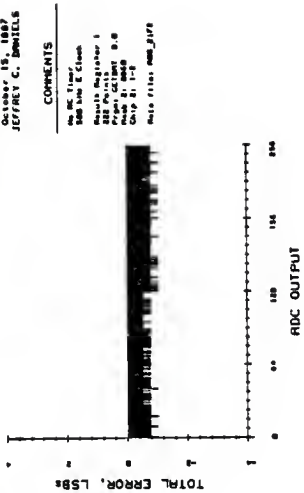


Figure 5-7. Total errors of the A/D using the four conversion, multiple input mode.

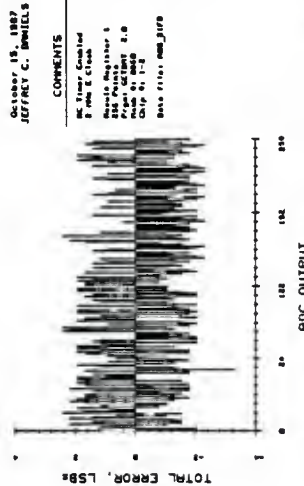
STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC

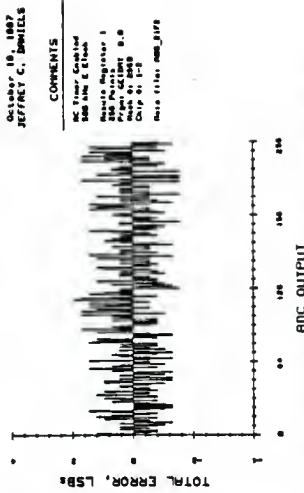


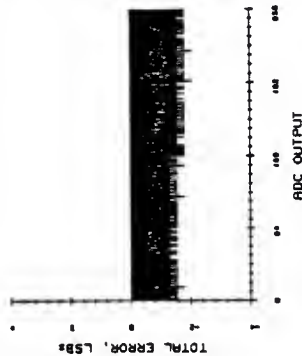
Figure 5-8. Total errors of the A/D using the continuous conversion, single input, input channel 1 mode.

STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. SMITHS

COMMENTS

HC 11 Eval
800 Vm, 5 Clock
Result Register 1
800 Prescaler 1
Power to 8000 0.0
Mode 01 100
Chip 01 1-0
Data File: mm_2199

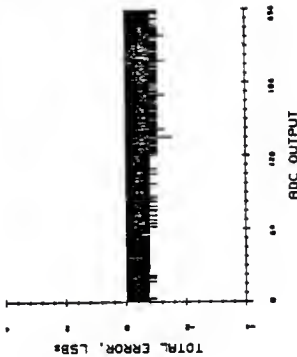


STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. SMITHS

COMMENTS

HC 11 Eval
800 Vm, 5 Clock
Result Register 1
800 Prescaler 1
Power to 8000 0.0
Mode 01 100
Chip 01 1-0
Data File: mm_2199

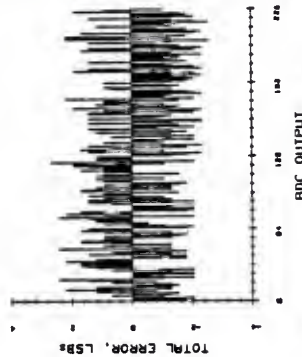


STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. SMITHS

COMMENTS

HC 11 Eval Eval
800 Vm, 5 Clock
Result Register 1
800 Prescaler 1
Power to 8000 0.0
Mode 01 100
Chip 01 1-0
Data File: mm_2199



STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. SMITHS

COMMENTS

HC 11 Eval Eval
800 Vm, 5 Clock
Result Register 1
800 Prescaler 1
Power to 8000 0.0
Mode 01 100
Chip 01 1-0
Data File: mm_2199

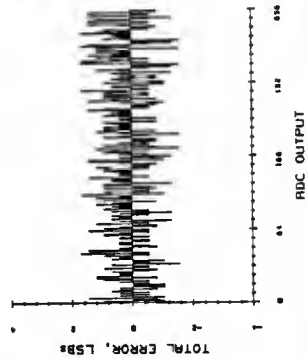
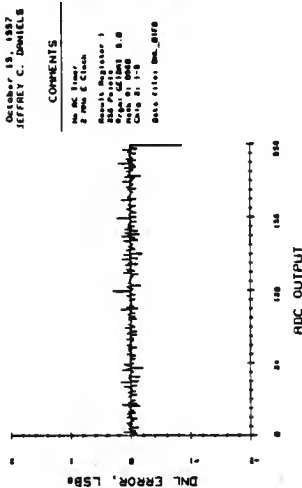


Figure 5-9. Total errors of the A/D using the continuous conversion, multiple mode.

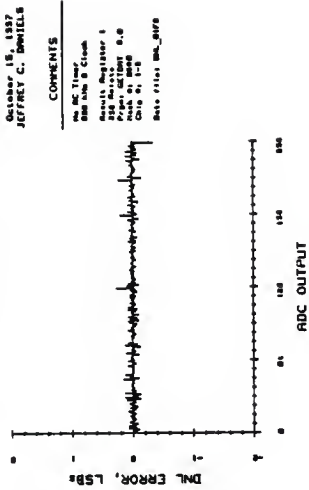
The number of occurrences of non-monotonic behavior was found by searching the total error data files. With the RC timer disabled (top plots), the number of occurrences of non-monotonic behavior was less than three in 1024 points using a ramp input between between 0 and 5 volts. With the RC timer enabled (bottom plots), non-monotonic behavior was apparent well over 300 times in 1024 points between 0 and 5 volts. This increase in non-monotonic behavior with the RC timer enabled over when the RC timer is disabled indicates the RC timer causes errors to occur in conversion results.

Histogram differential and integral non-linearity errors are shown in Figures 5-10 through 5-17. The top plots (RC timer disabled), the bottom plots (RC timer enabled), the left plots (2 MHz E clock), and the right plots (500 kHz E clock) show errors that fall well within Motorola specifications with only a slight increase in errors with the RC timer enabled and with higher E clock frequencies. However, it should be noted that the histogram procedure uses many data points in differential and integral non-linearity error calculations. Using many data points causes the noise to be averaged out, thus allowing the test to be of the actual A/D transition points. These eight figures (5-10 through 5-17), show that the A/D has transition points within specifications

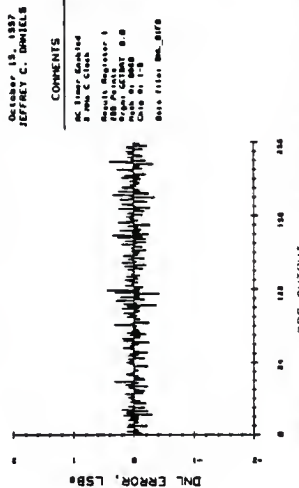
STATIC TEST OF HC11 RDC



STATIC TEST OF HC11 RDC



STATIC TEST OF HC11 RDC



STATIC TEST OF HC11 RDC

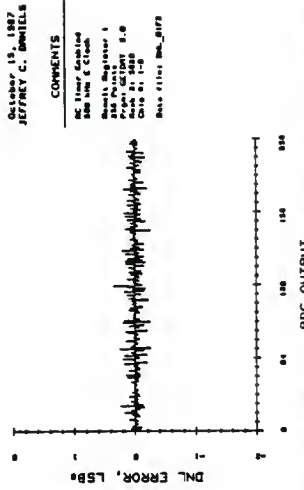
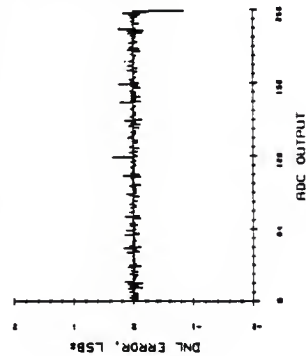


Figure 5-10. Differential non-linearity errors of the A/D using the four conversion, single input, input channel 1 mode.

STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. DANIELS

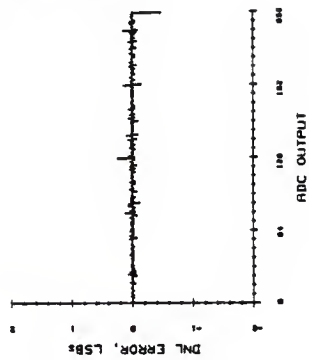
COMMENTS
 No DAC Error
 256 Points
 Result Register 1
 Bias at 2048
 Gain at 2048 0.0
 Code at 2048
 Chip at 170
 Data File: DM_1076



STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. DANIELS

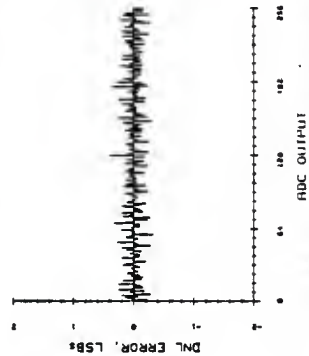
COMMENTS
 No DAC Error
 256 Points
 Result Register 1
 Bias at 2048
 Gain at 2048 0.0
 Code at 2048
 Chip at 170
 Data File: DM_1076



STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. DANIELS

COMMENTS
 No DAC Error
 256 Points
 Result Register 1
 Bias at 2048
 Gain at 2048 0.0
 Code at 2048
 Chip at 170
 Data File: DM_1076



STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. DANIELS

COMMENTS
 No DAC Error
 256 Points
 Result Register 1
 Bias at 2048
 Gain at 2048 0.0
 Code at 2048
 Chip at 170
 Data File: DM_1076

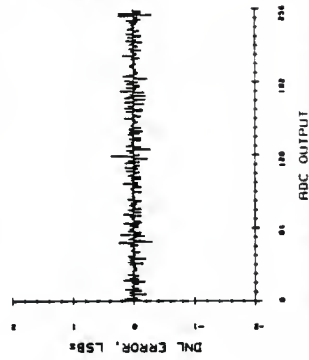
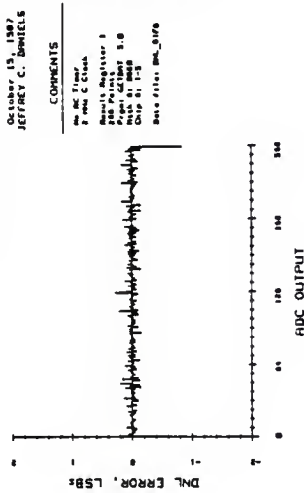
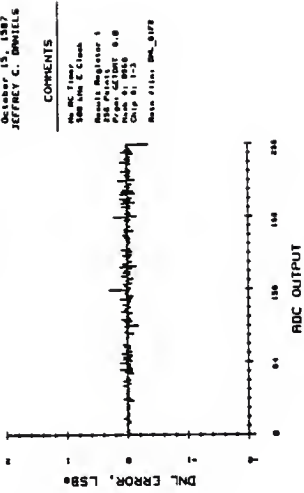


Figure 5-11. Differential non-linearity errors of the A/D using the four conversion, multiple input mode.

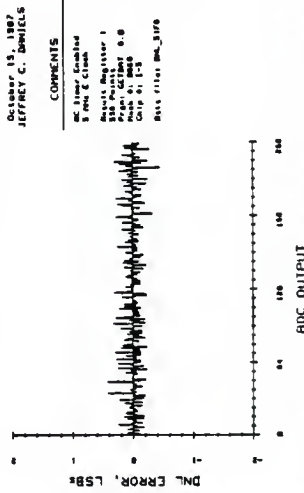
STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC

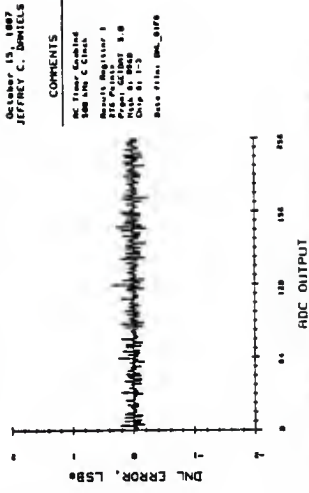


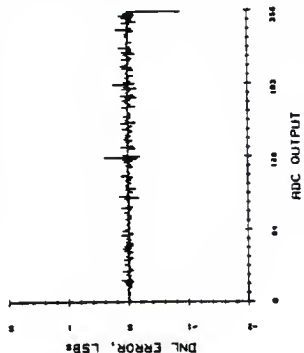
Figure 5-12. Differential non-linearity errors of the A/D using the continuous conversion, single input, input channel 1 mode.

STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. BOWHELL

COMMENTS

MC Timer Enabled
5 Pins 3 Clock
Result Register 1
336 Points
Peak Offset 0.0
Peak Gain 0.999
Gain Error 0.001
Gain Error 1.0
Data File: DM_3106

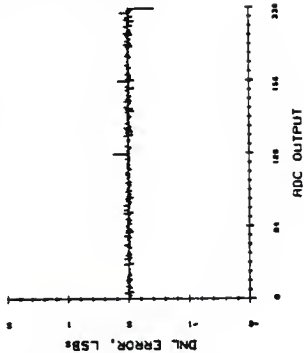


STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. BOWHELL

COMMENTS

MC Timer Enabled
5 Pins 3 Clock
Result Register 1
336 Points
Peak Offset 0.0
Peak Gain 0.999
Gain Error 0.001
Gain Error 1.0
Data File: DM_3107

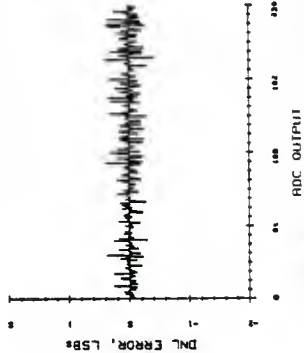


STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. BOWHELL

COMMENTS

MC Timer Enabled
5 Pins 3 Clock
Result Register 1
336 Points
Peak Offset 0.0
Peak Gain 0.999
Gain Error 0.001
Gain Error 1.0
Data File: DM_3106



STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. BOWHELL

COMMENTS

MC Timer Enabled
5 Pins 3 Clock
Result Register 1
336 Points
Peak Offset 0.0
Peak Gain 0.999
Gain Error 0.001
Gain Error 1.0
Data File: DM_3107

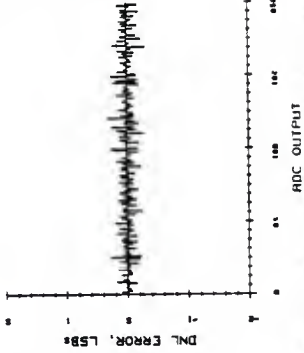
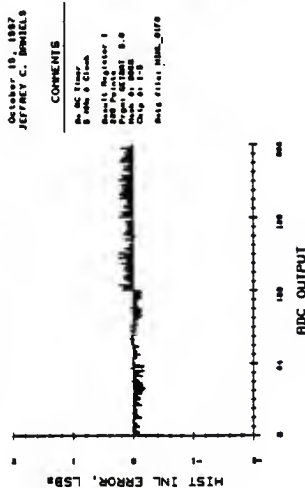
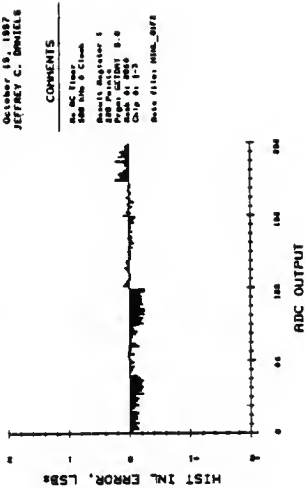


Figure 5-13. Differential non-linearity errors of the A/D using the continuous conversion, multiple mode.

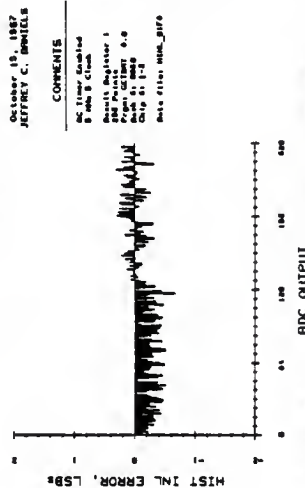
STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC

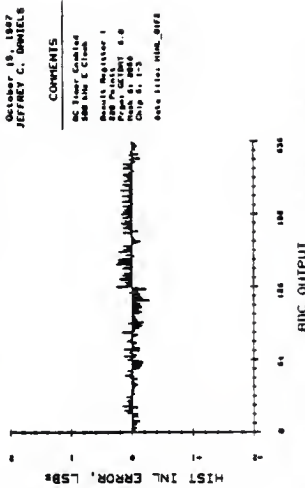
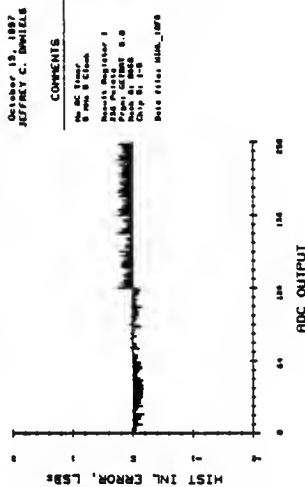
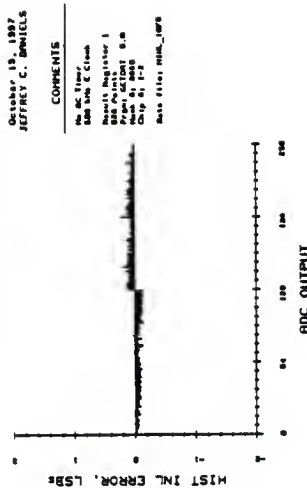


Figure 5-14. Histogram integral non-linearity errors of the A/D using the four conversion, single input, input channel 1 mode.

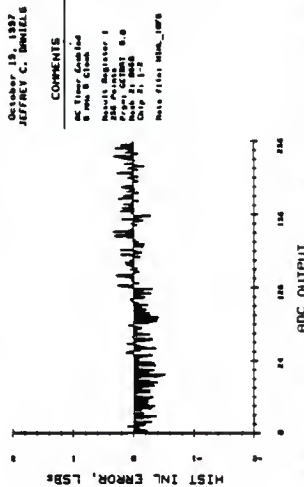
STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC

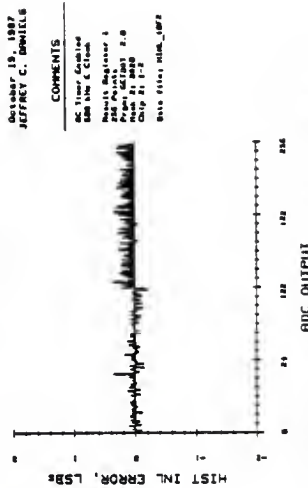
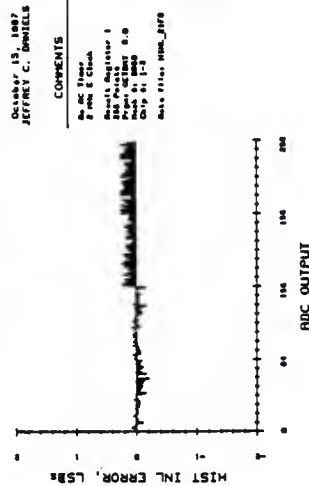
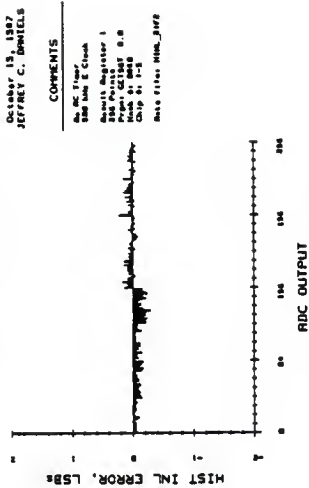


Figure 5-15. Histogram integral non-linearity errors of the A/D using the four conversion, multiple input mode.

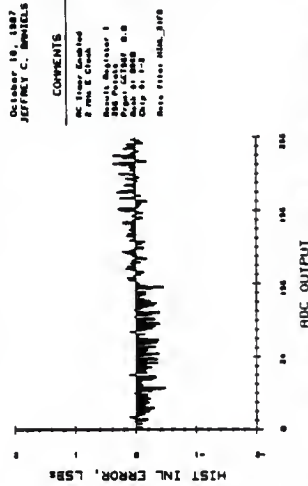
STATIC TEST OF HC11 RDC



STATIC TEST OF HC11 RDC



STATIC TEST OF HC11 RDC



STATIC TEST OF HC11 RDC

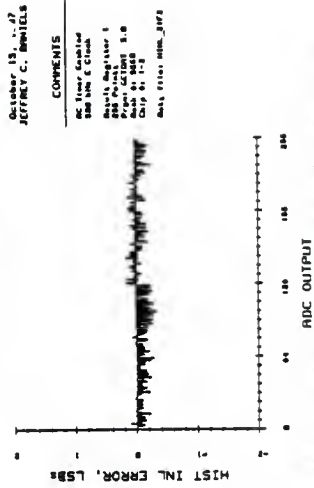
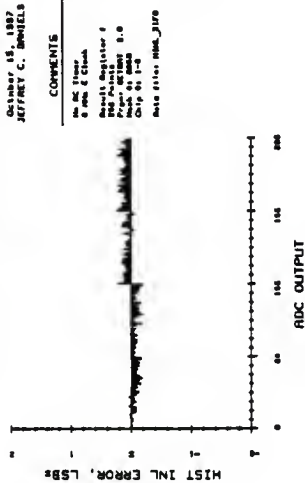
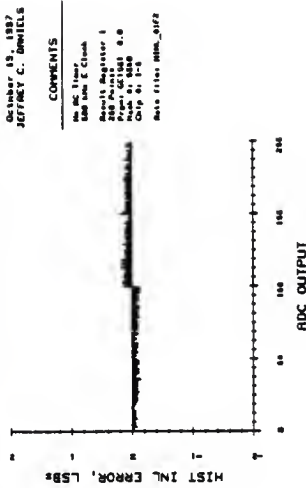


Figure 5-16. Histogram integral non-linearity errors of the A/D using the continuous conversion, single input, input channel 1 mode.

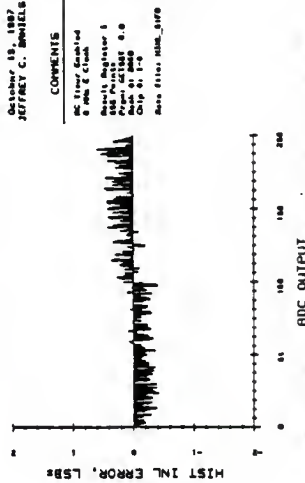
STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC



STATIC TEST OF HC11 ADC

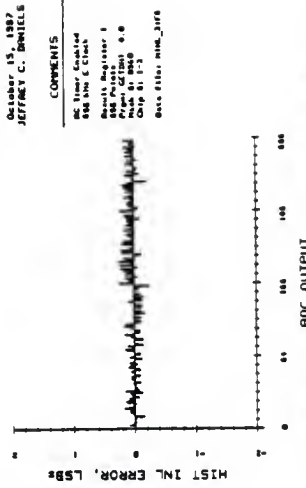


Figure 5-17. Histogram integral non-linearity errors of the A/D using the continuous conversion, multiple mode.

but these tests show no presence of errors found in other static tests.

No missing codes, checked by searching the histogram data for a bin count of zero, were found in any A/D configuration modes regardless of whether the RC timer was enabled or disabled.

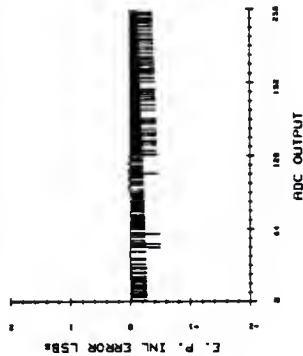
The end point integral non-linearity errors are shown in Figures 5-18 through 5-21. With the RC timer disabled (top plots), these errors fell well within specifications but it must be noted that gain and offset errors had been removed prior to error calculation. Again, a slight decrease in errors is seen with a decrease in frequency. Due to reasons discussed in Appendix C, Data for end point integral non-linearity with the RC timer enabled was not taken at this time.

STATIC TEST OF HC11 RDC

October 15, 1967
JEFFREY C. DANIELS

COMMENTS

In AC Input
2 Volts C Clock
250 Hz
250 Hz Integrator 1
250 Hz Integrator 2
Preamplifier 0.8
Peak 10000 0.8
Gain 1: 1.5
Gain 2: 1.5
Data File: ENC_010



STATIC TEST OF HC11 RDC

October 15, 1967
JEFFREY C. DANIELS

COMMENTS

In AC Clock
2 Volts C Clock
250 Hz
250 Hz Integrator 1
250 Hz Integrator 2
Preamplifier 0.8
Peak 10000 0.8
Gain 1: 1.5
Gain 2: 1.5
Data File: ENC_010

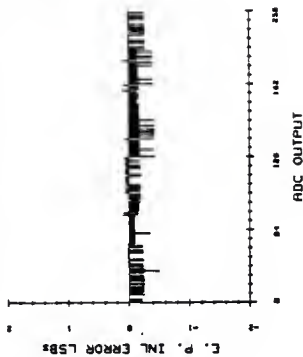


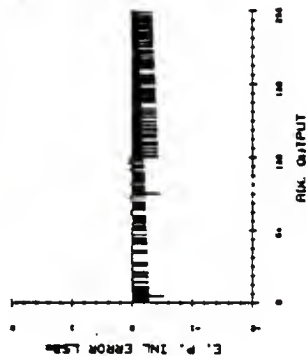
Figure 5-18. End Point integral non-linearity errors of the A/D using the four conversion, single input, input channel 1 mode.

STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. DANIELS

COMMENTS

Run on 81101
Serial Register 1
Data Points 100
Run on 81101
Run on 81101
Chip 81-119
Date 01/01/88 ESM_086



STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. DANIELS

COMMENTS

Run on 81101
Serial Register 1
Data Points 100
Run on 81101
Run on 81101
Chip 81-119
Date 01/01/88 ESM_086

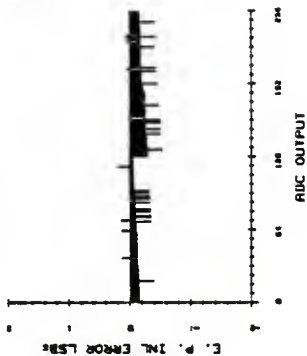


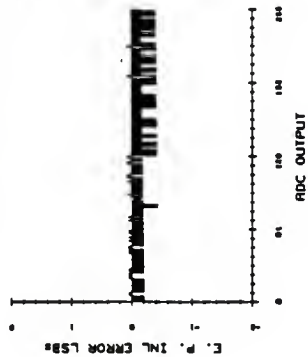
Figure 5-19. End Point integral non-linearity errors of the A/D using the four conversion, multiple input mode.

STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. BOWELS

COMMENTS

No AC Filter
5 MHz 8 Clock
Serial Register 1
Prescaler 8.0
Pres. Action 0.0
Chip 81 124
Data File: SIM_009



STATIC TEST OF HC11 ADC

October 15, 1987
JEFFREY C. BOWELS

COMMENTS

No AC Filter
5 MHz 8 Clock
Serial Register 1
Prescaler 8.0
Pres. Action 0.0
Chip 81 124
Data File: SIM_009

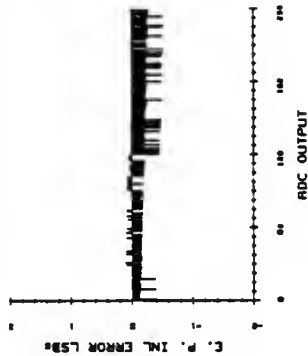
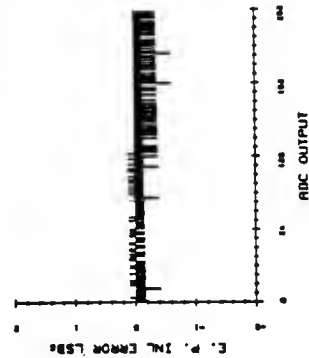


Figure 5-20. End Point integral non-linearity errors of the A/D using the continuous conversion, single input, input channel 1 mode.

STATIC TEST OF HC11 ADC

October 19, 1987
JEFFREY C. BOWELS

COMMENTS
No DC Trunc
256 bits Z Clock
Serial Register 1
256 Points
Print Interval 0.0
Data At 0000
Chip At 1.0
Data File: emc_j198



STATIC TEST OF HC11 ADC

October 19, 1987
JEFFREY C. BOWELS

COMMENTS
No DC Trunc
256 bits Z Clock
Serial Register 1
256 Points
Print Interval 0.0
Data At 0000
Chip At 1.0
Data File: emc_j198

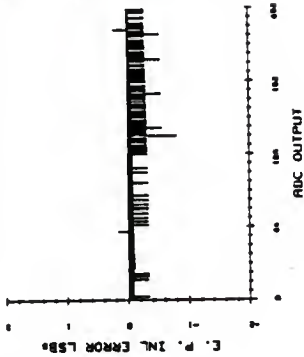


Figure 5-21. End Point integral non-linearity errors of the A/D using the continuous conversion, multiple mode.

Conclusion

Method 1, checking the CCF bit for the end of conversion, led to the discovery of large offset error in the results obtained from Result Register 3. Method 2, executing a large delay loop to allow the A/D conversions to be completed, displayed a large offset in Result Register 2. The magnitude of the offset in Methods 1 and 2 was different in each HC11 tested and decreased as the frequency was decreased. This pattern sensitivity can be verified by using two programs that are provided in Appendix A. These programs perform a quick check of conversion results with a logic probe or logic analyzer. They were written to eliminate the need for an elaborate testing setup for quick testing of the A/D. Using Method 3, total error calculations indicated the constant presence of small offsets, -1 LSB, and extreme conversion result errors when the RC timer was enabled. Also, Method 3's histogram procedure, which averages out noise, yielded results showing that the transition point errors of the A/D were well within Motorola specifications.

6.0 Dynamic Testing of the HC11's A/D

Testing an A/D with varying, dynamic, inputs is an excellent way to help characterize an A/D's actual performance in real world situations. The system configuration used to test the HC11's A/D with dynamic inputs is shown in figure 6-1. The basic testing procedure for most dynamic testing methods is to have the HC11 perform equally spaced A/D conversions on a precision sine wave. A conversion is performed, the result written to PORTB of the HC11, a pulse is sent to the IBM PCXT and then the loop is repeated. The IBM PCXT waits for a pulse, reads the data and then waits for another pulse. The IBM continues to receive data until the desired number of results is acquired. Finally, missing code existence and errors in the form of integral and differential non-linearity are calculated and then plotted. The software for IBM PCXT and the HC11 are shown in Appendix B.

The precision sine wave used in dynamic testing is generated from an HP3325A function generator. With a signal to noise ratio in excess of 60 dB, the HP3325A provides waveforms with adequate spectral purity when considering the eight bit resolution of the HC11's A/D.

The sampling frequency used in dynamic testing methods was desired to be as fast as the HC11 could perform A/D conversions. The HC11 can theoretically

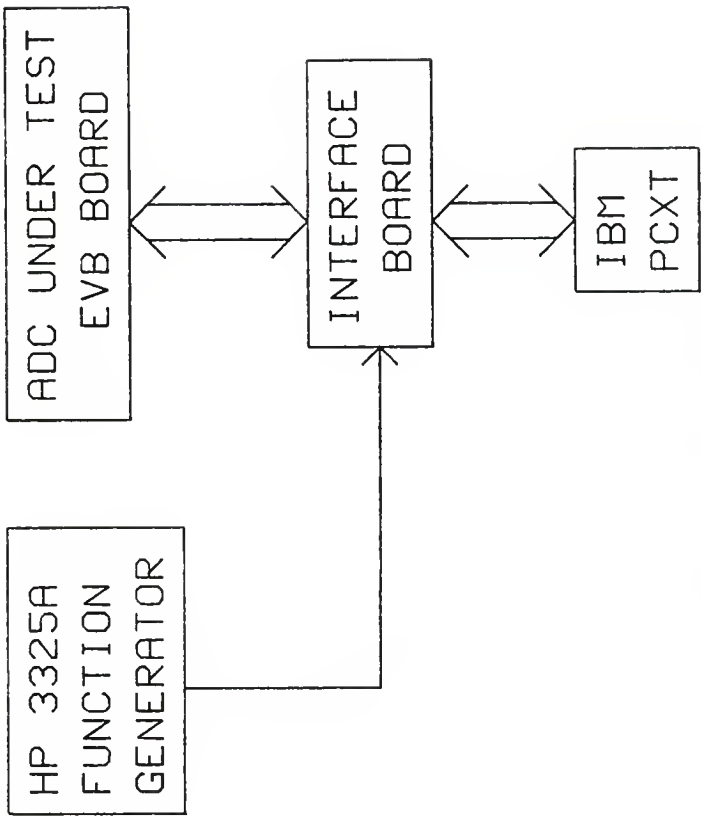


Figure 6-1. Dynamic Testing System.

perform conversions in excess of 62 kilohertz (kHz). However, due to the architecture of the IBM PCXT and its compatibles, the maximum sampling rate without missing results was determined through trial and error to be slightly larger than 4 kHz. Therefore, a sampling rate of 4 kHz was chosen.

The frequency for the sine wave to be sampled was chosen to 1406 Hz because the FFT procedure works best when an integral number of periods of the input signal are present in the number of samples taken.

Testing Procedure

Two testing methods were used to evaluate the dynamic performance of the HC11's A/D. These methods, developed by Doerfler², use a histogram procedure to find missing codes and to estimate differential non-linearity errors and a fast fourier transform (FFT) procedure to estimate integral non-linearity errors and to give an indication of overall system noise. These methods were tested on several HC11s at different E clock frequencies and with the A/D in four different modes of operation. These modes are:

- four-conversion, single input, input channel 1 (01)
- four-conversion, multiple input (10)
- continuous-conversion, single input, input channel 1 (21)
- and
- continuous-conversion, multiple input (31).

Also, each mode of operation and E clock frequency was tested with the RC timer enabled and disabled.

Method 1

Method 1 consists of using a histogram procedure developed by Doerfler². Briefly, this procedure uses a large number of data points to produce an estimate of differential non-linearity errors and to find missing codes. The data points are used to construct a histogram from which a cumulative histogram procedure is used to estimate the A/D's transition points. The transition point estimates now can be used to calculate differential non-linearity errors. Finally, a search of the histogram data files for bins with a count of zero determines where, if any, the missing codes occur.

For this method to produce meaningful estimates of differential non-linearity errors, enough data points must be collected to ensure that a proper distribution is obtained in the histogram. The minimum number of data points, n_{pts} , needed for B bit precision and $100(1-a)$ percent confidence is given by²

$$n_{pts} = \frac{z_{a/2}^2 \pi 2^{N-1}}{B^2}$$

where $z_{a/2}$ is found in a standard normal distribution table, and N is the resolution of the A/D converter. For example, for an 8-bit A/D, the number of data points required to estimate the differential non-linearity error

to within 0.1 bit with a 99% confidence requires 265600 samples.

Missing codes, found by searching the histogram data files for bins with a count of zero, are determined with the same accuracy and confidence level as differential non-linearity errors.

To properly produce the distribution of a sine wave in the histogram data, a sufficient number of points must be collected and also the sine wave must have the proper amplitude and offset. For the HC11's 8-bit A/D with 0 and +5 volt reference voltages, the input sine wave must have a 2.5 volt d.c. offset and a peak to peak amplitude of slightly larger than the reference voltage (i.e. 5.05 volts). This voltage ensures that all A/D codes have a chance to be exercised including the end bins. Ideally this method can be used to calculate the size of an offset if it is present. This becomes a problem because it requires that the input sine wave be exactly centered about the offset of 2.5 volts used in testing the HC11's A/D. Therefore the exact calculation of the offset present will not be performed but the differences in the offset between different operational modes and E clock frequencies can be observed because all of the data was collected in one period of time.

An important characteristic to keep in mind about this method is that the formation of a histogram causes

noise to be averaged out and become non-detectable. With the noise averaged out, the test results of the transition points are free from the influence of noise in the system.

Method 2

Method 2, also developed by Doerfler², uses a fast fourier transform (FFT) procedure to estimate integral non-linearity errors and also give an indication to overall system noise. Briefly, this method uses a power of 2, equally spaced data points (4096) of a spectrally pure sine wave. The data points are windowed with a Von Hann window to help eliminate spectral leakage and then an FFT is performed with the resulting spectrum being plotted. Integral non-linearity errors appear as harmonics of the fundamental frequency, the frequency of the input sine wave. These harmonics are aliased into the frequency window which is one half the sampling frequency. Further considerations for this method include an overall indication of overall system noise by raising the noise floor in the FFT output spectrum.

The harmonics of the fundamental frequency are folded back into the frequency window due to aliasing. In order to show exactly where they appear, a software simulation was performed. A 1406.25 Hz sine wave and its first eight harmonics were sampled at 4000 Hz with the amplitude of each harmonic being reduced by 20 dB to make it possible to detect the respective harmonic in frequency window.

The fractional input frequency was chosen for simulation purposes to ensure that the samples produced contained an integral number of periods in the number of points taken. Also, care must be taken in choosing the sampling frequency and the frequency of the input sine wave so that the harmonics are not aliased into the peak of the fundamental frequency, thus becoming undetectable. The results of this simulation are shown in figure 6-2 with the exact frequencies tabulated in table 6-1.

Harmonic	Frequency (in Hertz)
0	1406.25
1	1187.5
2	218.75
3	1625.0
4	968.75
5	437.5
6	1843.75
7	750.0
8	656.25

Table 6-1. Location of Harmonics in the Frequency window

The dynamic range of an N-bit converter is known to be²

$$\text{dynamic range} = 20 \log_{10}(2^N) = 6.02N \text{ dB.}$$

This equation implies that if the amplitude of the highest harmonic is less than $6.02N$, then the integral non-linearity is less than 1 LSB. Also, the number of bits of integral linearity can be calculated by dividing the amplitude of the highest harmonic by 6.02.

Harmonics of the DFT Window
HARM1406 4000HZ

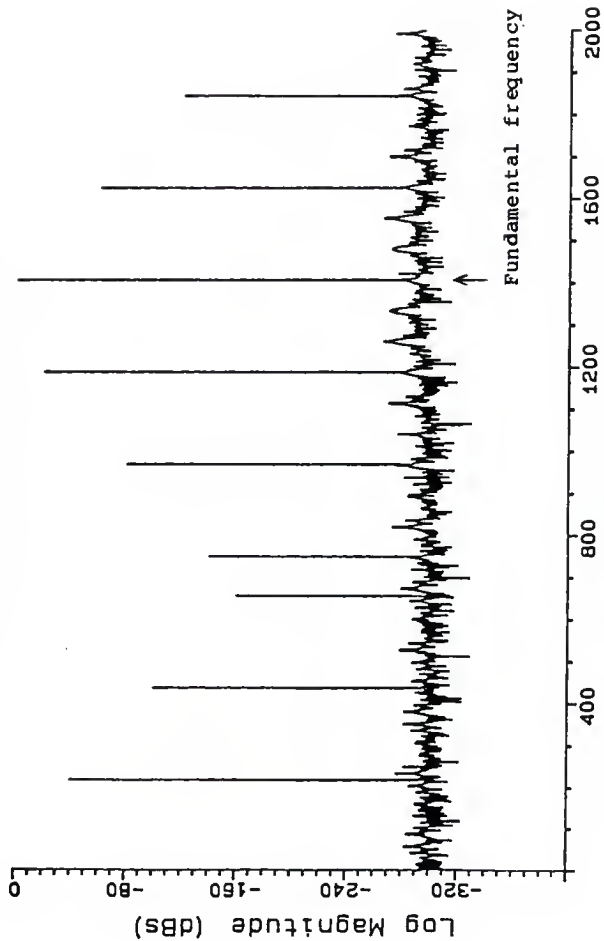


Figure 6-2. Harmonics of the DFT Window
1406.25 Hz sine wave sampled at 4000 Hz.

To determine the noise floor of a perfect 8-bit A/D sampling a 1406.25 sine wave at 4000 Hz, another software simulation was performed. The spectrum produced is shown in figure 6-3 and will be used in the analysis of this method's results obtained from the HC11's A/D.

The amplitude of the input sine wave for testing using Method 2 was a peak to peak voltage of 4.8 volts with a offset of 2.5 volts. The 4.8 volt input was used to eliminate the possibility of clipping which causes frequencies to appear in the output spectrum that actually do not exist.

Output Spectrum for an Ideal ADC
QNTZ1406 4000Hz 8 bits

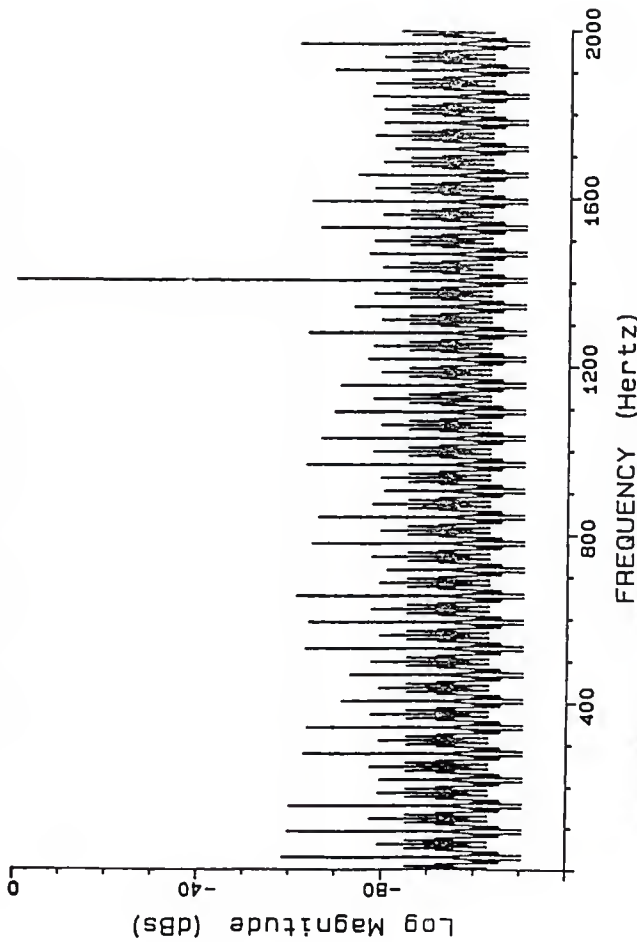


Figure 6-3. Spectrum for an ideal 8-bit A/D
1406.25 Hz sine wave sampled at 4000 Hz.

7.0 Dynamic Testing Results of the HC11's A/D

Due to time limitations, the dynamic testing of all HC11s acquired has not been completed at this time but one HC11 with the number 1-3 has been tested with the two methods described in chapter 6 in all possible modes and E clock frequencies both with, and without the RC timer.

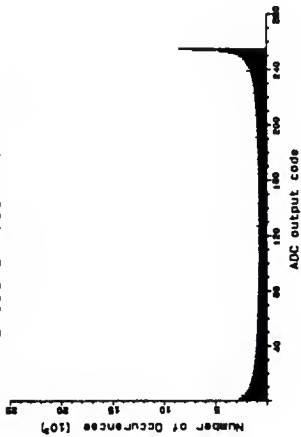
Method 1

Method 1, consisting of constructing a histogram using many data points to find missing codes and to produce a cumulative histogram to calculate differential non-linearity errors at the A/D's transition points was performed on one HC11 at four A/D operational modes and at two E clock frequencies. The plots for these tests are shown in figures 7-1 to 7-8 with the top plots from data with a 2 MHz E clock and the bottom plots from a 500kHz E clock.

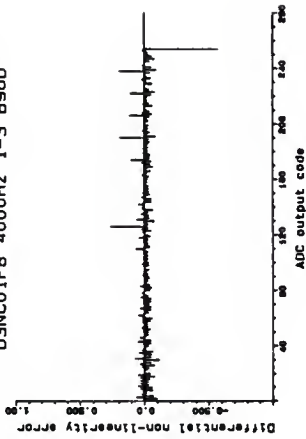
For all different operational modes of the HC11's A/D the Histogram Data plots with the RC timer disabled with a 2 MHz E clock frequency indicates the presence of a small offset because the number of data points in the last bin in the histogram is very small in comparison to other plots with the RC timer enabled at a 2 MHz E clock (top plots) and at an E clock frequency of 500 kHz (bottom plots).

Differential non-linearity errors are well within Motorola specifications in most combinations of

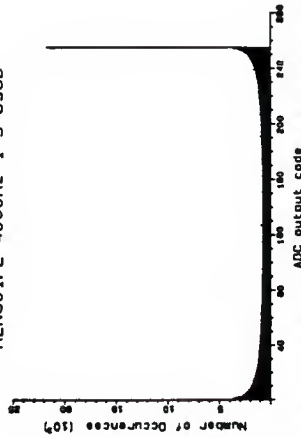
Histogram data
H3NCO1FB 4000Hz 1-3 B960



Histogram Test of HC11 ADC
D3NCO1FB 4000Hz 1-3 B960



Histogram data
H2NCO1F2 4000Hz 1-3 B960



Histogram Test of HC11 ADC
D2NCO1F2 4000Hz 1-3 B960

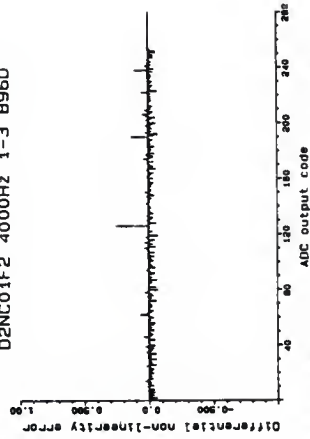
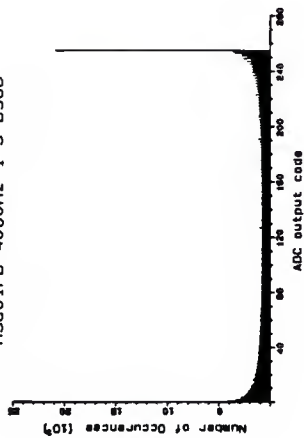
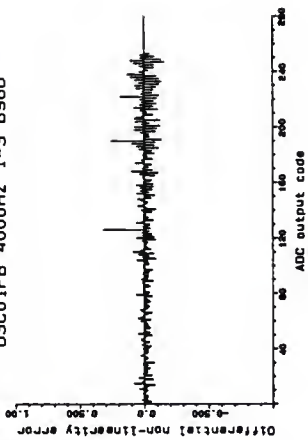


Figure 7-1. Histogram data and Differential non-linearity errors for A/D. Four conversion, single input, input channel 1. RC timer disabled.

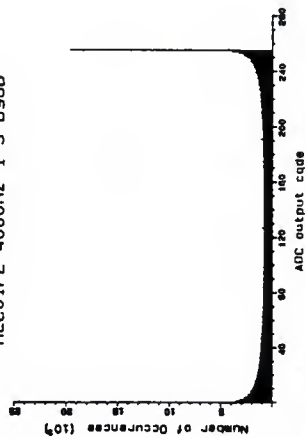
Histogram data
H3C01FB 4000HZ 1-3 B96D



Histogram Test of HC11 ADC
D2C01FB 4000HZ 1-3 B96D



Histogram data
H2C01F2 4000HZ 1-3 B96D



Histogram Test of HC11 ADC
D2C01F2 4000HZ 1-3 B96D

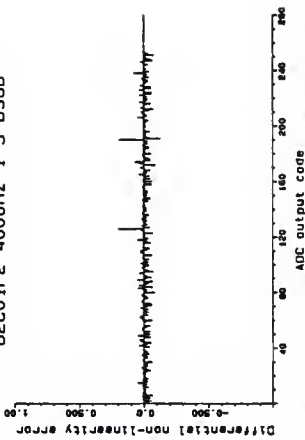
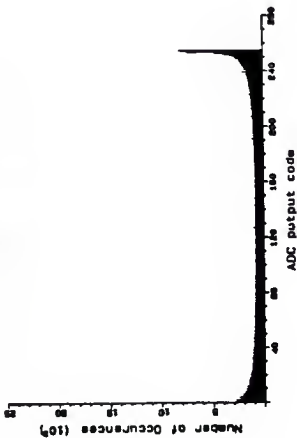
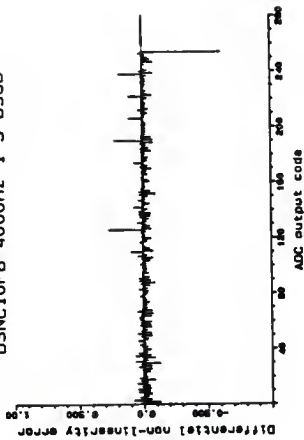


Figure 7-2. Histogram data and Differential non-linearity errors for A/D. Four conversion, single input, input channel 1. RC timer enabled.

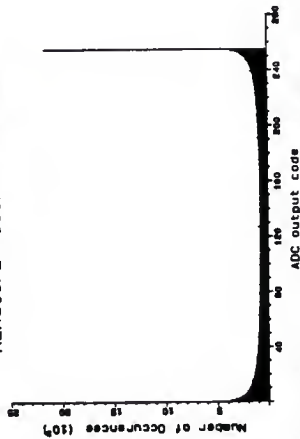
H3NC10FB 4000Hz 1-3 B96D



Histogram Test of HC11 ADC
D3NC10FB 4000Hz 1-3 B96D



H2NC10F2 4000Hz 1-3 B96D



Histogram Test of HC11 ADC
D2NC10F2 4000Hz 1-3 B96D

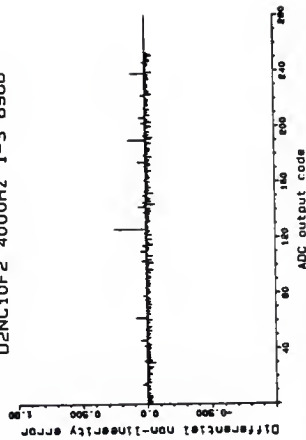
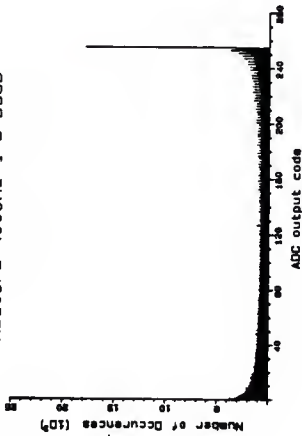
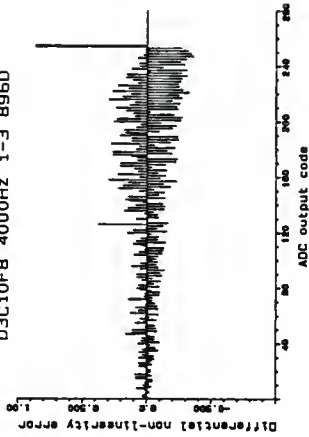


Figure 7-3. Histogram data and Differential non-linearity errors for A/D. Four conversion, multiple input. RC timer disabled.

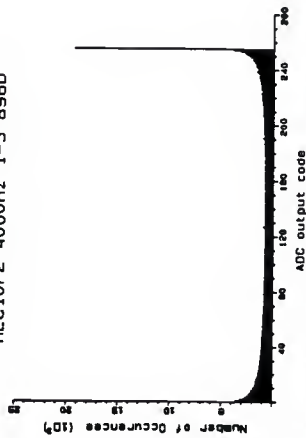
Histogram data
H2C10F2 4000Hz 1-3 B96D



Histogram Test of HC11 ADC
D2C10F2 4000Hz 1-3 B96D



Histogram data
H2C10F2 4000Hz 1-3 B96D



Histogram Test of HC11 ADC
D2C10F2 4000Hz 1-3 B96D

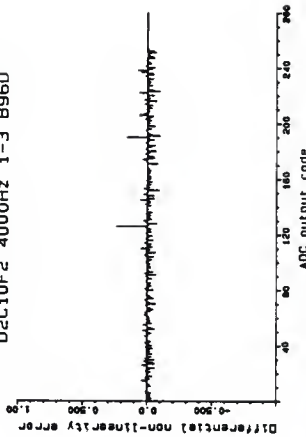
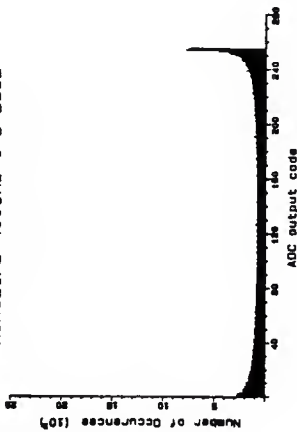
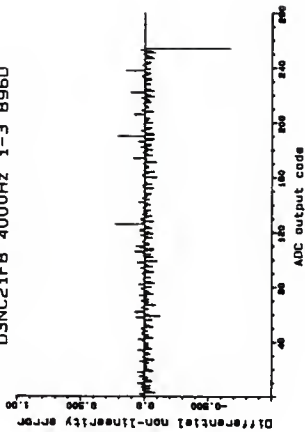


Figure 7-4. Histogram data and Differential non-linearity errors for A/D. Four conversion, multiple input. RC timer enabled.

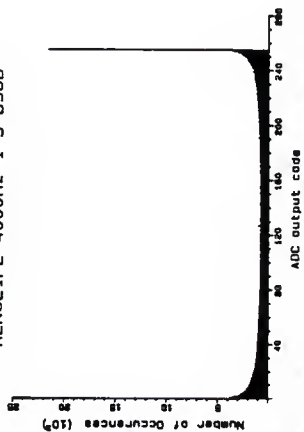
Histogram data
H3NC21F8 4000Hz 1-3 896D



Histogram Test of HC11 ADC
D3NC21F8 4000Hz 1-3 896D



Histogram data
H2NC21F2 4000Hz 1-3 896D



Histogram Test of HC11 ADC
D2NC21F2 4000Hz 1-3 896D

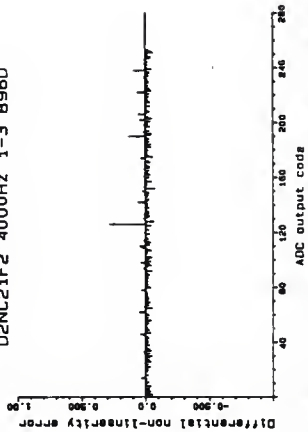
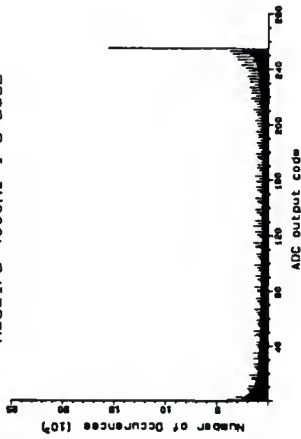
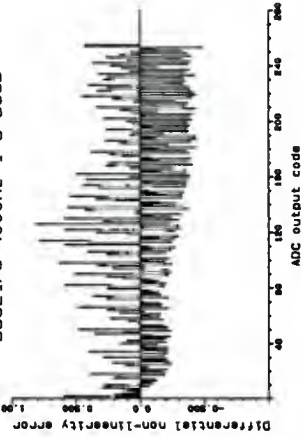


Figure 7-5. Histogram data and Differential non-linearity errors for A/D. Continuous-conversion, single input, input channel 1. RC timer disabled.

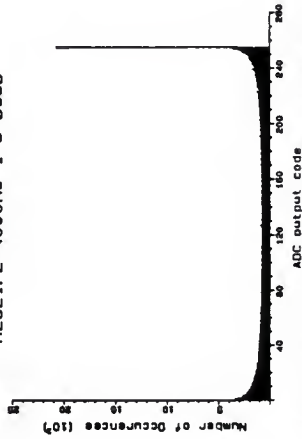
Histogram data
H3C21F8 4000Hz 1-3 B96D



Histogram Test of HC11 ADC
D3C21F8 4000Hz 1-3 B96D



Histogram data
H2C21F2 4000Hz 1-3 B96D



Histogram Test of HC11 ADC
D2C21F2 4000Hz 1-3 B96D

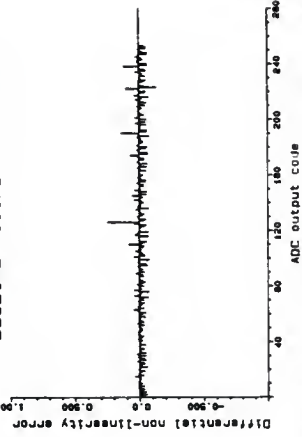
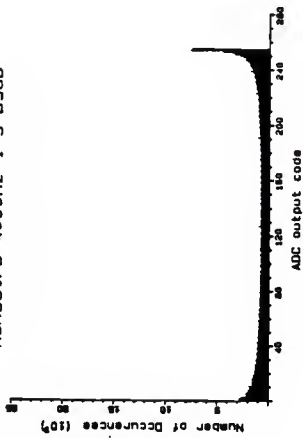
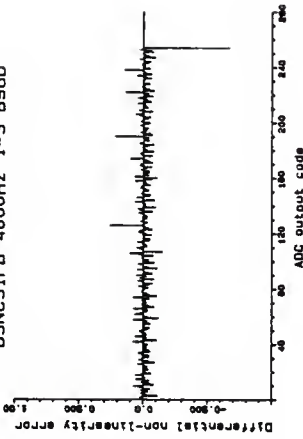


Figure 7-6. Histogram data and Differential non-linearity errors for A/D. Continuous-conversion, single input, input channel 1. RC timer enabled.

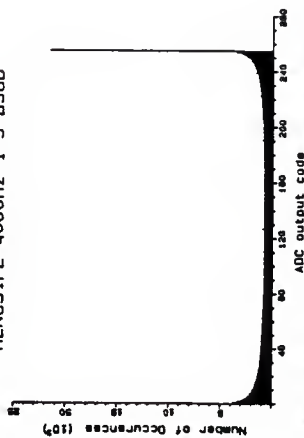
Histogram data
H3NC31F2 4000HZ 1-3 B96D



Histogram Test of HC11 ADC
D2NC31F2 4000HZ 1-3 B96D



Histogram data
H2NC31F2 4000HZ 1-3 B96D



Histogram Test of HC11 ADC
D2NC31F2 4000HZ 1-3 B96D

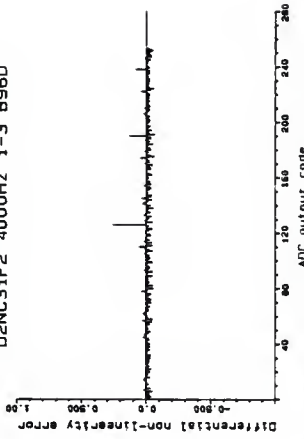
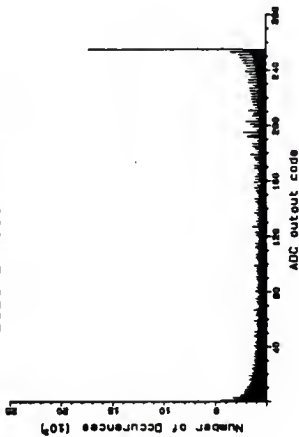
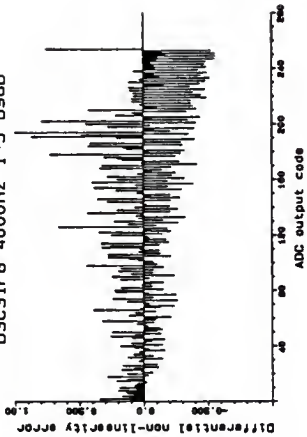


Figure 7-7. Histogram data and Differential non-linearity errors for A/D. Continuous-conversion, multiple input. RC timer disabled.

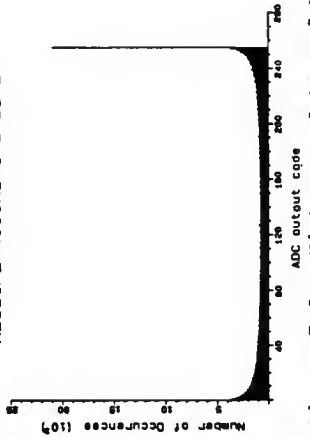
Histogram data
H3C31FB 4000HZ 1-3 896D



Histogram Test of HC11 ADC
D2C31FB 4000HZ 1-3 896D



Histogram data
H2C31F2 4000HZ 1-3 896D



Histogram Test of HC11 ADC
D2C31F2 4000HZ 1-3 896D

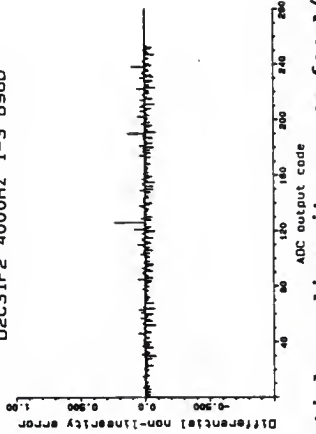


Figure 7-8. Histogram data and Differential non-linearity errors for A/D. Continuous-conversion, multiple input. RC timer enabled.

operational modes, E clock frequencies, and with the RC timer enabled and disabled except for continuous conversion modes at an E clock frequency of 2 Mhz (top plots) with the RC timer enabled. This exception is shown in figures 7-6 and 7-8. In all cases, the differential non-linearity errors increase in magnitude with an increase in frequency.

No missing codes were found in the histogram data files for any combination of A/D operational mode and E clock frequency with or without the RC timer enabled or disabled.

Method 2

Integral non-linearity errors, calculated to within one LSB from the harmonics in output FFT spectrum are shown in figures 7-9 to 7-12 with the RC timer enabled in the bottom plots and the 2 MHz E clock results on the left. Also, an indication of system noise can be observed as well.

Integral non-linearity errors seem to be within Motorola specifications in all combinations of A/D operational modes, E clock frequencies, and with the RC timer enabled and disabled except for the continuous-conversion, multiple input mode at a 2 MHz E clock frequency with the RC timer enabled, figure 7-12.

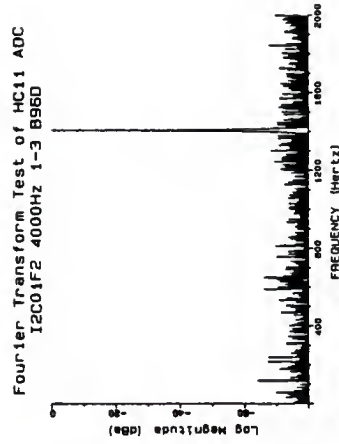
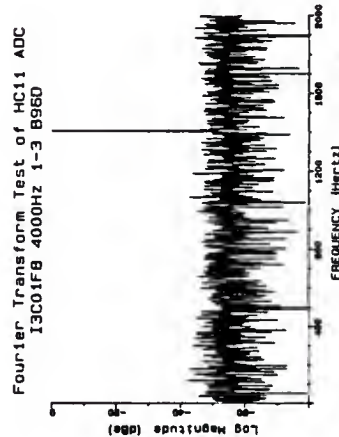
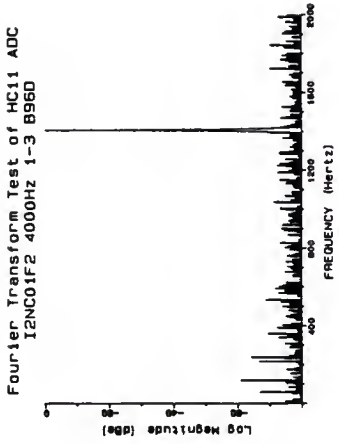
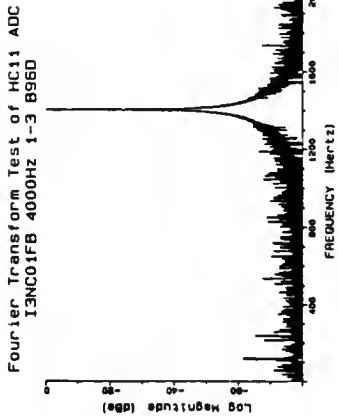
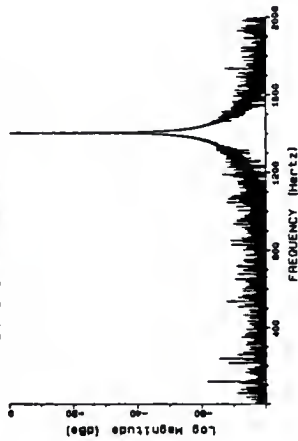
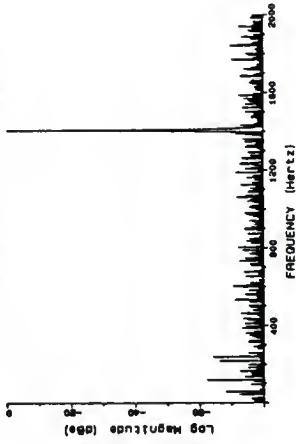


Figure 7-9. Fourier Transform Results of A/D. Four-conversion, single input, input channel 1

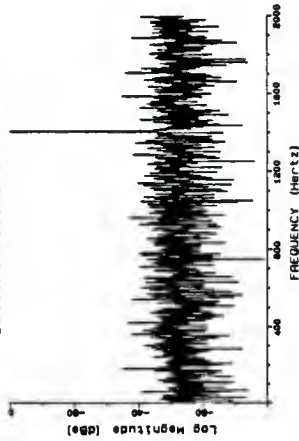
Fourier Transform Test of HC11 ADC
I3NC10FB 4000HZ 1-3 B96D



Fourier Transform Test of HC11 ADC
I2NC10F2 4000HZ 1-3 B96D



Fourier Transform Test of HC11 ADC
I3C10FB 4000HZ 1-3 B96D



Fourier Transform Test of HC11 ADC
I2C10F2 4000HZ 1-3 B96D

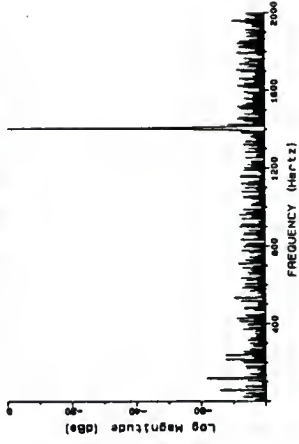


Figure 7-10. Fourier Transform Results of A/D.
Four-conversion, multiple input.

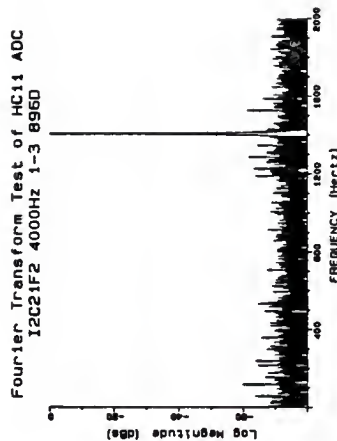
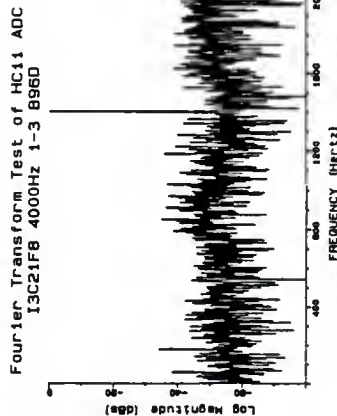
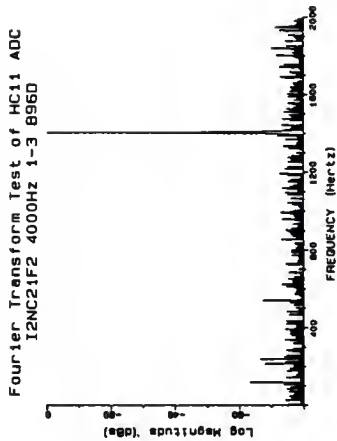
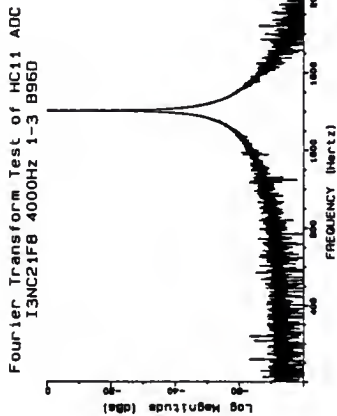
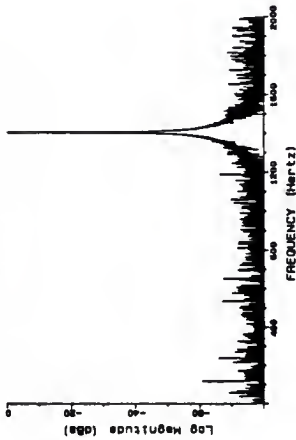
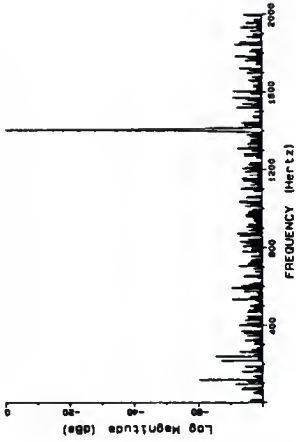


Figure 7-11. Fourier Transform Results of A/D. Continuous-conversion, single input, input channel 1

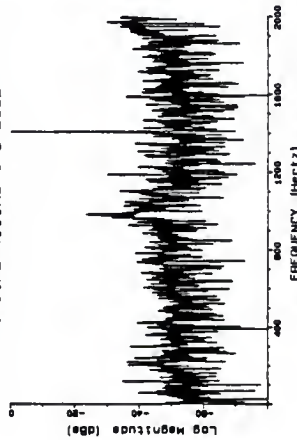
Fourier Transform Test of HC11 ADC
I3NC31FB 4000Hz 1-3 B96D



Fourier Transform Test of HC11 ADC
I2NC31F2 4000Hz 1-3 B96D



Fourier Transform Test of HC11 ADC
I3C31FB 4000Hz 1-3 B96D



Fourier Transform Test of HC11 ADC
I2C31F2 4000Hz 1-3 B96D

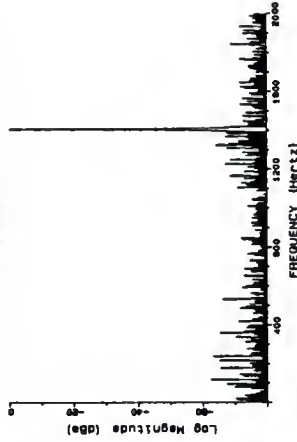


Figure 7-12. Fourier Transform Results of A/D. Continuous-conversion, multiple input.

Overall system noise, indicated by the raising of the noise floor in comparison of an ideal 8-bit A/D, figure 6-3 is not apparent except in results obtained with the RC timer enabled at a 2 MHz E clock frequency.

Conclusion

Although no missing codes were found in any histogram test performed, small offsets were apparent in histogram plots with E clock frequencies of 2 MHz with the RC timer disabled. Differential non-linearity errors, with noise averaged out, are very small and within specifications except in the case of continuous-conversion modes with an E clock frequency of 2 MHz with the RC timer enabled. Integral non-linearity errors are within specifications except for results with the RC timer enabled at 2 MHz E clock frequencies. Overall system noise is apparent in all configurations at 2 MHz E clock rates with the RC timer enabled.

8.0 Summary and Recommendations

Static and dynamic testing of the HCl1s for this thesis indicates the possibility of the HCl1's A/D operating within specifications in future mask releases if the problems found during testing are corrected. In all cases of static testing, when noise and offsets are removed from the conversion results, the A/D falls within specifications for differential and integral non-linearity errors. In dynamic testing, all errors discovered had been previously found using static tests indicating the HCl1's A/D has no large scale dynamic sensitivities. This indicates that dynamic testing need not be included in production floor testing of the HCl1's A/D for this mask. If mask changes occur in the future, a dynamic characterization should be performed with several HCl1s to ensure that dynamic sensitivities are not introduced with the mask change. Again, if dynamic sensitivities are not found in the newer mask, then dynamic testing need not be performed on the production floor.

The most informative test presented in this thesis was the total error determination in Method 3 of the static testing procedure. This test consists of using 1024 step, ramp input between 0 and +5 volts. Using a precision digital voltage meter, each step voltage was measured and then compared with the HCl1's A/D conversion to yield the total errors in conversion results. This

test gave indications of no missing codes, non-monotonic behavior, constant offsets, and the presence of RC timer induced errors.

Two programs that give indications of noise and pattern sensitivities are provided in Appendix A. These programs eliminate the need of an elaborate testing setup and require only a logic probe or logic analyzer.

Further testing recommendations for the HC11's A/D are to isolate the pattern sensitivity between Method 1 and Method 2 of the Static Testing Procedure, find the source of the constant offset found in Method 3 of the Static Procedure, and determine the cause of RC timer induced errors found in most testing methods used in this thesis. Due to the lack of wafer level testing facilities at this university, Motorola should probe the HC11 at the wafer level to find the source of the pattern sensitivities, the constant offsets, and the RC timer induced errors found in testing methods used in this thesis.

Appendix A

```

*****
*
* SOURCE FILE:   qkccfck.src
*
* DESCRIPTION:   This program provides a quick
*               check of the HC11's A/D
*               conversion process using a check
*               of the CCF bit to ensure valid
*               results are in the Result
*               Registers. The user needs to
*               provide the following inputs
*               prior to execution.
*
*               Location in
*               RAM
*
*               00 Hex   the configuration of
*                       the A/D that is
*                       written to the ADCTL.
*
*               01 - 02 Hex the address of the
*                       Result Register to be
*                       checked.
*
*               VRH      a precision 5 volt
*                       reference.
*
*               VRL      tied to ground.
*
*               Also, the user must supply an
*               analog input to be converted if
*               the A/D is configured to convert
*               an external input.
*               The result of the conversion is
*               written to PORTB and can be
*               checked using a logic probe.
*
*               The RC timer can be enabled to
*               clock the A/D system by changing
*               the instruction
*
*                   oraa #$80
*                   to
*                   oraa #$c0.
*
*               This program continually
*               executes until the user aborts
*               it.
*
* AUTHOR:       Jeffrey C. Daniels   9-3-87
*               Kansas State University
*
*****

```

```

PORTB equ $1004   PORTB address
                org $c000

                ldaa $1039   Power up A/D system.
                oraa #$80    RC timer off.
                staa $1039

*              idx $01      Have index register point to
                        the Result Register of choice.

CONVRT ldaa $00      Initiate conversion.
        staa $1030

CHECK  ldab $1030   Check to see if conversion in
        bpl CHECK  done.

        ldaa 0,X    Load result.
        staa PORTB Store result to PORTB.

        bra CONVRT Do another conversion.

```

* SOURCE FILE: qkdlyck.src

* DESCRIPTION: This program provides a quick check of the HC11's A/D conversion process using the execution of a long delay loop to ensure valid results are in the Result Registers. The user needs to provide the following inputs prior to execution.

Location in RAM

- 00 Hex the configuration of the A/D that is written to the ADCTL.
- 01 - 02 Hex the address of the Result Register to be checked.
- VRH a precision 5 volt reference.
- VRL tied to ground.

Also, the user must supply an analog input to be converted if the A/D is configured to convert an external input. The result of the conversion is written to PORTB and can be checked using a logic probe.

The RC timer can be enabled to clock the A/D system by changing the instruction

```

    ora #0
to
    ora #0.

```

This program continually executes until the user aborts it.

AUTHOR: Jeffrey C. Daniels 9-3-87
Kansas State University

```

PORTB equ $1004   PORTB address
DELAY equ 76

    org $c000

    ldaa $1039    Power up A/D system.
    oraa #$80     RC timer off.
    staa $1039

*    ldy $01      Have index register point to
                    the Result Register of choice.

CONVRT ldaa $00    Initiate conversion.
        staa $1030

LOOP   ldx #DELAY  Wait 450 clock cycles.
        dex
        bne LOOP

        ldaa 0,Y   Load result.
        staa PORTB Store result to PORTB.

        bra CONVRT Do another conversion.

```



```

*****
*
*   Source file: ckccf4.src
*
*   This program was written to statically
*   test the HC11 microprocessor.
*
*   RC oscillator is disabled.
*   Place ADC conversion mode in location 00
*   before running the program.
*
*   8-11-87
*
*   Jeffrey C. Daniels
*
*   Revisions: 8-11-87 Created from stget4.src.
*
*****

```

```

ADRO EQU $1031
PORTB EQU $1004
RESPTR EQU $0001

```

```

ORG $C000

LDY #$1000    Point to port A.

BCLR 0,Y $40  Clear flip flop.
BSET 0,Y $40

CLR $1004     Clear PORT B
BSET 0,Y $20  Latch PORT B into
BCLR 0,Y $20  High Byte of Data Latch

LDX #ADRO     Initialize pointer to
STX RESPTR    result register.

LDAA $1039    Enable ADC - -
ORAA #$80     Power up ADC
STAA $1039    RC timer off.

LDAB $00
STAB $1030    Initiate conversion.

```

```

* Start of main loop *

```

```

NTREDY LDAA 0,Y    Check to if HP has sent
        ANDA #$04  a pulse to start
        BEQ NTREDY conversion.

        LDX RESPTR  Check to see if conversion
        CPX #ADRO  has already been done.

```

	BNE	NXTOUT	If so, jump to NXTOUT.
	LDAB	\$00	
	STAB	\$1030	Initiate conversion.
CHECK	LDAB	\$1030	Check if conversion
	BPL	CHECK	is done.
NXTOUT	LDX	RESPTR	
	LDAA	0,X	
	STAA	PORTB	Load result
	BSET	0,Y \$10	Store result in Low
	BCLR	0,Y \$10	Byte of data latch.
	BCLR	0,Y \$40	Clear flip flop.
	BSET	0,Y \$40	
	INC	RESPTR+1	Increment pointer to next
	LDX	RESPTR	Result register and then
	CPX	#ADRO+4	check if four results have
	BNE	CONT	been outputted to PORTB.
	LDX	#ADRO	If 4 results have been
	STX	RESPTR	sent then update result
*			pointer.
CONT	BRA	NTREYD	

```

*****
*
* Source file: ckdly4.src
*
* This program was written to statically
* test the HC11 microprocessor.
*
* RC oscillator is disabled.
* Place ADC conversion mode in location 00
* before running the program.
*
* 8-11-87
*
* Jeffrey C. Daniels
*
* Revisions: 8-11-87 Created from sttest4.src.
*
*****

```

```

ADRO EQU $1031
PORTB EQU $1004
RESPTR EQU $0001
LOOPNO EQU 76

```

```

ORG $C080

LDY #$1000 Point to port A.

BCLR 0,Y $40 Clear flip flop.
BSET 0,Y $40

CLR $1004 Clear PORT B
BSET 0,Y $20 Latch PORT B into
BCLR 0,Y $20 High Byte of Data Latch

LDX #ADRO Initialize pointer to
STX RESPTR result register.

LDAA $1039 Enable ADC - -
ORAA #$80 Power up ADC
STAA $1039 RC timer off.

LDAB $00
STAB $1030 Initiate conversion.

```

```

* Start of main loop *

```

```

NTREDY LDAA 0,Y Check to if HP has sent
ANDA #$04 a pulse to start
BEQ NTREDY conversion.

```

	LDX RESPTR	Check to see if conversion
	CPX #ADRO	has already been done.
	BNE NXTOUT	If so, jump to NXTOUT.
	LDAB \$00	
	STAB \$1030	Initiate conversion.
	LDX #LOOPNO	Wait 450 clock cycles.
DELAY	DEX	
	BNE DELAY	
NXTOUT	LDX RESPTR	
	LDAA 0,X	
	STAA PORTB	Load result
	BSET 0,Y \$10	Store result in Low
	BCLR 0,Y \$10	Byte of data latch.
	BCLR 0,Y \$40	Clear flip flop.
	BSET 0,Y \$40	
	INC RESPTR+1	Increment pointer to next
	LDX RESPTR	Result register and then
	CPX #ADRO+4	check if four results have
	BNE CONT	been outputted to PORTB.
	LDX #ADRO	If 4 results have been
*	STX RESPTR	sent then update result
		pointer.
CONT	BRA NTREDY	

*

* Source file: stnrc2.src

*

* This program was written to statically
* test the HCl1 microprocessor
* utilizing the HP test system that
* Steve Draving developed.

*

*

* RC oscillator is disabled.
* Place ADC conversion mode in location 00
* before running the program.
* Place which result register to read in
* location 01 and 02 which will be read into
* the X register.
* Continous conversions.

*

* 12Mar87

*

* Jeffrey C. Daniels

*

* Revisions: 6-25-87 This program created from
* jdst5.src.

*

* 6-29-87 Created from stnrc.src to
* take out interupt structure.

*

```
ORG $C200

LDY #$1000    Point to port A.

BCLR 0,Y $40  Clear flip flop.
BSET 0,Y $40

CLR $1004     Clear PORT B
BSET 0,Y $20  Latch PORT B into
BCLR 0,Y $20  High Byte of Data Latch

LDAA $1039    Enable ADC - -
ORAA #$80     Power up ADC
STAA $1039    RC timer off.

LDAB $00
STAB $1030    Initiate conversion.

NTREDDY LDAA 0,Y    Check to if HP has sent
        ANDA #$04   a pulse to start
        BEQ NTREDDY conversion.
```

	LDAB \$00	
	STAB \$1030	Initiate conversion.
CHECK	LDAB \$1030	Check if conversion
	BPL CHECK	is done.
	LDX \$01	
	LDAA 0,X	
	STAA \$1004	Load result
	BSET 0,Y \$10	Store result in Low
	BCLR 0,Y \$10	Byte of data latch.
	BCLR 0,Y \$40	Clear flip flop.
	BSET 0,Y \$40	
	BRA NTREYD	

*

* Source file: strc2.src

*

* This program was written to statically
* test the HC11 microprocessor
* utilizing the HP test system that
* Steve Draving developed.

*

*

* RC oscillator is Enabled.
* Place ADC conversion mode in location 00
* before running the program.
* Place which result register to read in
* location 01 and 02 which will be read into
* the X register.
* Continous conversions.

*

* 17 Jun 87

*

* Jeffrey C. Daniels

*

* Revisions: 6-25-87 This program created from
* jdst6.src.

*

* 6-29-30 Created from strc.src to
* take out interupt structure.

*

ORG \$C300

LDY #\$1000 Point to port A.

BCLR 0,Y \$40 Clear flip flop.
BSET 0,Y \$40

CLR \$1004 Clear PORT B
BSET 0,Y \$20 Latch PORT B into
BCLR 0,Y \$20 High Byte of Data Latch

LDAA \$1039 Enable ADC - -
ORAA #\$c0 Power up ADC
STAA \$1039 RC timer on.

LDAB \$00
STAB \$1030 Initiate conversion.

NTREDY LDAA 0,Y Check to see if HP has
ANDA #\$04 sent a pulse to start
BEQ NTREDY conversion.

	LDAB \$00	
	STAB \$1030	Initiate conversion.
CHECK	LDAB \$1030	Check if conversion
	BPL CHECK	is done.
	LDX \$01	
	LDAA 0,X	
	STAA \$1004	Load result
	BSET 0,Y \$10	Store result in Low
	BCLR 0,Y \$10	Byte of data latch.
	BCLR 0,Y \$40	Clear flip flop.
	BSET 0,Y \$40	
	BRA NTREYD	


```

10 | .....
20 | **                                RQFOUR                ver 2.0                **
30 | .....
40 | **
50 | **      This program reads the four Result Registers of the      **
60 | **      6BHC11's onboard AOC and displays them to the screen. The  **
70 | **      OVM readings are also displayed on the screen.  None of the  **
80 | **      information is stored in arrays or stored in files. This  **
90 | **      program provides a quick check to verify that the 4 Result  **
100 | **      Registers are functioning properly.                        **
110 | **
120 | **      Jaff's STGET4.OBJ program is used to drive the 6BHC11.    **
130 | **
140 | **      MICHAEL PANKRATZ                04 AUGUST 1987                **
150 | **
160 | .....
170 |
180 | PRINTER IS 16
190 | PRINT PAGE
200 | PRINT TAB(30);"AOC DATA AQUISITION"
210 | PRINT TAB(25);"Tasting the 4 Result Registers"
220 | PRINT LIN(3)
230 |
240 | Initialize: |
250 | OUTPUT 709;"FIRANSTZ1"                | Initialize DVM
260 | RESET 3                                | Initialize GPIO for AOC
270 | RESET 2                                | Initialize GPIO for precision OAC
280 |
290 | BEEP
300 | DISP "Press any key to begin data acquisition."
310 | ON KBO GOTO Get_data ,ALL
320 | Wait:   GOTO Wait
330 |
340 | Get_data: |
350 |
360 | PRINT "Press any key to abort."
370 | ON KBO GOTO Exit ,ALL                | Quit if any key is pressed
380 |
390 | Loop_hera: |
400 | TRIGGER 709                | Start the DVM
410 | Rd:  STATUS 709;Stat
420 | IF BIT(Stat,0)<>1 THEN Rd        | Wait till ready
430 | ENTER 709;Ovm                | Read OVM
440 |
450 | Chan1=READBIN(3)                | Read result register 1
460 | DISP Ovm;TAB(20);Chan1;TAB(30);Chan2;TAB(40);Chan3;TAB(50);Chan4
470 | Chan2=READBIN(3)                | Read result register 2
480 | DISP Ovm;TAB(20);Chan1;TAB(30);Chan2;TAB(40);Chan3;TAB(50);Chan4
490 | Chan3=READBIN(3)                | Read result register 3
500 | DISP Ovm;TAB(20);Chan1;TAB(30);Chan2;TAB(40);Chan3;TAB(50);Chan4
510 | Chan4=READBIN(3)                | Read result register 4
520 | DISP Ovm;TAB(20);Chan1;TAB(30);Chan2;TAB(40);Chan3;TAB(50);Chan4
530 |
540 | GOTO Loop_hera
550 |
560 | Exit: |
570 | DISP "Program terminated."
580 | BEEP
590 | ENO

```

```

10 | .....
20 | **                               GETDAT                               ver 5.0                               **
30 | .....
40 | **
50 | **      This program collects data from the ADC under test          **
60 | **      (the 68HC11's onboard ADC) and writes it to a file.          **
70 | **      The file can be read by PLDT and PRDAT but only the first    **
80 | **      array (the raw data) will be read. The bin count array and    **
90 | **      other data will be ignored.                                    **
100 | **
110 | **      The file format is as follows. The first element in          **
120 | **      the file is the raw data array size. It is followed by the   **
130 | **      array of data itself. Next is the size of the bin count      **
140 | **      array, followed by the array itself. Then the reference      **
150 | **      voltage, Vref, and the ADC resolution, Ras, are stored.      **
160 | **      Finally, 4 transition points are stored for gain and offset   **
170 | **      error calculations. They are 0-->1, 6-->7 & 7-->8 (arbitrary **
180 | **      for step width), and 254-->255.                                **
190 | **
200 | **      The program calls Utrans(Pre_tog, Res, Vref), a function     **
210 | **      to find the transition point voltages.                        **
220 | **
230 | **      Version 2.0 change the DNL error method from the             **
240 | **      theoretical method (using transition points) to the           **
250 | **      histogram method. Now only 4 transition points are taken     **
260 | **      to figure offset and gain errors. Instead, the ADC under     **
270 | **      test is read 10 times and the results are placed into bins.  **
280 | **
290 | **      Versions 3.0 and 3.5 were modifications made to the         **
300 | **      toggle function. These improvements are outlined in the      **
310 | **      header for the function (see below).                          **
320 | **
330 | **      Version 4.0 was a modification made in conjunction with      **
340 | **      a change made in the HC11 program. The delay to allow the    **
350 | **      DAC to set up was taken out of the HC11 program and put in   **
360 | **      this program. That simply involved changing two existing     **
370 | **      delay loops from 5ms to 100ms.                                **
380 | **
390 | **      Version 5.0 first determines the minimum and maximum        **
400 | **      ADC output values and uses these in the TOGFN instead of     **
410 | **      sending 0->1 and 254->255. This will allow testing of        **
420 | **      converters which do not operate over their full range.      **
430 | **      Also, transition points 6->7 and 7->8 are not taken since     **
440 | **      they are no longer used by ERROR. The two variables are      **
450 | **      now used to store the minimum and maximum ADC count         **
460 | **      values that were sent into the toggle function.              **
470 | **
480 | **      MICHAEL PANKRATZ                               05 AUGUST 1987  **
490 | **
500 | .....
510 |
520 | DIM Input(1,1024)                               ! Data array
530 | DIM Bin(1,256)                                  ! Bin count array
540 | DIM Utr(3)                                       ! Transition voltage array
550 |
560 |
570 | Constants:   !
580 |   Vref=5     ! ADC reference voltage
590 |   Res=8      ! ADC resolution (in bits)

```

```

600 Samples=1024                ! Number of samples taken
610 Umin=0                      ! Valid values: 0 to Vref
620 Vmax=Vref                   ! Valid values: 0 to Vref > Umin
630 !
640 !
650 PRINTER IS 16
660 PRINT PAGE
670 PRINT TAB(33);"ADC DATA AQUISITON"
680 PRINT TAB(20);"Data for Offset, Gain, INL, end DNL errors"
690 PRINT LIN(3)
700 !
710 !
720 Initialize: !
730 OUTPUT 709;"FIRANSTZ21"      ! Initialize DVM
740 RESET 3                      ! Initialize GPIO for ADC
750 RESET 2                      ! Initialize GPIO for precision DAC
760 FDR I=0 TO 2*Res-1          ! Initialize bin count array
770   Bin(0,I)=I
780   Bin(1,I)=0
790 NEXT I
800 !
810 !
820 Open_file: !
830 REDIM Input(1,Samples-1)
840 REDIM Bin(1,2*Res-1)
850 !
860 BEEP
870 ! Detfile$="601F2"
880 EDIT "Enter filename for the dete: ",Detfile$
890 ASSIGN #1 TO Detfile$,Stet
900 IF Stet=0 THEN PURGE Detfile$ ! Delete if file already exists
910 Records=INT((Samples+2*Res)/16)+1 ! Calculate number of records
920 CREATE Detfile$,Records      ! Create the dete file
930 ASSIGN #1 TO Detfile$       ! Open the file
940 !
950 !
960 BEEP
970 DISP "Press eny key to bagin dete acquisition."
980 DN KBD GOTO Get_trens ,ALL
990 Wait: GOTO Wait
1000 !
1010 !
1020 Get_trans: !
1030 DISP
1040 PRINT "Finding trentions: "
1050 Dvel=0
1060 GOSUB Set_dec
1070 Vtr(1)=READBIN(3)           ! Determine min ADC output value
1080 Cmin=Vtr(1)
1090 Vtr(0)=FNVtrens(Cmin,Res,Vref) ! Voltage of 1st trention point
1100 !
1110 Dvel=262143
1120 GOSUB Set_dec
1130 Vtr(2)=READBIN(3)           ! Determine mex ADC output value
1140 Cmax=Vtr(2)-1
1150 Vtr(3)=FNVtrens(Cmax,Res,Vref) ! Voltage of lest trention point
1160 BEEP
1170 !
1180 !
1190 Dmin=INT(Umin*2*18/Vref)

```

```

1200 Dmax=INT(Vmax*2^18/Vref)
1210 Ustep=(Vmax-Umin)/(Samples-1)
1220 Dstep=INT(Ustep*2^18/Vref)      ! Step size to incr. the DAC
1230 !
1240 PRINT
1250 PRINT "Sampling";Samples;"points between";Umin;"end";Vmax;"volts."
1260 PRINT "Press any key to abort."
1270 !
1280 !
1290 ON KBD GOTO Exit ,ALL          ! Quit if any key is pressed
1300 FOR I=0 TO Samples-1
1310     DISP "Conversion #";I
1320     Dval=I*Dstep+Dmin          ! Digital value for this sample
1330     S0SUB Set_dec              ! Set the DAC with value in Dval
1340     !
1350     TRIGGER 709                ! Start the DVM
1360 Rd: STATUS 709;Stat
1370     IF BIT(Stat,0)<>1 THEN Rd   ! Wait till ready
1380     ENTER 709;Input(0,I)      ! Read DVM
1390     !
1400     Input(1,I)=READBIN(3)      ! Read ADC under test
1410     Index=Input(1,I)
1420     Bin(1,Index)=Bin(1,Index)+1
1430     !
1440     FOR J=1 TO 9               ! Update the bins
1450         Index=READBIN(3)
1460         Bin(1,Index)=Bin(1,Index)+1
1470     NEXT J
1480 NEXT I
1490 DISABLE                       ! Turns off key-abort function
1500 !
1510 !
1520 Write_file: !
1530 PRINT #1;Samples,Input(*)      ! Store data
1540 PRINT #1;2^Res,Bin(*)
1550 PRINT #1;Vref,Res,Utr(*)
1560 !
1570 !
1580 Exit: ASSIGN #1 TO *           ! Close the file
1590 DISP "Program terminated."
1600 BEEP
1610 WAIT 750
1620 ENABLE
1630 GOTO Constants
1640 END
1650 !
1660 !
1670 Set_dec: ! Value is passed in through Dval to set the DAC
1680     High=INT(Dval/65536)        ! High byte of the DAC
1690     Mid=INT(Dval/256)-256*High  ! Middle byte for DAC
1700     Low=Dval-65536*High-256*Mid ! Low byte for the DAC
1710     !
1720     WRITE BIN 2;High,High+1024,High ! \
1730     WRITE BIN 2;Mid,Mid+512,Mid    ! | - Send word to the DAC
1740     WRITE BIN 2;Low,Low+256,Low,0 ! /
1750     !
1760     WAIT 100                   ! 100ms delay
1770 RETURN
1780 !
1790 !

```

```

1800 |
1810 | .....
1820 | **                                T06FN          (T06SUB ver 4.0)          **
1830 | .....
1840 | **
1850 | **      This function determines the input voltage just before
1860 | **      end after a toggle point of the ADC under test (in this
1870 | **      case, the 68HC11's on-board converter). The full 18 bits
1880 | **      resolution of the precision DAC are used to obtain as
1890 | **      accurate results as possible. The results are averaged
1900 | **      and returned in the function name. The format is:
1910 | **
1920 | **      FNVtrans(Togpt, Res, Vref)
1930 | **
1940 | **      where:
1950 | **      Togpt - the desired ADC output value BEFORE
1960 | **              the transition. 0 <= Togpt <= (2*Res)-2
1970 | **      Res   - the resolution of the ADC under test
1980 | **              (in bits)
1990 | **      Vref  - the ADC reference voltage
2000 | **
2010 | **      Note: The DVM and SPID busses must be initialized before
2020 | **              this function is called.
2030 | **
2040 | **      Version 2.0 added a lower resolution binary pre-search
2050 | **      which dramatically reduced the search time for a toggle
2060 | **      point.
2070 | **      Version 3.0 made a few changes to give the function
2080 | **      the capability to catch missing code. The function then
2090 | **      then gives the users the option to enter a new toggle point
2100 | **      (or the same one to check for repeatability) or to terminate
2110 | **      the program. Returns a 999 to indicate missing code error.
2120 | **
2130 | **      Version 4.0 made a couple more changes to help fight
2140 | **      missing code errors by checking the ADC output after coming
2150 | **      out of the binary search and kicking it back up there if the
2160 | **      ADC value was below the entered toggle point value.
2170 | **
2180 | **      MICHAEL PANKRATZ          24 JUN 1997
2190 | **
2200 | .....
2210 | DEF FNVtrans(Togpt,Res,Vref)
2220 | .....
2230 |
2240 |
2250 | Init: !
2260 | PRINT Togpt;"-->";Togpt+1
2270 | Cvolt=0 ! Current DAC output voltage
2280 | Ccdc=0 ! Current ADC output value
2290 | Pvolt=0 ! Previous DAC output voltage
2300 | Pcdc=0 ! Previous ADC output value
2310 |
2320 |
2330 | Vmin=Togpt*(Vref/2*Res) ! Starting input voltage to ADC
2340 | Dmin=INT(Vmin*2^18/Vref) ! Start value for DAC
2350 | Vstep=Vref/2*(Res+1) ! 1/2 LSB of the ADC under test
2360 | Dstep=INT(Vstep*2^18/Vref) ! Step size of DAC
2370 |
2380 |
2390 | Dec=Dmin

```

```

2400 Bin_res=218-13) | Set min step size to 13 bit res.
2410 Bin:| Binary search for ADC toggle point (to 13 bit resolution)
2420 IF Dstep<Bin_res THEN Seq | Take the DAC to 13 bit resolution
2430 Dec=Dec+Dstep | DAC input value
2440 IF Dec>262143 THEN Dec=262143 | Prevent over-ranging the DAC
2450 Lp2:GDSU8 Set_dec | Set the DAC
2460 Cdc=READBIN(3) | Get current ADC value
2470 DISP "DAC input:":iDec,"ADC output:":iCdc
2480 IF Cdc<=Togpt THEN Bin | Did toggle occur?
2490 Dec=Dec-Dstep | Set DAC to before toggle point
2500 IF Dec<0 THEN Dec=0 | Prevent under-ranging the DAC
2510 IF Dstep>=Bin_res THEN Dstep=INT(Dstep/2) | Divide step size by 2
2520 GOTO Lp2
2530 |
2540 |
2550 Seq: | Sequential search of toggle point (18 bit resolution)
2560 Dstep=1 | Set DAC step size to 1
2570 IF Cdc=Togpt THEN Lp3 | Make sure ADC value is good
2580 Dstep=Bin_res | Set DAC step size to min value
2590 GOTO Bin | Try again
2600 |
2610 Lp3:Dec=Dec+Dstep
2620 GDSU8 Set_dec | Set the DAC
2630 Pdc=Cdc | Store previous value of ADC
2640 Cdc=READBIN(3) | Get current ADC value
2650 DISP "DAC input:":iDec,"ADC output:":iCdc
2660 IF Cdc>Pdc THEN Exit | Did toggle occur?
2670 GOTO Lp3
2680 |
2690 |
2700 Exit: |
2710 GDSU8 Reed_dvm | Current DAC output
2720 Cvolt=Voltege
2730 Dec=Dec-Dstep
2740 GDSU8 Set_dec
2750 GDSU8 Reed_dvm | Previous DAC output
2760 Pvolt=Voltege
2770 Ave=(Cvolt+Pvolt)/2 | Average to find transition voltage
2780 |
2790 |
2800 IF (Cdc=Pdc+1) AND (Cdc=Togpt+1) THEN Dk !No missing codes
2810 PRINTER IS 16 | Output device is the screen
2820 FOR X=1 TO 3
2830 BEEP
2840 WAIT 250
2850 NEXT X
2860 PRINT "Missing Code!"
2870 PRINT "Actual results: ":iPdc;"-->":iCdc
2880 PRINT "Desired results:":iTogpt;"-->":iTogpt+1
2890 Errs="N"
2900 EDIT "Enter a New toggle point or Terminate (N/T)?",Errs
2910 IF UPCs(Errs[1,1])="T" THEN Term
2920 Inp: INPUT "Enter desired ADC output BEFORE the toggle",Togpt
2930 IF (Togpt<0) OR (Togpt>218-2) THEN Inp
2940 GOTO Init
2950 Term: Ave=999
2960 Dk: RETURN Ave
2970 FNEND
2980 |
2990 |

```

```

3000 |
3010 Set_dac: | Calculetes DAC input word and sends it to the DAC
3020 Dvel=Dac | Digital value for this sample
3030 High=INT(Dval/65536) | High byte for the DAC
3040 Mid=INT(Dvel/256)-256*High | Middle byte for the DAC
3050 Low=Dvel-65536*High-256*Mid | Low byte for the DAC
3060 WRITE BIN 2:High,High+1024,High | \
3070 WRITE BIN 2:Mid,Mid+512,Mid | - Set the DAC
3080 WRITE BIN 2:Low,Low+256,Low,0 | /
3090 WAIT 100 | Peuse for 100 msec
3100 RETURN
3110 |
3120 |
3130 |
3140 Read_dvm: | Takes one DVM reading
3150 | It returns the value in 'Voltege'
3160 TRIGGER 709 | Begin reeding DVM
3170 Wait: STATUS 709:Dvmstat
3180 IF BIT(Dvmstat,0)<>1 THEN Wait | Is it finished?
3190 ENTER 709:Voltege | Read the value from the DVM
3200 RETURN

```

```

10 | .....
20 | **                               DMAIL           The Transmitter **
30 | .....
40 | **
50 | **       This program was written to run on an HP 98458.  It **
60 | ** reads in a raw data file created by GETDAT and sends it over **
70 | ** the HP-IB bus to a HP 9236 computer.  There are several **
80 | ** things which must be noted: **
90 | **
100 | ** 1. The 98458 must be configured as the controller (it is **
110 | ** normally in this mode), and the 9236 must be in the **
120 | ** non-controller mode.  This requires changing a jumper **
130 | ** on the motherboard of the 9236 (jumper should connect **
140 | ** the left two prongs).  Be sure to put the jumper back **
150 | ** to its original position when the transfer is completed. **
160 | **
170 | ** 2. The 9236 must have its version of DMAIL (the receiver) **
180 | ** running first, before this program is started, or it **
190 | ** will miss some of the data. **
200 | **
210 | ** 3. The DMAILER only sends over raw data files.  If it **
220 | ** is desired to send a BASIC program, use EMAIL. **
230 | **
240 | **
250 | ** Written by HEWLETT-PACKARD **
260 | ** Modified by Michael Penkretz      20 July 1987 **
270 | **
280 | .....
290 DIM Data(1,1024),Data2(1,256),Vtr(3) ! The data arrays
300 Size=81 ! The size of a raw data file
310 !
320 !
330 PRINTER IS 16
340 PRINT PAGE
350 PRINT TAB(35);"HP DATA MAILER"
360 PRINT TAB(22);"Data transfer from a 98458 to a 9236"
370 PRINT LIN(3)
380 !
390 !
400 Input: BEEP
410 Datafile$="A01F8" ! Input file name
420 EDIT "Enter name of file to transfer (must be ASCII):",Datafile$
430 ASSIGN #1 TO Datafile$,Stet
440 IF Stet<>! THEN Cont ! Does file exist?
450 PRINT "File ";Datafile$;" does not exist."
460 PRINT
470 BEEP
480 WAIT 200
490 GOTO Input
500 !
510 Cont: !
520 OUTPUT 720;Datafile$,Size ! Send over the file name & size
530 !
540 !
550 Read_file: !
560 DISP "Reading data from file..."
570 READ #1;Size1
580 REDIM Data(1,Size1-1)
590 READ #1;Data1(*) ! Read in first array

```



```

600      READ #1;Size2
610      REQIM Data2(1,Size2-1)
620      READ #1;Data2(*)           ! Raad in second array
630      READ #1;Vraf,Ras,Vtr(*)   ! Raad in raamaining data
640      !
650      !
660      Sand_data: !
670      OISP "Sending data over HPI8..."
680      OUTPUT 720;Size1           ! Sand size of 1st array
690      FOR I=0 TO 1
700          FOR J=0 TO Size1-1
710              OUTPUT 720;Data1(I,J) ! Sand 1st array
720          NEXT J
730      NEXT I
740      OUTPUT 720;Size2         ! Size of 2nd array
750      FOR I=0 TO 1
760          FOR J=0 TO Size2-1
770              OUTPUT 720;Data2(I,J) ! Send 2nd array
780          NEXT J
790      NEXT I
800      OUTPUT 720;Vraf          ! Sand remaining values
810      OUTPUT 720;Res
820      FOR I=0 TO 3
830          OUTPUT 720;Vtr(I)
840      NEXT I
850      EoJ: !
860      ASSIGN #1 TO *           ! Close input file
870      OISP "Data transfer completed."
880      $EEP
890      END

```

```

10 | .....
20 | **   for the 9236   DATAMAIL   The Receiver   **
30 | .....
40 | **
50 | **   This program was written to run on the HP 9236 computer.   **
60 | **   It receives data files created by GETDAT over the HPiB   **
70 | **   bus and stores it on disk. The first item transferred over   **
80 | **   the HPiB bus is the file name and size so this program does   **
90 | **   not need to prompt the user for any information. There are   **
100 | **   several things which must be observed for the Data Mailer to   **
110 | **   operate properly:   **
120 | **
130 | **   1. The 9845B must be configured as the controller (it is   **
140 | **   normally in this mode), and the 9236 must be in the   **
150 | **   non-controller mode. This requires changing a jumper   **
160 | **   on the motherboard of the 9236 (jumper should connect   **
170 | **   the left two prongs). Be sure to put the jumper back   **
180 | **   to its original position when the transfer is completed.   **
190 | **
200 | **   2. The 9236 must have its version of DATAMAIL (the Receiver)   **
210 | **   running first, before the Transmitter program on the   **
220 | **   9845B is started or some of the data will get lost.   **
230 | **
240 | **   3. The EMAILER can only send ASCII formatted files. If it   **
250 | **   is desired to send a BASIC program, this program will   **
260 | **   not work. Use EMAIL2 to send programs.   **
270 | **
280 | **
290 | **   Written by HEWLETT-PACKARD   **
300 | **   Modified by Michael Penkretz   20 July 1987   **
310 | **
320 | .....
330 DIM Data(1,1024),Data2(1,256),Vtr(3)
340 |
350 |
360 OUTPUT 2;CHR$(255)&CHR$(75); | Clear the screen
370 PRINT TABXY(33,2);CHR$(136);"HP DATA MAILER"
380 PRINT TAB(22);CHR$(13B);"Data transfer from a 9845B to a 9236"
390 PRINT
400 PRINT
410 PRINT
420 |
430 |
440 ASSIGN @Ifile TD 7 | Set up HPiB like an input file
450 |
460 DISP "Waiting for data."
470 ENTER @Ifile;Outfile#;Fsize | Read filename & size off the HPiB
480 DISP "Receiving filename."
490 BEEP
500 |
510 Open_file: |
520 DN ERROR 60SUB File_exists
530 CREATE BOAT Outfile#,Fsize
540 ASSIGN @Ofile TD Outfile# | Open output file on disk
550 OFF ERROR
560 |
570 |
580 Read_data: |
590 BEEP

```

```

600      OISP "Receiving data..."
610      ENTER @Ifile;Size1          ! Read in size of 1st array
620      REDIM Odata1(1,Size1-1)
630      FOR I=0 TO 1
640          FOR J=0 TO Size1-1
650              ENTER @Ifile;Odata1(I,J) ! Read in first array
660              NEXT J
670          NEXT I
680      ENTER @Ifile;Size2          ! Size of 2nd array
690      REDIM Odata2(1,Size2-1)
700      FOR I=0 TO 1
710          FOR J=0 TO Size2-1
720              ENTER @Ifile;Odata2(I,J) ! Read in second array
730              NEXT J
740          NEXT I
750      ENTER @Ifile;Vref;Res      ! Read in remaining data
760      FOR I=0 TO 3
770          ENTER @Ifile;Vtr(I)
780      NEXT I
790      !
800      !
810  Write_data: !
820      OISP "Writing data to a file..."
830      OUTPUT @0file;Size1;Odata1(*)
840      OUTPUT @0file;Size2;Odata2(*)
850      OUTPUT @0file;Vref;Res;Vtr(*)
860      !
870      !
880  Eof: !
890      ASSIGN @0file TO *          ! Close the files
900      ASSIGN @Ifile TO *
910      OISP "Data transfer complete."
920      PRINT CHR$(140);"Data is stored in ";CHR$(135);Outfiles
930      GOTO Exit
940      !
950      !
960      !
970  File_exists: ! Purges the file if it already exists
980      IF ERRN=54 THEN
990          PURGE Outfiles
1000         RETURN
1010        ELSE
1020            PRINT CHR$(137);CHR$(130)
1030            PRINT "Terminal Error!"
1040            PRINT "Error code";ERRN
1041            PRINT CHR$(128);CHR$(139);
1042            STOP
1050        ENO IF
1060        !
1070        !
1080  Exit:BEEP
1090  PRINT CHR$(139)
1100  END

```

```

10 | .....
20 | **      for the 9236          ERROR          ver 5.236      **
30 | .....
40 | **
50 | **      This program takes the data file created by GETDAT     **
60 | **      calculates the offset error, gain error, integral nonlin- **
70 | **      earity, differential nonlinearity, and absolute errors. The **
80 | **      nonlinearity and absolute errors are written to files which **
90 | **      may be read by PLOT if desired.                          **
100 | **
110 | **      INL error is calculated using the method outlined in   **
120 | **      ANALOG-DIGITAL CONVERSION HANDBOOK, 3rd ED (Analog Devices), **
130 | **      pp 317-330.                                             **
140 | **
150 | **      DNL error is calculated using the histogram method     **
160 | **      outlined in D. Doerfler's thesis, p 34.                **
170 | **
180 | **      ABS error is the difference between the ADC output and  **
190 | **      the ideal straight line.                                **
200 | **
210 | **      Offset and Gain errors are also calculated using the   **
220 | **      methods obtained from the A-D CONVERSIONS HANDBOOK, pp 317-330. **
230 | **
240 | **      Version 4.0 added a loop to check for non-monotonocities **
250 | **      end missing code. Counters keep track of the number of **
260 | **      occurrences and the last element is also stored. The number **
270 | **      of occurrence and the value of the last occurrences are then **
280 | **      printed out.                                           **
290 | **
300 | **      Version 5.0 added Alpha & Beta, correction factors, to **
310 | **      help eliminate offset and gain errors from the data. It now **
320 | **      calculates INL using 2 methods: endpoint (with Alpha & Beta) **
330 | **      end the histogram method from Doerfler's thesis. Also fixed **
340 | **      program to check for true missing code by detecting any **
350 | **      empty bins read in from the new data file. And added a few **
360 | **      bells and whistles to make I/O a little more friendly.   **
370 | **      Also using middle 2 Vtrens variables to store ADC values for **
380 | **      the first and last transitions.                          **
390 | **
400 | **
410 | **      MICHAEL PANKRATZ                                     11 August 1987 **
420 | **
430 | .....
440 |
450 | DIM Data(1,1024),Abs(1,1024)          | Must make these arrays larger if
460 | DIM Bin(1,256),Dnl(1,256)            | testing an ADC with more than
470 | DIM Inl(1,256),HInl(1,256)          | 8 bits.
480 | DIM Vtrens(3),Non_mono(1),Code(1)
490 | Dld=0                                | An error flag
500 |
510 |
520 | PRINTER IS 1
530 | PRINT CHR$(12);CHR$(140);
540 | PRINT TAB(20);"OFFSET, GAIN, INL, DNL, & ABSOLUTE ERRORS"
550 | PRINT CHR$(136)
560 | PRINT
570 | PRINT
580 |
590 |
600 |

```

```

600 ON ERROR GOTO No_file
610 CAT
620 Inp1: 8EEP
630 Infile$="A01F2"
640 OUTPUT 2;Infile$;
650 INPUT "Enter input filename: ",Infile$
660 ASSIGN @Ifile TO Infile$           ! Open input file
670 OFF ERROR
680 GOTO Inp2
690 |
700 No_file: |
710 IF ERRN=56 THEN
720 PRINT CHR$(137);"File ";Infile$;" does not exist."
730 PRINT CHR$(136)
740 8EEP
750 WAIT .75
760 GOTO Inp1
770 ELSE
780 PRINT CHR$(137);CHR$(130)
790 PRINT "Error";ERRN;"ocurred while opening ";Infile$
800 PRINT CHR$(128);CHR$(139)
810 STOP
820 ENO IF
830 |
840 |
850 Inp2: |
860 Pos=LEN(Infile$)-3                 ! Compute output filenames
870 Name$=Infile$(Pos)
880 Outfile1$="EINL_"&Name$           ! End point INL
890 Outfile2$="HINL_"&Name$         ! Histogram INL
900 Outfile3$="ONL_"&Name$          ! Histogram ONL
910 Outfile4$="ABS_"&Name$          ! Total Error
920 OUTPUT 2;Outfile1$;
930 INPUT "Enter filename for end point INL error: ",Outfile1$
940 OUTPUT 2;Outfile2$;
950 INPUT "Enter filename for histogram INL error: ",Outfile2$
960 OUTPUT 2;Outfile3$;
970 INPUT "Enter filename for histogram ONL error: ",Outfile3$
980 OUTPUT 2;Outfile4$;
990 INPUT "Enter filename for absolute error: ",Outfile4$
1000 |
1010 |
1020 ENTER @Ifile;Samples             ! Read in data
1030 REOIM Oeta(1,Samples-1),Abs(1,Samples-1)
1040 ENTER @Ifile;Dete(*)
1050 |
1060 ENTER @Ifile;Osamples
1070 REOIM Sin(1,Osamples-1),Onl(1,Osamples-1)
1080 REOIM Inl(1,Osamples-1),Hinl(1,Osamples-1)
1090 ENTER @Ifile;Sin(*)
1100 ENTER @Ifile;Vref;Res;Vtrans(*)
1110 |
1120 |
1130 Constants: |
1140 Vmin=0
1150 Vmax=Vref
1160 Lsb=Vref/2*Res
1170 Vf=Vtrans(0)                     ! Voltage to cause first transition
1180 Vl=Vtrans(3)                     ! Voltage to cause last transition
1190 Cf=Vtrans(1)+1                   ! Count after first transition

```

```

1200 C1=Vtrans(2)           ! Count after last transition
1210 !
1220 IF (Cf<>INT(Cf) AND C1<>INT(C1)) OR (Cf=0 AND C1=0) THEN
1230   Cf=1                 ! If processing an old data file,
1240   C1=255              ! assign default values to
1250   Old=1                ! Cf & C1 and set a flag
1260 ENO IF
1270 !
1280 !
1290 !
1300 PRINT
1310 PRINT "Calculating offsat and gain errors."
1320 ! Offsat error
1330 Voffsat=Uf+(Uf-V1)/(C1-Cf)+Lsb/2
1340 Coffsat=Voffsat/Lsb
1350 !
1360 !
1370 ! Gain error
1380 Vgain=Vraf-2*Lsb+Uf-V1
1390 Cgain=Vgain/Lsb
1400 !
1410 !
1420 !
1430 PRINT "Calculating absoluta error."
1440 Amax=-65536
1450 Amin=65536
1460 FOR X=0 TO Samples-1   ! Absoluta error
1470   Abs(0,X)=Data(0,X)
1480   Abs(1,X)=Data(1,X)-(Data(0,X)-Umin)*2*Ras/(Umax-Umin)
1490   IF Abs(1,X)>Amax THEN
1500     Amax=Abs(1,X)
1510     Max2=Abs(0,X)
1520   ENO IF
1530   IF Abs(1,X)<Amin THEN
1540     Amin=Abs(1,X)
1550     Min2=Abs(0,X)
1560   ENO IF
1570 NEXT X
1580 !
1590 !
1600 !
1610 PRINT "Correcting raw data."
1620 Alpha=Lsb*(C1-Cf)/(V1-Uf)           ! Data correction constants to
1630 Beta=Lsb*((V1+Cf-Uf*C1)/(V1-Uf)-1/2) ! aliminate offset & gain errs
1640 !
1650 FOR I=0 TO Samples-1               ! Correct raw voltage data
1660   Data(0,I)=Alpha+Data(0,I)+Beta
1670 NEXT I
1680 !
1690 FOR I=0 TO 3                       ! Correct the transition voltages
1700   Vtrans(I)=Alpha+Vtrans(I)+Beta
1710 NEXT I
1720 !
1730 !
1740 !
1750 PRINT "Calculating and point intagral nonlinearity error."
1760 Slope=254/(Vtrans(3)-Vtrans(0))
1770 Imax=-65536
1780 Imin=65536
1790 Prev=0

```

```

1800 I=1
1810 FOR X=0 TO Samples-1          ! Integral Nonlinearity Error
1820   IF Data(1,X)>Prav THEN
1830     Inl(0,I)=Data(1,X)
1840     Inl(1,I)=Data(1,X)-Slope*(Data(0,X)-Lsb/2)-1
1850     IF Inl(1,I)>Imax THEN
1860       Imax=Inl(1,I)
1870       Maxl=Inl(0,I)
1880     END IF
1890     IF Inl(1,I)<Imin THEN
1900       Imin=Inl(1,I)
1910       Minl=Inl(0,I)
1920     END IF
1930     Prev=Data(1,X)
1940     I=I+1
1950   END IF
1960 NEXT X
1970 !
1980 !
1990 !
2000 PRINT "Calculating histogram integral nonlinearity error."
2010 Eno=0
2020 FOR X=1 TO Osamples-2
2030   Eno=Eno+Bln(1,X)
2040 NEXT X
2050 Eno=Eno/(Osamples-2)
2060 !
2070 Slope=0
2080 FOR X=1 TO Osamples-2
2090   Slope=Slope+Bln(1,X)
2100 NEXT X
2110 Slope=Slope/(Eno*(Osamples-2))
2120 !
2130 Hmax=-65536
2140 Hmin=65536
2150 FOR X=0 TO Osamples-1
2160   Hln(0,X)=X
2170   Hln(1,X)=0
2180   FOR Y=0 TO X-1
2190     Hln(1,X)=Hln(1,X)+Bln(1,Y)
2200   NEXT Y
2210   Hln(1,X)=(Hln(1,X)-Bln(1,0))/Eno*(1-X)*Slope
2220   IF Hln(1,X)>Hmax THEN
2230     Hmax=Hln(1,X)
2240     Mex3=Hln(0,X)
2250   END IF
2260   IF Hln(1,X)<Hmin THEN
2270     Hmin=Hln(1,X)
2280     Min3=Hln(0,X)
2290   END IF
2300 NEXT X
2310 !
2320 !
2330 !
2340 PRINT "Calculating histogram differential nonlinearity error."
2350 Dmax=-65536
2360 Dmin=65536
2370 Eno=10*2^10/Osamples          ! DAC resolution is 2^10
2380 !                               ! ADC resolution is 2^8
2390 Eno0=Eno/2                     ! ENO for first bin (1/2 the normal)

```

```

2400 En0=3/2*Eno          | EN0 for last bin (3/2 the normal)
2410 FOR X=0 TO Osamples-1 | Differential Nonlinearity Error
2420   Onl(0,X)=X
2430   Onl(1,X)=Bin(1,X)/Eno-1
2440   IF X=0 THEN Onl(1,X)=Bin(1,X)/Eno0-1
2450   IF X=Osamples-1 THEN Onl(1,X)=Bin(1,X)/Eno1-1 | Calculate first bin
2460   IF Onl(1,X)>Omax THEN | Calculate last bin
2470     Omax=Onl(1,X)
2480     Bmax=Onl(0,X)
2490   END IF
2500   IF Onl(1,X)<Omin THEN
2510     Omin=Onl(1,X)
2520     Bmin=Onl(0,X)
2530   END IF
2540 NEXT X
2550 |
2560 |
2570 |
2580 PRINT "Searching for non-monotonic values and missing coda."
2590 Non_monotonic=0      | Non-monotonic error counter
2600 Missing_code=0     | Missing code counter
2610 Prav=0
2620 FOR X=0 TO Samples-1
2630   IF Data(1,X)<Prav THEN | Check for non-monotonicities
2640     Non_monotonic=Non_monotonic+1
2650     Non_mono(0)=Data(0,X) | Stores the last occurrence
2660     Non_mono(1)=Data(1,X)
2670   END IF
2680   Prav=Data(1,X)
2690 NEXT X
2700 |
2710 FOR X=0 TO Osamples-1
2720   IF Bin(1,X)=0 THEN | Check for missing coda
2730     Missing_code=Missing_code+1
2740     Code(0)=Data(0,4*X) | Stores the last occurrence
2750     Code(1)=Bin(0,X)
2760   END IF
2770 NEXT X
2780 |
2790 |
2800 |
2810 Print_results: BEEP
2820 Out$="PRINTER"
2830 OUTPUT 2;Out$;
2840 INPUT "List device (SCREEN/PRINTER):",Out$
2850 IF UPC$(Out$(1,1))="P" THEN PRINTER IS 701
2860 |
2870 Maxform:  IMAGE "      Maximum: ", 30.30, " LSBs at bit ", 30
2880 Minform:  IMAGE "      Minimum: ", 30.30, " LSBs at bit ", 30
2890 |
2900 PRINT TAB(20);"ERROR CALCULATIONS"
2910 IF UPC$(Out$(1,1))="P" THEN
2920   PRINT
2930 ELSE
2940   PRINT CHR$(13B)
2950 END IF
2960 PRINT
2970 PRINT "Input Filanama: ";Infile$
2980 PRINT
2990 PRINT

```



```

3000 Cgain=PROUND(Cgain,-3) ! Round data (3 places)
3010 Coffsat=PROUND(Coffsat,-3)
3020 Alpha=PROUND(Alpha,-5)
3030 Beta=PROUND(Beta,-5)
3040 PRINT "Gain Error: " ;Cgain;"LSBs";TAB(40);"Alpha: " ;Alpha
3050 PRINT "Offsat Error: " ;Coffsat;"LSBs";TAB(40);"Beta: " ;Beta
3060 PRINT
3070 PRINT "End point Integral Nonlinearity Error ----- File: ;iOutfile1$
3080 PRINT USING Maxform;Imax,Max1
3090 PRINT USING Minform;Imin,Min1
3100 PRINT
3110 PRINT "Histogram Integral Nonlinearity Error ----- File: ;iOutfile2$
3120 PRINT USING Maxform;Hmax,Max3
3130 PRINT USING Minform;Hmin,Min3
3140 PRINT
3150 PRINT "Histogram Differential Nonlinearity Error -- File: ;iOutfile3$
3160 PRINT USING Maxform;Dmax,Bmax
3170 PRINT USING Minform;Dmin,Bmin
3180 PRINT
3190 PRINT "Total Error ----- File: ;iOutfile4$
3200 Amax=PROUND(Amax,-3) ! Round data
3210 Amin=PROUND(Amin,-3)
3220 Max2=PROUND(Max2,-4)
3230 Min2=PROUND(Min2,-4)
3240 PRINT " Maximum: ;iAmax;"LSBs at";Max2;"v"
3250 PRINT " Minimum: ;iAmin;"LSBs at";Min2;"v"
3260 PRINT
3270 IF Did THEN PRINT "Did data file, default and count values used:"
3280 Vf=PROUND(Vf,-4)
3290 V1=PROUND(V1,-4)
3300 PRINT Cf;"->";Cf+1;" : " ;Vf;"v";TAB(40);C1-1;"->";C1;" : " ;V1;"v"
3310 |
3320 PRINT
3330 PRINT "Bin 0: ;iBin(1,0);TAB(40);"Bin 255: ;iBin(1,255)
3340 |
3350 IF Non_monotonic THEN
3360 PRINT
3370 PRINT "Non-monotonicity occurred";iNon_monotonic;"times."
3380 Non_mono(0)=PROUND(Non_mono(0),-4)
3390 PRINT "The last occurrence was";iNon_mono(1);"at";iNon_mono(0);"v"
3400 END IF
3410 |
3420 IF Missing_coda THEN
3430 PRINT
3440 PRINT "Missing coda occurred";iMissing_coda;"times."
3450 Coda(0)=PROUND(Coda(0),-4)
3460 PRINT "The last occurrence was";iCode(1);"et about";iCoda(0);"v"
3470 END IF
3480 |
3490 Eject: IF UPCs(Outs[1,1])="P" THEN PRINT CHR$(12)
3500 PRINTER IS 1
3510 |
3520 |
3530 File: |
3540 DN ERROR GDSUB Fila_exists
3550 |
3560 Outfile$=Outfile1$ ! Write end point Integral Error
3570 Records=INT(Dsamples/16)+1
3580 CREATE BOAT Outfile1$,Records
3590 ASSIGN @dfile TO Outfile1$

```

```

3600 OUTPUT @Ofile:Osamples;Inl(*)
3610 ASSIGN @Ofile TO *
3620 !
3630 Outfile$=Outfile2$ ! Write histogram Integral Error
3640 Records=INT((Osamples/16)+1
3650 CREATE BOAT Outfile2$,Records
3660 ASSIGN @Ofile TO Outfile2$
3670 OUTPUT @Ofile:Osamples;HInl(*)
3680 ASSIGN @Ofile TO *
3690 !
3700 Outfile$=Outfile3$ ! Write histogram Differential Err
3710 Records=INT((Osamples)/16)+1
3720 CREATE BOAT Outfile3$,Records
3730 ASSIGN @Ofile TO Outfile3$
3740 OUTPUT @Ofile:Osamples;Onl(*)
3750 ASSIGN @Ofile TO *
3760 !
3770 Outfile$=Outfile4$ ! Write Absolute Error
3780 Records=INT((Samples/16)+1
3790 CREATE BOAT Outfile4$,Records
3800 ASSIGN @Ofile TO Outfile4$
3810 OUTPUT @Ofile:Samples;Abs(*)
3820 ASSIGN @Ofile TO *
3830 GOTO Exit
3840 !
3850 !
3860 File_exists: ! Purge file if it already exists
3870 IF ERRN=54 THEN
3880 PURGE Outfile$
3890 RETURN
3900 ELSE
3910 PRINT CHR$(137);CHR$(130)
3920 PRINT "Error";ERRN;"occured when writing to ";Outfile$
3930 PRINT CHR$(128);CHR$(139)
3940 STOP
3950 ENO IF
3960 !
3970 !
3980 Exit: !
3990 ASSIGN @Ifile TO * ! Close file
4000 !
4010 BEEP
4020 PRINT CHR$(139)
4030 OISP "Program terminated."
4040 !WAIT .75
4050 !OISP "Loading CRUNCH program."
4060 !LOADO "CRUNCH"
4070 ENO

```

```

10 | .....
20 | **      for the 9236          CRUNCH          ver 3.236      **
30 | .....
40 | **
50 | **      This program takes the data file created by ERROR end **
60 | ** streamlines the data by finding the relative maximums end **
70 | ** minimums and throws the rest of the data away. The output **
80 | ** file is 1/4 the size of the input file (256 points compered **
90 | ** to 1024). The output file can be read by PLOT if a graph **
100 | ** is desired. Version 3.0 puts X axis in terms of AOC output. **
110 | **
120 | **      MICHAEL PANKRATZ          13 July 1987          **
130 | **
140 | .....
150 |
160 | OIM In1(1,1024),Out(1,256)
170 |
180 |
190 | PRINTER IS 1
200 | PRINT CHR$(12);          | Clear screen
210 | PRINT TAB(27);CHR$(13B);"CRUNCH ABSOLUTE ERROR DATA"
220 | PRINT
230 | PRINT
240 | PRINT
250 |
260 |
270 | Infile$="ABS_01F2"
280 | Inp1: |
290 | BEEP
300 | ON ERROR GOTO No_file
310 | OUTPUT 2;Infile$;
320 | INPUT "Enter input INL error filename: ",Infile$
330 | ASSIGN @Ifile TO Infile$          | Open input file
340 | OFF ERROR
350 | GOTO Inp2
360 |
370 | No_file: |
380 |     IF ERRN=56 THEN
390 |         PRINT CHR$(137);"File ";Infile$;" does not exist."
400 |         PRINT CHR$(138)
410 |         BEEP
420 |         WAIT .75
430 |         GOTO Inp1
440 |     ELSE
450 |         PRINT CHR$(137);CHR$(130)
460 |         PRINT "Error";ERRN;"occured when opening ";Infile$
470 |         PRINT CHR$(128);CHR$(139)
480 |         STOP
490 |     END IF
500 |
510 |
520 | Inp2: |
530 |     Outfile$="C"&Infile$
540 |     OUTPUT 2;Outfile$;
550 |     INPUT "Enter crunched output filename: ",Outfile$
560 |
570 |
580 | ENTER @Ifile;Samples          | Read input file size
590 | REOIM In1(1,Samples-1)

```

```

500 Samples2=INT(Samples/4)
510 REOIM Out(1,Samples2-1)
520 ENTER @Ifile;Inl(*) | Read in the data
530 ASSIGN @Ifile TO *
540 |
550 |
560 PRINT "Crunching..."
570 FOR I=0 TO Samples2-1
580 Out(1,I)=0
590 FOR J=0 TO 3
700 IF ABS(Inl(1,I+4+J))<ABS(Out(1,I)) THEN Nxt
710 Out(1,I)=Inl(1,I+4+J) | Put max value in 2nd array
720 Out(0,I)=I | Make X axis the ADC output
730 Nxt: NEXT J
740 NEXT I
750 |
760 |
770 Write_data: |
780 ON ERROR GOSUB File_exists
790 Records=INT((Samples2+1)/16)+1
800 CREATE BDAT Outfile$,Records | Create new file
810 ASSIGN @Ofile TO Outfile$
820 OUTPUT @Ofile;Samples2;Out(*) | Write data to file
830 GOTO Exit
840 |
850 File_exists: |
860 IF ERRN=54 THEN
870 PURGE Outfile$
880 RETURN
890 ELSE
900 PRINT CHR$(137);CHR$(130)
910 PRINT "Error ";ERRN;"occured when writing to ";Outfile$
920 PRINT CHR$(128);CHR$(139)
930 STOP
940 ENO IF
950 |
960 |
970 Exit: |
980 PRINT CHR$(139);
990 ASSIGN @Ifile TO * | Close files
1000 ASSIGN @Ofile TO *
1010 BEEP
1020 OISP "Program terminated."
1030 ENO

```

Appendix B

```

*****
*
* SOURCE FILE:   dynrcf8.src
*
* FUNCTION:      Program.
*
* DESCRIPTION:
*
*   This program does A/D conversions in a loop
*   that causes the HC11's ADC to have a sampling
*   rate of 4.0 kHz. The A/D conversions are
*   outputted to PORTB. This result is picked up
*   by the IBM PCXT and is stored in a data file
*   for later processing.
*
*   The A/D configuration is stored in location
*   00. The channel converted is channel one and
*   the result is read from from ADR3 which is
*   found at memory location $1034.
*
*   This program is for use with an 8 MHz crystal
*   on the EVB board.
*
* DOCUMENTATION
* FILES:         None.
*
* ARGUMENTS:    A/D configuration is stored in
*               location 00 prior to execution.
*
* RETURN:       None.
*
* FUNCTIONS
* CALLED:       None.
*
* AUTHOR:       Jeffrey C. Daniels
*
* DATE CREATED: 7-28-87
*
* REVISIONS:    This program was created from
*               dynrc.src.
*
*****

```

```

ADR0   equ $1031
ADR1   equ $1032
ADR2   equ $1033
ADR3   equ $1034
PORTA  equ $1000
PORTB  equ $1004
LOOPNO equ 76

```

	org	\$c400	
	ldaa	\$1039	Power up A/D.
	oraa	#\$80	
	staa	\$1039	
	ldy	#PORTA	Point inx to PORTA
	bset	0,y \$20	
*	ldaa	\$00	Put A/D configuration accumulator A.
CONVERT	staa	\$1030	Initiate conversion.
DELAY	ldx	#LOOPNO	
	dex		Wait for conversion to be completed.
	bne	DELAY	
	ldab	ADR3	
	stab	PORTB	
	bclr	0,y \$20	Send pulse to IBM that data is ready.
	bset	0,y \$20	
	ldx	#\$00	Waste 10 clock cycles.
	ldx	#\$00	
	nop		
	nop		
	bra	CONVERT	

```

*****
*
* SOURCE FILE:   dyrcf8.src
*
* FUNCTION:      Program.
*
* DESCRIPTION:
*
*   This program does A/D conversions in a loop
*   that causes the HC11's ADC to have a sampling
*   rate of 4.0 kHz. The A/D conversions are
*   outputted to PORTB. This result is picked up
*   by the IBM PCXT and is stored in a data file
*   for later processing.
*
*   The A/D configuration is stored in location
*   00. The channel converted is channel one and
*   the result is read from from ADR4 which is
*   found at memory location $1034.
*
*   This program is for use with an 8 MHz crystal
*   on the EVB board.
*
* DOCUMENTATION
* FILES:         None.
*
* ARGUMENTS:    A/D configuration is stored in
*               location 00 prior to execution.
*
* RETURN:       None.
*
* FUNCTIONS
* CALLED:       None.
*
* AUTHOR:       Jeffrey C. Daniels
*
* DATE CREATED: 7-28-87
*
* REVISIONS:    This program was created from
*               dyrc.src.
*
*****

```

```

ADR0   equ $1031
ADR1   equ $1032
ADR2   equ $1033
ADR3   equ $1034
PORTA  equ $1000
PORTB  equ $1004
LOOPNO equ 76

```


	org	\$c500	
	ldaa	\$1039	Power up A/D.
	oraa	#\$c0	
	staa	\$1039	
	ldy	#PORTA	Point inx to PORTA
	bset	0,y \$20	
*	ldaa	\$00	Put A/D configuration accumulator A.
CONVERT	staa	\$1030	Initiate conversion.
DELAY	ldx	#LOOPNO	
	dex		Wait for conversion to be completed.
	bne	DELAY	
	ldab	ADR3	
	stab	PORTB	
	bclr	0,y \$20	Send pulse to IBM that data is ready.
	bset	0,y \$20	
	ldx	#\$00	Waste 10 clock cycles.
	ldx	#\$00	
	nop		
	nop		
	bra	CONVERT	

```

*****
*
* SOURCE FILE:   dynrcf2.src
*
* FUNCTION:     Program.
*
* DESCRIPTION:
*
*   This program does A/D conversions in a loop
*   that causes the HCl1's ADC to have a sampling
*   rate of 4.0 kHz. The A/D conversions are
*   outputted to PORTB. This result is picked up
*   by the IBM PCXT and is stored in a data file
*   for later processing.
*
*   The A/D configuration is stored in location
*   00. The channel converted is channel one and
*   the result is read from from ADR2 which is
*   found at memory location $1033.
*
*   This program is for use with an 2 MHz crystal
*   on the EVB board.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   A/D configuration is stored in
*              location 00 prior to execution.
*
* RETURN:     None.
*
* FUNCTIONS
* CALLED:     None.
*
* AUTHOR:     Jeffrey C. Daniels
*
* DATE CREATED: 7-28-87
*
* REVISIONS:   This program was created from
*              dynrc.src.
*
*****

```

```

ADR0   equ $1031
ADR1   equ $1032
ADR2   equ $1033
ADR3   equ $1034
PORTA  equ $1000
PORTB  equ $1004
LOOPNO equ 15

```

	org	\$c600	
	ldaa	\$1039	Power up A/D.
	oraa	#\$80	
	staa	\$1039	
	ldy	#PORTA	Point inx to PORTA
	bset	0,y \$20	
	ldx	#LOOPNO	Put delay loop length
	stx	\$01	at locations 01 and 02.
*	ldaa	\$00	Put A/D configuration
			accumulator A.
CONVERT	staa	\$1030	Initiate conversion.
	ldx	\$01	
DELAY	dex		Wait for conversion to
	bne	DELAY	be completed.
	ldab	ADR2	
	stab	PORTB	
	bclr	0,y \$20	Send pulse to IBM that
	bset	0,y \$20	data is ready.
	bra	CONVERT	

*

* SOURCE FILE: dyrcf2.src

*

* FUNCTION: Program.

*

* DESCRIPTION:

*

* This program does A/D conversions in a loop
* that causes the HC11's ADC to have a sampling
* rate of 4.0 kHz. The A/D conversions are
* outputed to PORTB. This result is picked up
* by the IBM PCXT and is stored in a data file
* for later processing.

*

* The A/D configuration is stored in location
* 00. The channel converted is channel one and
* the result is read from from ADR2 which is
* found at memory location \$1033.

*

* This program is for use with an 2 MHz crystal
* on the EVB board.

*

* DOCUMENTATION

* FILES: None.

*

* ARGUMENTS: A/D configuration is stored in
* location 00 prior to execution.

*

* RETURN: None.

*

* FUNCTIONS

* CALLED: None.

*

* AUTHOR: Jeffrey C. Daniels

*

* DATE CREATED: 7-28-87

*

* REVISIONS: This program was created from
* dyrc.src.

*

ADR0 equ \$1031
ADR1 equ \$1032
ADR2 equ \$1033
ADR3 equ \$1034
PORTA equ \$1000
PORTB equ \$1004
LOOPNO equ 15

	org	\$c700	
	ldaa	\$1039	Power up A/D.
	oraa	#\$c0	
	staa	\$1039	
	ldy	#PORTA	Point inx to PORTA
	bset	0,y \$20	
	ldx	#LOOPNO	Put delay length at
	stx	\$01	locations 01 and 02.
*	ldaa	\$00	Put A/D configuration
			accumulator A.
CONVERT	staa	\$1030	Initiate conversion.
	ldx	\$01	
DELAY	dex		Wait for conversion to
	bne	DELAY	be completed.
	ldab	ADR3	
	stab	PORTB	
	bclr	0,y \$20	Send pulse to IBM that
	bset	0,y \$20	data is ready.
	bra	CONVERT	

GETDAT.EXE Make File

```
getdat.obj : getdat.c local.h  
            msc getdat;  
  
getdat.exe : getdat.obj  
            link/stack:5000 getdat;
```

DYHIS.EXE Make File

```
dyhis.obj : dyhis.c local.h  
           msc dyhis;  
  
dyhis.exe : dyhis.obj  
           link dyhis;
```

DYFFT.EXE Make File

```
cadd.obj : cadd.c complex.h  
          msc/AL cadd;  
  
csub.obj : csub.c complex.h  
          msc/AL csub;  
  
cmult.obj : cmult.c complex.h  
           msc/AL cmult;  
  
cdiv.obj : cdiv.c complex.h  
          msc/AL cdiv;  
  
cexpon.obj : cexpon.c complex.h  
           msc/AL cexpon;  
  
cmplx.obj : cmplx.c complex.h  
           msc/AL cmplx;  
  
cneg.obj : cneg.c complex.h  
          msc/AL cneg;  
  
cmag.obj : cmag.c complex.h  
          msc/AL cmag;  
  
cmagsq.obj : cmagsq.c complex.h  
            msc/AL cmagsq;
```

```

cmath.lib : cmagsq.obj cmag.obj cneg.obj cmplx.obj \
           cexpon.obj cdiv.obj cmult.obj csub.obj \
           cadd.obj
           lib cmath-+cadd;
           lib cmath-+csub;
           lib cmath-+cmult;
           lib cmath-+cdiv;
           lib cmath-+cexpon;
           lib cmath-+cmplx;
           lib cmath-+cneg;
           lib cmath-+cmag;
           lib cmath-+cmagsq;

fft.obj : fft.c cmath.h complex.h local.h
         msc/AL fft;

normal.obj : normal.c complex.h local.h
           msc/AL normal;

window.obj : window.c cmath.h complex.h local.h
           msc/AL window;

dyfft.obj : dyfft.c cmath.h complex.h local.h
           msc/AL dyfft;

dyfft.exe : dyfft.obj normal.obj window.obj fft.obj cmath.lib
           link dyfft normal window fft,,cmath.lib;

```

HARMON1.EXE Make File

```

cadd.obj : cadd.c complex.h
         msc/AL cadd;

csub.obj : csub.c complex.h
         msc/AL csub;

cmult.obj : cmult.c complex.h
         msc/AL cmult;

cdiv.obj : cdiv.c complex.h
         msc/AL cdiv;

cexpon.obj : cexpon.c complex.h
         msc/AL cexpon;

cmplx.obj : cmplx.c complex.h
         msc/AL cmplx;

cneg.obj : cneg.c complex.h
         msc/AL cneg;

```

```

cmag.obj : cmag.c complex.h
          msc/AL cmag;

cmagsq.obj : cmagsq.c complex.h
           msc/AL cmagsq;

cmath.lib : cmagsq.obj cmag.obj cneg.obj cmplx.obj \
           cexpon.obj cdiv.obj cmult.obj csub.obj \
           cadd.obj
           lib cmath-+cadd;
           lib cmath-+csub;
           lib cmath-+cmult;
           lib cmath-+cdiv;
           lib cmath-+cexpon;
           lib cmath-+cmplx;
           lib cmath-+cneg;
           lib cmath-+cmag;
           lib cmath-+cmagsq;

fft.obj : fft.c cmath.h complex.h local.h
        msc/AL fft;

window.obj : window.c cmath.h complex.h local.h
          msc/AL window;

harmonl.obj : harmonl.c local.h cmath.h complex.h
           msc/AL harmonl;

harmonl.exe : harmonl.obj fft.obj window.obj cmath.lib
            link harmonl fft window,,cmath.lib;

```

QNTZ1.EXE Make File

```

cadd.obj : cadd.c complex.h
          msc/AL cadd;

csub.obj : csub.c complex.h
          msc/AL csub;

cmult.obj : cmult.c complex.h
           msc/AL cmult;

cdiv.obj : cdiv.c complex.h
          msc/AL cdiv;

cexpon.obj : cexpon.c complex.h
           msc/AL cexpon;

cmplx.obj : cmplx.c complex.h
           msc/AL cmplx;

```



```

cneg.obj : cneg.c complex.h
          msc/AL cneg;

cmag.obj : cmag.c complex.h
          msc/AL cmag;

cmagsq.obj : cmagsq.c complex.h
            msc/AL cmagsq;

cmath.lib : cmagsq.obj cmag.obj cneg.obj cmplx.obj \
            cexpon.obj cdiv.obj cmult.obj csub.obj \
            cadd.obj
            lib cmath-+cadd;
            lib cmath-+csub;
            lib cmath-+cmult;
            lib cmath-+cdiv;
            lib cmath-+cexpon;
            lib cmath-+cmplx;
            lib cmath-+cneg;
            lib cmath-+cmag;
            lib cmath-+cmagsq;

fft.obj : fft.c cmath.h complex.h local.h
          msc/AL fft;

window.obj : window.c cmath.h complex.h local.h
            msc/AL window;

qntzl.obj : qntzl.c local.h cmath.h complex.h
            msc/AL qntzl;

qntzl.exe : qntzl.obj fft.obj window.obj cmath.h
            link qntzl fft window,,cmath.lib;

```

```

/*****
*
* SOURCE FILE:   getfft.c
*
* FUNCTION:     main program
*
* DESCRIPTION:  This program receives the data for the
*              fft and histogram tests for dynamic
*              testing from the ppi in IBM PCXT.
*              Various information is prompted from
*              the user and all information is then
*              stored in a user specified files in
*              binary format for later processing.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   None.
*
* RETURN:      Binary files containing all valid
*              information.
*
* FUNCTIONS
* CALLED:      None.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 8-3-87
*
* REVISIONS:   8-3-87 This program was created from
*              getfft.c and getthis.c.
*
*****/

```

```

#include <stdio.h>
#include <conio.h>
#include "local.h"

int configuration,
    num_pts = NUM_DFT_POINTS;

int intdata[ NUM_DFT_POINTS ];

char filename[ STRING_LEN ],
    mode[ MODE_LEN ],
    chip_number[ CHIP_NO_LEN ],
    date[ DATE_LEN ],
    lot_number[ LOT_NO_LEN ];

float inp_float;

```

```

double samp_freq,
      clock_freq,
      hist[RESOLUTION];

FILE *out_file;

main()
{
    register i,j;
    unsigned char data[NUM_DFT_POINTS];

/* Set up ppi communications.                                     */
    outp(CONTROL,PPI_CONFIG);

/******
/* Enter data information.                                     */
/******

/* Enter the date.                                           */

    printf("\n\n\n\n\n\n\n\n\n\n\n\n\n\n\n\n");
    puts("Enter the date is this form - - ");
    puts("mm-dd-yy");
    scanf("%s",date);
    printf("The date is: %s\n\n\n",date);

/* Enter chip number.                                         */

    puts("Enter the chip number of the hc11");
    scanf("%s",chip_number);
    printf("The chip number is : %s\n\n\n",
           chip_number);

/* Enter lot number of HC11.                                  */

    puts("Enter the lot number of the HC11");
    scanf("%s",lot_number);
    printf("The lot number is : %s\n\n\n",
           lot_number);

/* Enter the clock frequency.                                 */

    puts("Enter the clock frequency for the");
    puts(" test system in MHz.");
    scanf("%e",&inp_float);
    clock_freq = (double)inp_float;
    printf("The clock frequency is: %f\n\n\n",
           clock_freq);

```

```

/* Enter the sampling frequency.          */
puts("Enter the sampling frequency of the HC11");
puts("in Hertz.");
scanf("%e",&inp_float);
samp_freq = (double)inp_float;
printf("The sampling freq. is: %f\n\n",
       samp_freq);

FOREVER
{
/* Enter the mode of the HC11.          */
puts("Enter the mode of the HC11.");
puts("An example - - 00");
scanf("%s",mode);
printf("The mode is: %s\n\n",mode);

/* Take data.                          */
puts("Set up fft input sine wave and hit ");
puts("RETURN to start data acquisition.\n");

getch();

/* Throw out 10 samples.                */
for ( i = 0; i < 10; i++ )
    inp(PORTB);

/* Take valid data.                    */
for( i = -1; i++ < NUM_DFT_POINTS;)
    {
        while( ! (0x01 & (int)inp(PORTA) ))
            ;
        data[i] = inp(PORTB);
    }

puts("Some data");
for ( i = 0; i < 20; i++ )
    printf("%i\n",(int)data[i]);
printf("\n\n\n");

```

```

/* Enter output filename. */
    puts("Enter the fft output data filename.");
    puts("An example is: INRC01P8.OUT");
    scanf("%s",filename);
    printf("The output filename is: %s\n\n\n",
           filename);

/* Convert data from character to integer. */
    for ( i = 0; i < NUM_DFT_POINTS; i++ )
        intdata[i] = (int)data[i];

/* Write out data and information to output */
/* file in binary format. */
    out_file = fopen(filename,"w+b");

    fwrite(date,sizeof(char),DATE_LEN,out_file);

    fwrite(chip_number,sizeof(char),CHIP_NO_LEN,
           out_file);

    fwrite(lot_number,sizeof(char),LOT_NO_LEN,
           out_file);

    fwrite(mode,sizeof(char),MODE_LEN,out_file);

    fwrite((char *)&clock_freq,sizeof(double),1,
           out_file);

    fwrite((char *)&samp_freq,sizeof(double),1,
           out_file);

    fwrite((char *)&num_pts,sizeof(int),1,
           out_file);

    fwrite((char *)intdata,sizeof(int),
           NUM_DFT_POINTS,out_file);

    fclose(out_file);

/*****
/* Take histogram data. */
*****/
    puts("Set up histogram input sine wave and hit");
    puts("RETURN to start data acquisition.\n\n\n");

    getch();

```

```

/* Zero out histogram array */
    for( i = 0; i < RESOLUTION; i++ )
        hist[i] = 0.0;

/* Throw out 10 samples. */
    for ( i = 0; i < 10; i++ )
        inp(PORTB);

/* Take valid data. */
    for( j = 0; j < ( NUM_HIS_POINTS / LOOP_SIZE );
        j++ )
    {
        printf(" %i",j);
        for( i = -1; i++ < LOOP_SIZE; )
        {
            while( ! (0x01 & (int)inp(PORTA) ))
                ;
            data[i] = inp(PORTB);
        }

        for( i = 0; i < LOOP_SIZE; i++ )
        {
            hist[(int)data[i]] = hist[(int)data[i]] + 1;
        }
    }

    puts("Some data");
    for ( i = 0; i < RESOLUTION; i++ )
        printf("%i %f\n",i,hist[i]);

/* Enter output filename. */
    puts("Enter the histogram output data filename.");
    puts("An example is: hnrc01f8.out");
    scanf("%s",filename);
    printf("The output filename is: %s\n\n",filename);

/* Write out data and information to output */
/* file in binary format. */
    out_file = fopen(filename,"w+b");

    fwrite(date,sizeof(char),DATE_LEN,out_file);

    fwrite(chip_number,sizeof(char),CHIP_NO_LEN,
           out_file);

```

```
fwrite(lot_number, sizeof(char), LOT_NO_LEN,  
      out_file);  
fwrite(mode, sizeof(char), MODE_LEN, out_file);  
fwrite((char *)&clock_freq, sizeof(double), 1,  
      out_file);  
fwrite((char *)&samp_freq, sizeof(double), 1,  
      out_file);  
fwrite((char *)&num_pts, sizeof(int), 1,  
      out_file);  
fwrite((char *)hist, sizeof(double),  
      RESOLUTION, out_file);  
  
fclose(out_file);  
  
}  
  
exit(0);  
  
}
```

```

/*****
*
* SOURCE FILE:   dyhis.c
*
* FUNCTION:     main()
*
* DESCRIPTION:  This program reads in the data and
*               information taken in a dynamic histogram
*               test of the hcl1 ADC.  The data
*               manipulated with methods described by
*               Doerfler.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   None.
*
* RETURN:      ascii file containing data and
*               information
*
* FUNCTIONS
* CALLED:      none.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-30-87
*
* REVISIONS:   None.
*
*****/

```

```

#include <stdio.h>
#include <conio.h>
#include <math.h>
#include "local.h"

char in_filename[STRING_LEN],
     out_filename[STRING_LEN],
     mode[MODE_LEN],
     chip_number[CHIP_NO_LEN],
     date[DATE_LEN],
     lot_number[LOT_NO_LEN];

double samp_freq,
        fund_freq,
        clock_freq,
        max_mag;

```



```

double hist[RESOLUTION],
       voltage[RESOLUTION],
       diff[RESOLUTION],
       cum_his,
       lsb;

int num_pts;

FILE *in_file,
     *out_file;

main()
{
    register i;

    puts("\n\nEnter the input filename.");
    scanf("%s",in_filename);

    /* Open file to read in data, stop program if
    /* file cannot be opened.

    if(( in_file = fopen(in_filename,"r+b")) == NULL )
    {
        printf("\n\n %s could not be opened or doesn't",
               " exist.\n\n",in_filename);
        exit(1);
    }

    /* Read in data and information.

    fread(date,sizeof(char),DATE_LEN,in_file);
    printf("date = %s\n\n",date);

    fread(chip_number,sizeof(char),CHIP_NO_LEN,
           in_file);
    printf("The chip number is %s\n\n",chip_number);

    fread(lot_number,sizeof(char),LOT_NO_LEN,in_file);
    printf("The lot number is %s\n\n",lot_number);

    fread(mode,sizeof(char),MODE_LEN,in_file);
    printf("The mode is %s\n\n",mode);

    fread((char *)&clock_freq,sizeof(double),1,in_file);
    printf("clock_freq is %f\n\n",clock_freq);

    fread((char *)&samp_freq,sizeof(double),1,in_file);
    printf("samp_freq = %f\n\n",samp_freq);

    fread((char *)&num_pts,sizeof(int),1,in_file);
    printf("num_pts = %i\n\n",num_pts);

```

```

    fread((char *)hist, sizeof(double), num_pts, in_file);

/* For this algorithm the amplitude of the input */
/* waveform is normalized to fall between -1 and */
/* 1 volts. */

    lsb = 2.0 / pow( (double)2, (double) NUM_BITS);

    cum_his = hist[0];
    voltage[0] = -cos(PI * cum_his / NUM_HIS_POINTS);

    for ( i = 1; i < RESOLUTION; i++ )
    {
        cum_his = cum_his + hist[i];
        voltage[i] = -cos( PI * cum_his
            / NUM_HIS_POINTS );
        diff[i-1] = ( voltage[i] - voltage[i-1] )
            / lsb - 1;
    }

/* Write information and data to output file. */

    printf("\n\nThe input filename was: %s\n\n",
        in_filename);

    puts("\n\nEnter the filename for the ");
    puts("histogram data.");
    puts("\n\nAn example - - a:hnr01f8. \n\n");
    scanf("%s", out_filename);

    out_file = fopen(out_filename, "w");

    fprintf(out_file, "%s %iHz %s %s\n",
        out_filename, (int)(samp_freq),
        chip_number, lot_number);

    for ( i = 0; i < RESOLUTION; i++ )
        fprintf(out_file, "%i %f \n", i, hist[i]);
    fclose(in_file);
    fclose(out_file);

    puts("\n\nEnter the filename for the ");
    puts("output data.");
    puts("\n\nAn example - - a:dnr01f8. \n\n");
    scanf("%s", out_filename);

    out_file = fopen(out_filename, "w");

    fprintf(out_file, "%s %iHz %s %s\n",
        out_filename, (int)(samp_freq),
        chip_number, lot_number);

```

```
for ( i = 0; i < RESOLUTION; i++ )  
    fprintf(out_file,"%i %f \n",i,diff[i]);  
fclose(in_file);  
fclose(out_file);  
exit(0);  
}
```

```

/*****
*
* SOURCE FILE:   dyfft.c
*
* FUNCTION:      main()
*
* DESCRIPTION:   This program reads in the data and
*                information taken in a dynamic test of
*                the hc11 ADC. The data is first
*                normalized to a range between 0 and 1,
*                windowed with a Von Honn window, taken
*                through a fast fourier transform, and
*                then the log magnitude is taken. This
*                final result is then placed into an
*                output file to be plotted.
*
* DOCUMENTATION
* FILES:         None.
*
* ARGUMENTS:     None.
*
* RETURN:        ascii file containing data and
*                information
*
* FUNCTIONS
* CALLED:        normalize_data();
*                window_data();
*                fft();
*
* AUTHOR:        Jeffrey C. Daniels
*
* DATE CREATED:  6-9-87
*
* REVISIONS:     None.
*
*****/

#include <stdio.h>
#include <conio.h>
#include <math.h>
#include "cmath.h"
#include "complex.h"
#include "local.h"

DCOMPLEX input_data[ NUM_DFT_POINTS ],
          trans_data[ NUM_DFT_POINTS ],
          z[ NUM_DFT_POINTS ]; /* COMPLEX work array */

int data[ NUM_DFT_POINTS ];

```

```

char in_filename[STRING_LEN],
    out_filename[STRING_LEN],
    mode[MODE_LEN],
    chip_number[CHIP_NO_LEN],
    date[DATE_LEN],
    lot_number[LOT_NO_LEN];

double freqs[NUM_DFT_POINTS];

double samp_freq,
    fund_freq,
    clock_freq,
    max_mag;

int num_pts,
    act_len;

FILE *in_file,
    *out_file;

main()
{
    register i;

    puts("\n\nEnter the input filename.");
    scanf("%s",in_filename);

    /* Open file to read in data, stop program if      */
    /* file cannot be opened.                          */

    if(( in_file = fopen(in_filename,"r+b")) == NULL )
    {
        printf("%s could not be opened or doesn't",
            " exist.\n\n",in_filename);
        exit(1);
    }

    /* Read in data and information.                    */

    fread(date,sizeof(char),DATE_LEN,in_file);
    printf("date = %s\n\n",date);

    fread(chip_number,sizeof(char),CHIP_NO_LEN,
        in_file);
    printf("The chip number is %s\n\n",chip_number);

    fread(lot_number,sizeof(char),LOT_NO_LEN,in_file);
    printf("The lot number is %s\n\n",lot_number);

    fread(mode,sizeof(char),MODE_LEN,in_file);
    printf("The mode is %s\n\n",mode);

```

```

    fread((char *)&clock_freq,sizeof(double),1,in_file);
    printf("clock_freq is %f\n\n",clock_freq);

    fread((char *)&samp_freq,sizeof(double),1,in_file);
    printf("samp_freq = %f\n\n",samp_freq);

    fread((char *)&num_pts,sizeof(int),1,in_file);
    printf("num_pts = %i\n\n",num_pts);

    fread((char *)data,sizeof(int),num_pts,in_file);
    puts("some data");
    for( i = 0; i < 20; i++)
        printf("%i\n",data[i]);

/* Transform data from integer to                */
/* complex array.                                */

    for ( i = 0; i < num_pts; i++ )
        input_data[i] = cmplx((double)data[i],0.0);

/* Normalize data between to an lsb.            */
puts("Normalizing data.");
    normalize_data( input_data,trans_data,num_pts );

/* Window the input data.                        */
puts("Windowing data");
    window_data( trans_data, num_pts );

/* Perform fast fourier transform.              */
puts("Performing fft");
    act_len = fft( trans_data, trans_data,
                  num_pts, DFT_N);

/* Find the log magnitude of frequency data.    */
puts("Finding magnitude of data.");
    max_mag = 0.0;

/* Take out dc offset.                          */

    trans_data[0].re = 1e-4;
    trans_data[1].re = 1e-4;
    trans_data[2].re = 1e-4;

    trans_data[0].im = 0.0;
    trans_data[1].im = 0.0;
    trans_data[2].im = 0.0;

    for ( i = 3; i < act_len / 2; i++ )

```

```

{
    trans_data[i].re = cmag( trans_data[i]);
    trans_data[i].im = 0.0;

    if ( trans_data[i].re < 1e-5 )
        trans_data[i].re = 1e-5;

    if ( trans_data[i].re > max_mag )
    {
        max_mag = trans_data[i].re;
        printf("max_mag = %f at pt. %i\n",max_mag,i);
    }
}

/* Convert results to dBs and produce          */
/* frequency array.                            */

fund_freq = samp_freq / act_len;

puts("Finding dBs.");
for ( i = 0; i < act_len / 2; i++ )
{
    trans_data[i].re = 20.0
        * log10(trans_data[i].re / max_mag);
    freqs[i] = (double)i * fund_freq;
}

/* Write information and data to output file.  */

printf("\n\nThe input filename was: %s\n\n",
        in_filename);

puts("\n\nEnter the filename for the ");
puts("output data.");
puts("\n\nAn example - - a:data.out \n\n");
scanf("%s",out_filename);

out_file = fopen(out_filename,"w");

fprintf(out_file,"%s %iHz %s %s\n",
        out_filename,(int)(samp_freq),
        chip_number,lot_number);

for ( i = 0; i < act_len / 2; i++ )
    fprintf(out_file,"%f %f %i\n",freqs[i],
        trans_data[i].re,i);

fclose(in_file);
fclose(out_file);

exit(0);
}

```

```

/*****
*
* SOURCE FILE:   normal.c
*
* FUNCTION:     VOID normalize_data(x,y,num_pts)
*
* DESCRIPTION:  This function normalizes data from an
*              ADC to the range between 0 and 1.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   x - DCOMPLEX * - pointer to complex array
*
*              y - DCOMPLEX * - pointer to complex array
*
*              num_pts - int - number of points in
*                      the arrays
*
* RETURN:      None.
*
* FUNCTIONS
* CALLED:      None.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-9-87
*
* REVISIONS:   None.
*
*****/

```

```

#include <math.h>
#include "complex.h"
#include "local.h"

VOID normalize_data(x,y,num_pts)
DCOMPLEX *x,
          *y;

int num_pts;
{
    register i;
    double lsb;
    lsb = (VHIGH - VLOW) / pow( (double)2, (double)NUM_BITS);
    for ( i = 0; i < num_pts; i++ )
    {
        y[i].re = x[i].re * lsb;
        y[i].im = 0.0;
    }
    return;
}

```



```

/*****
*
* SOURCE FILE:   window.c
*
* FUNCTION:      VOID window_data( x, num_pts )
*
* DESCRIPTION:   This function windows data in the array
*                x with a Von Hann window.
*
* DOCUMENTATION
* FILES:         None.
*
* ARGUMENTS:     x - DCOMPLEX * - pointer to complex array
*
*                num_pts - int - number of points in the
*                            window
*
* RETURN:        None.
*
* FUNCTIONS
* CALLED:        None.
*
* AUTHOR:        Jeffrey C. Daniels
*
* DATE CREATED:  6-9-87
*
* REVISIONS:     None.
*
*****/

```

```

*****/
#include <math.h>
#include "cmath.h"
#include "complex.h"
#include "local.h"

extern DCOMPLEX z [NUM_DFT_POINTS];

VOID window_data( x, num_pts )
DCOMPLEX *x;
int num_pts;

{
    register i;
    double multiplier;

/* Create a Von Hann window.                                     */

    for( i = 0; i < num_pts; i++ )
    {
        multiplier = 0.5 * ( 1.0 -
                             cos(2.0 * PI * i / num_pts ));
        z[i].re = multiplier;
    }
}

```

```
    z[i].im = multiplier;
}

/* Now multiply data by the window.                */
for ( i = 0; i < num_pts; i++ )
    x[i] = cmult(x[i],z[i]);
return;
}
```

```

/*****
*
* SOURCE FILE:   fft.c
*
* FUNCTION:      int fft(x,y,n,inverse)
*                DCOMPLEX *x,
*                *y;
*                int n,inverse;
*
* DESCRIPTION:   This function performs the decimation in
*                frequency fast fourier transform.
*
* DOCUMENTATION
* FILES:        None.
*
* ARGUMENTS:    x  - - pointer to DCOMPLEX input array
*                y  - - pointer to DCOMPLEX output array
*                n  - - the desired length of the DFT
*                   ( or inverse DFT ) to be performed.
*                inverse - - a flag to indicate whether
*                   a forward DFT or an inverse DFT
*                   is to be performed
*
*                equal to:   DFT      : forward DFT ( with
*                               multiplier of 1 )
*                               DFT_N   : forward DFT ( with
*                               multiplier of 1/n )
*                               IDFT    : inverse DFT ( with
*                               multiplier of 1 )
*                               IDFT_N  : inverse IDFT ( with
*                               multiplier of 1/n )
*
* RETURN:       actual length of the DFT ( IDFT ) performed
*                If the desired length, n, is an integer
*                power of 2, then the actual length is
*                equal to n.  Otherwise, the actual length
*                is the largest integer power of 2 which is
*                less than n.
*
* FUNCTIONS
* CALLED:       DCOMPLEX cexpon();
*
* AUTHOR:       Jeffrey C. Daniels
*
* DATE CREATED: 6-3-87
*
* REVISIONS:    None.
*
*****/

```

```

#include <math.h>
#include "cmath.h"
#include "complex.h"
#include "local.h"

extern DCOMPLEX z[NUM_DFT_POINTS];

int fft(x,y,n,inverse)
    DCOMPLEX *x,
    *y;
    int n,inverse;
{
    int dft_length,i,iter_num,
        j,k,l,length,
        m,num_blocks,
        offset,sign;

    double mult_fac,theta;

    DCOMPLEX tempc;

    /* Find actual length of the DFT or IDFT to be performed. */
    length = 2;
    while ( length < n )
        length = length * 2;

    if ( length != n )
        length = length / 2;

    /* Determine whether DFT or IDFT and also the          */
    /* multiplication factor.                               */
    switch ( inverse )
    {
        case DFT_N:
            sign = 1;
            mult_fac = 1.0 / (double)length;
            break;
        case IDFT:
            sign = -1;
            mult_fac = 1.0;
            break;
        case DFT:
            sign = 1;
            mult_fac = 1.0;
            break;
        default:
            sign = -1;
            mult_fac = 1.0 / (double)length;
    }
}

```

```

/* Copy input array into output array if the pointers */
/* are not to the same array. */

    if ( x != y )
        for ( i = 0; i < length ; i++ )
            y[i] = x[i];

/* Initialize variables */

    offset = 0;
    iter_num = 0;
    dft_length = length;

/* Now perform the DFT or IDFT */

    while ( length >= 2 )
    {
        num_blocks = (int)pow( (double)2.0, (double)iter_num );
        iter_num = iter_num + 1;
        length = length / 2;
        offset = 0;

        for ( i = 1; i <= num_blocks; i++ )
        {
            for ( j = 0; j < length; j++ )
            {
                m = j + offset;
                z[m] = cadd( y[m], y[m+length] );
                z[m + length] = cmult( csub( y[m], y[m + length] ),
                                     cexpon( -(double)sign * PI
                                              * (double)j
                                              / (double)length ));
            }
            offset = length * 2 + offset;
        }
        for ( i = 0; i < dft_length; i++ )
            y[i] = z[i];
    }

/* Now unscramble the DFT ( or IDFT ) coefficients */

    j = 0;
    for ( i = 0; i <= dft_length - 2; i++ )
    {
        if ( i < j )
        {
            tempc = y[j];
            y[j] = y[i];
            y[i] = tempc;
        }

        k = dft_length / 2 ;
    }

```

```

while ( k <= j )
{
    j = j - k;
    k = k / 2;
}

j = j + k;

/* Now multiply by the multiplication factor */
for ( i = 0; i <= dft_length - 1; i++ )
    y[i] = cmult( y[i], cmplx(mult_fac,0.0) );
return(dft_length);
}

```

```

/*****
*
* SOURCE FILE:   cadd.c
*
* FUNCTION:     DCOMPLEX cadd(x,y)
*               DCOMPLEX x,y;
*
* DESCRIPTION:  This function performs the addition of
*               the two DCOMPLEX numbers x and y.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   x - DCOMPLEX number
*               y - DCOMPLEX number
*
* RETURN:      result of the DCOMPLEX addition
*               of x and y
*
* FUNCTIONS
* CALLED:      None.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-2-87
*
* REVISIONS:   None.
*
*****/

```

```
#include "complex.h"
```

```

DCOMPLEX cadd(x,y)
DCOMPLEX x,y;

{
    DCOMPLEX z;

    z.re = x.re + y.re;
    z.im = x.im + y.im;

    return(z);
}

```

```

/*****
*
* SOURCE FILE:   csub.c
*
* FUNCTION:     DCOMPLEX csub(x,y)
*               DCOMPLEX x,y;
*
* DESCRIPTION:  This function performs the subtraction
*               of the two DCOMPLEX numbers x and y.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   x - DCOMPLEX number
*               y - DCOMPLEX number
*
* RETURN:      result of the DCOMPLEX subtraction of
*               x and y
*
* FUNCTIONS
* CALLED:      None.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-2-87
*
* REVISIONS:   None.
*****/

```

```

#include "complex.h"

DCOMPLEX csub(x,y)
DCOMPLEX x,y;

{
  DCOMPLEX z;

  z.re = x.re - y.re;
  z.im = x.im - y.im;

  return(z);
}

```



```

/*****
*
* SOURCE FILE:   cdiv.c
*
* FUNCTION:     DCOMPLEX cdiv(x,y)
*               DCOMPLEX x,y;
*
* DESCRIPTION:  This function performs the division of
*               the two DCOMPLEX numbers x and y.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   x - DCOMPLEX number
*               y - DCOMPLEX number
*
* RETURN:      result of the DCOMPLEX division of
*               x and y
*
* FUNCTIONS
* CALLED:      None.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-2-87
*
* REVISIONS:   None.
*****/

```

```
#include "complex.h"
```

```
DCOMPLEX cdiv(x,y)
```

```
DCOMPLEX x,y;
```

```
{
```

```
DCOMPLEX z;
```

```

z.re = ( x.re * y.re + x.im * y.im )
        / ( y.re * y.re + y.im * y.im );
z.im = ( x.im * y.re - x.re * y.im )
        / ( y.re * y.re + y.im * y.im );

```

```
return(z);
```

```
}
```

```

/*****
*
* SOURCE FILE:   cexpon.c
*
* FUNCTION:     DCOMPLEX cexpon(theta)
*               double theta;
*
* DESCRIPTION:  This function performs the operation of
*               exp(j * theta).
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   theta - double
*
* RETURN:      the DCOMPLEX number exp( j * theta)
*
* FUNCTIONS
* CALLED:      None.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-2-87
*
* REVISIONS:   None.
*
*****/

```

```

#include <math.h>
#include "complex.h"

DCOMPLEX cexpon(theta)
double theta;

{
    DCOMPLEX z;

    z.re = cos(theta);
    z.im = sin(theta);

    return(z);
}

```

```

/*****
*
* SOURCE FILE:   cmplx.c
*
* FUNCTION:     DCOMPLEX cmplx(x,y)
*              double x,y;
*
* DESCRIPTION:  This function makes a DCOMPLEX number
*              from the two double numbers x and y.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   x - double number
*              y - double number
*
* RETURN:      the DCOMPLEX number x + jy
*
* FUNCTIONS
* CALLED:      None.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-2-87
*
* REVISIONS:   None.
*
*****/

```

```

*****/

```

```

#include "complex.h"

DCOMPLEX cmplx(x,y)
double x,y;

{
    DCOMPLEX z;

    z.re = x;
    z.im = y;

    return(z);
}

```

```

/*****
*
* SOURCE FILE:   cneg.c
*
* FUNCTION:     DCOMPLEX cneg(x)
*               DCOMPLEX x;
*
* DESCRIPTION:  This function performs the negation of
*               the DCOMPLEX number x.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   x - DCOMPLEX number
*
* RETURN:      result of the negation of x
*
* FUNCTIONS
* CALLED:      None.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-2-87
*
* REVISIONS:   None.
*
*****/

```

```
#include "complex.h"
```

```
DCOMPLEX cneg(x)
DCOMPLEX x;
```

```
{
    DCOMPLEX z;

    z.re = - x.re;
    z.im = - x.im;

    return(z);
}
```

```

/*****
*
* SOURCE FILE:   cmag.c
*
* FUNCTION:     double cmag(x)
*              DCOMPLEX x;
*
* DESCRIPTION:  This function finds the magnitude of the
*              DCOMPLEX number x.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   x - DCOMPLEX number
*
* RETURN:      double - the magnitude of x
*
* FUNCTIONS
* CALLED:      None.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-2-87
*
* REVISIONS:   None.
*
*****/

```

```

#include <math.h>
#include "complex.h"

double cmag(x)
DCOMPLEX x;
{
    double z;

    z = sqrt( x.re * x.re + x.im * x.im );

    return(z);
}

```

```

/*****
*
* SOURCE FILE:   cmagsq.c
*
* FUNCTION:     double cmagsq(x)
*               DCOMPLEX x;
*
* DESCRIPTION:  This function finds the magnitude squared
*               of the DCOMPLEX number x.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   x - DCOMPLEX number
*
* RETURN:      double - the magnitude squared of x
*
* FUNCTIONS
* CALLED:      None.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-2-87
*
* REVISIONS:   None.
*
*****/

```

```

#include "complex.h"

double cmagsq(x)
DCOMPLEX x;

{
    double z;

    z = x.re * x.re + x.im * x.im;

    return(z);
}

```

```

/*****
*
* SOURCE FILE:   cmult.c
*
* FUNCTION:     DCOMPLEX cmult(x,y)
*               DCOMPLEX x,y;
*
* DESCRIPTION:  This function performs the multiplication
*               of the two DCOMPLEX numbers x and y.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   x - DCOMPLEX number
*               y - DCOMPLEX number
*
* RETURN:      result of the DCOMPLEX multiplication of
*               x and y
*
* FUNCTIONS
* CALLED:      None.
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-2-87
*
* REVISIONS:   None.
*****/

```

```

#include "complex.h"

DCOMPLEX cmult(x,y)
DCOMPLEX x,y;

{
    DCOMPLEX z;

    z.re = x.re * y.re - x.im * y.im;
    z.im = x.im * y.re + x.re * y.im;

    return(z);
}

```

```

/*****
*
* SOURCE FILE:   harmonl.c
*
* FUNCTION:     main()
*
* DESCRIPTION:  This program is used to find the
*              location of harmonics in the DFT window.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   None.
*
* RETURN:      ascii file containing 20 * log10 of the
*              frequency data.
*
* FUNCTIONS
* CALLED:      fft(x,y,n,inverse)
*              DCOMPLEX *x,*y;
*              int n,inverse
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 6-15-87
*
* REVISIONS:   6-23-87 Threw out Doerfler's algorithm
*                  and used my own.
*
*****/

```

```

#include <stdio.h>
#include <conio.h>
#include <math.h>
#include "cmath.h"
#include "complex.h"
#include "local.h"

DCOMPLEX x[NUM_DFT_POINTS];
DCOMPLEX y[NUM_DFT_POINTS];
DCOMPLEX z[NUM_DFT_POINTS];

double freqs[NUM_DFT_POINTS];

main()
{
    char out_filename[STRING_LEN + 1];

    int inverse=DFT_N;
    int n;
    int act_len;
    int i,j;

```



```

float inp_float;

double ampli,
       delta,
       frequency,
       fund_freq,
       max_mag,
       samp_freq,
       w;

FILE *out_file;

puts("Enter the frequency of sine wave desired.");
scanf("%f",&inp_float);
frequency = (double)inp_float;
printf("frequency = %f\n\n",frequency);

puts("Enter the sampling frequency.");
scanf("%f",&inp_float);
samp_freq = (double)inp_float;
printf("samp_freq = %f\n\n",samp_freq);

puts("Enter the number of points desired.");
scanf("%i",&n);
printf(" n = %i\n\n",n);

w = TWOPI * frequency / samp_freq;

for ( j = 1; j < 10; j++ )
{
    printf("%i ",j);
    ampli = pow( (double)10.0, (double)(1-j) );
    for ( i = 0; i < n; i++ )
    {
        x[i].re = x[i].re + ampli
                * sin( j * w * i );
        x[i].im = 0.0;
    }
}

/* Window data. */

puts(" ");
puts("Windowing data.");
window_data(y,act_len);

/* Perform Fast Fourier Transform. */

puts("Performing FFT");

act_len = fft(x,y,n,inverse);

```

```

printf("Actual length = %i\n",act_len);

puts("Finding magnitude");
max_mag = 0.0;

/* Find the magnitude of frequency data. */
for ( i = 0; i < act_len; i++ )
{
    y[i].re = cmag( y[i] );

    if( y[i].re < 1e-300 )
        y[i].re = 1e-15;

    if ( y[i].re >= max_mag )
        max_mag = y[i].re;

    y[i].im = 0.0;
}

/* Convert results to dBs. */
puts("Finding dBs.\n");

fund_freq = samp_freq / act_len;

for ( i = 0; i < act_len; i++ )
{
    y[i].re = 20.0 * log10(y[i].re / max_mag);
    freqs[i] = fund_freq * i;
}

/* Write out information to a data file. */
puts("Enter the output data filename.");
scanf("%s",out_filename);

out_file = fopen(out_filename,"w");

fprintf(out_file,"%s %iHz \n",out_filename,
        (int)samp_freq);

for( i = 0; i < act_len/2; i++ )
    fprintf(out_file,"%f %f\n",freqs[i],y[i].re);

fclose(out_file);

exit(0);
}

```

```

/*****
*
* SOURCE FILE:   qntz1.c
*
* FUNCTION:     main()
*
* DESCRIPTION:  This program is used to find the spectrum
*              of an ideal ADC.
*
* DOCUMENTATION
* FILES:       None.
*
* ARGUMENTS:   None.
*
* RETURN:      ascii file containing 20 * log10 of the
*              frequency data.
*
* FUNCTIONS
* CALLED:      fft(x,y,n,inverse)
*              DCOMPLEX *x,*y;
*              int n,inverse
*              window ( x,n )
*              DCOMPLEX *x;
*              int n;
*
* AUTHOR:      Jeffrey C. Daniels
*
* DATE CREATED: 7-15-87
*
* REVISIONS:   Created from datgen.c.
*
*****/

```

```

#include <stdio.h>
#include <conio.h>
#include <math.h>
#include "cmath.h"
#include "complex.h"
#include "local.h"

DCOMPLEX x[NUM_DFT_POINTS],
          y[NUM_DFT_POINTS],
          z[NUM_DFT_POINTS];

double freqs[NUM_DFT_POINTS];

```

```

main()
{
    char out_filename[STRING_LEN + 1];

    int inverse=DFT_N;
    int n;
    int act_len;
    int i,num_bits;
    float inp_float;

    double ampli,
           frequency,
           fund_freq,
           lsb,
           max_mag,
           samp_freq,
           vhigh,vlow,
           w;

    FILE *out_file;

    puts(" ");
    puts("Enter the number of bits of the ADC");
    scanf("%i",&num_bits);
    printf("Number of bits = %i\n\n",num_bits);

    puts("Enter the high reference voltage");
    scanf("%f",&inp_float);
    vhigh = (double)inp_float;
    printf("High reference voltage = %f\n\n",vhigh);

    puts("Enter the low reference voltage");
    scanf("%f",&inp_float);
    vlow = (double)inp_float;
    printf("Low reference voltage = %f\n\n",vlow);

    puts("Enter the frequency of sine wave desired.");
    scanf("%f",&inp_float);
    frequency = (double)inp_float;
    printf("frequency = %f\n\n",frequency);

    puts("Enter the sampling frequency.");
    scanf("%f",&inp_float);
    samp_freq = (double)inp_float;
    printf("samp_freq = %f\n\n",samp_freq);

    puts("Enter the number of points desired.");
    scanf("%i",&n);
    printf(" n = %i\n\n",n);

    ampli = ( vhigh - vlow ) / 2.0;
    w = TWOPI * frequency / samp_freq;

```

```

lsb = ( vhigh - vlow )
      / pow( (double)2.0,(double)num_bits);

for ( i = 0; i < n; i++ )
{
  x[i].re = ampli * sin( w * i );
  x[i].im = 0.0;
}

/* Quantize data to NUM_BITS. */

puts("Quantizing data");
for ( i = 0; i < n; i++ )
  y[i].re = lsb * floor( x[i].re / lsb );

/* Window data. */

puts("Windowing data");
window_data ( y, n );

/* Perform Fast Fourier Transform. */

puts("Performing FFT");

act_len = fft(y,y,n,inverse);
printf("Actual length = %i\n",act_len);

puts("Finding magnitude");

max_mag = 0.0;

/* Find the magnitude of frequency data. */

for ( i = 0; i < act_len / 2; i++ )
{
  y[i].re = cmag( y[i] );

  if( y[i].re < 1e-7 )
    y[i].re = 1e-7;

  if ( y[i].re > max_mag )
    max_mag = y[i].re;

  y[i].im = 0.0;
}

/* Convert results to dBs. */

puts("Finding dBs.\n");

fund_freq = samp_freq / act_len;

```

```

for ( i = 0; i < act_len / 2; i++ )
{
    y[i].re = 20.0 * log10(y[i].re / max_mag);
    freqs[i] = fund_freq * i;
}

/* Write out information to a data file.          */
puts("Enter the output data filename.");
scanf("%s",out_filename);

out_file = fopen(out_filename,"w");

fprintf(out_file,"%s %iHz %i bits\n",
        out_filename,(int)samp_freq,num_bits);

for( i = 0; i < act_len / 2; i++ )
    fprintf(out_file,"%f %f %i\n",
            freqs[i],y[i].re,i);

fclose(out_file);

exit(0);
}

```

```

/*****
*
* SOURCE FILE:   local.h
*
* FUNCTION:      include file
*
* DESCRIPTION:   This file is an include file containing
*                various definitions used in many
*                functions.
*
* DOCUMENTATION
* FILES:         None.
*
* ARGUMENTS:     None.
*
* RETURN:        None.
*
* FUNCTIONS
* CALLED:        None.
*
* AUTHOR:        Jeffrey C. Daniels
*
* DATE CREATED:  6-3-87
*
* REVISIONS:     None.
*
*****/

```

```

#ifndef _local
#define _local

#define FALSE 0
#define TRUE 1
#define NO 0
#define YES 1

#define VOID void
#define FOREVER for(;;)

#define PI 3.141592653589793
#define TWOPI 6.283185307179586
#define RADDEG 0.017453292519943
#define DEGRAD 57.29577951308232

#define DFT 0 /* Forward DFT with multiplier of 1.0 */
#define DFT_N 1 /* Forward DFT with multiplier of 1.0/N */
#define IDFT 2 /* Inverse DFT with multiplier of 1.0 */
#define IDFT_N 3 /* Inverse DFT with multiplier of 1.0/N */

#define NUM_DFT_POINTS 4096
#define NUM_HIS_POINTS 327680

```

```
#define LOOP_SIZE      4096

#define STRING_LEN     80
#define CHIP_NO_LEN    20
#define DATE_LEN       8
#define MODE_LEN       2
#define LOT_NO_LEN     3

#define PORTA          0x380 /* Ports on IBM PCXT Metrabyte */
#define PORTB          0x381 /* Board */
#define PORTC          0x382
#define CONTROL        0x383
#define PPI_CONFIG    0xb6

#define VHIGH          5
#define VLOW           0
#define NUM_BITS       8
#define RESOLUTION     256

/* Funtion definitions. */
VOID window_data();
VOID normalize_data();

int fft();

#endif
```



```

/*****
*
* SOURCE FILE:   cmath.h
*
* FUNCTION:      include file
*
* DESCRIPTION:   This file is an include file containing
*                the definitions for the functions
*                involving COMPLEX numbers.
*
* DOCUMENTATION
* FILES:         None.
*
* ARGUMENTS:     None.
*
* RETURN:        None.
*
* FUNCTIONS
* CALLED:        None.
*
* AUTHOR:        Jeffrey C. Daniels
*
* DATE CREATED:  6-2-87
*
* REVISIONS:     None.
*
*****/

```

```

#ifndef _cmath
#define _cmath

#include "complex.h"

DCOMPLEX cadd();
DCOMPLEX csub();
DCOMPLEX cmult();
DCOMPLEX cdiv();
DCOMPLEX cmplx();
DCOMPLEX cexpon();
DCOMPLEX cneg();

double cmag();
double cmagsq();
double cphase();
double cphased();

#endif

```

```

/*****
*
* SOURCE FILE:   complex.h
*
* FUNCTION:      include file
*
* DESCRIPTION:   This file is an include file containing
*                the definitions for the DCOMPLEX data
*                structure. A DCOMPLEX number is just
*                a double precision complex.
*
* DOCUMENTATION
* FILES:         None.
*
* ARGUMENTS:     None.
*
* RETURN:        None.
*
* FUNCTIONS
* CALLED:        None.
*
* AUTHOR:        Jeffrey C. Daniels
*
* DATE CREATED:  6-2-87
*
* REVISIONS:     None.
*
*****/

#ifndef _dcomplex
#define _dcomplex

typedef struct dcomplex
{
    double re,
           im;
} DCOMPLEX;

#endif

```

Appendix C

End Point Transition Procedure^{3,7}

This procedure is an alternative to the histogram procedure for calculating integral non-linearity errors from a line that passes through the first and last transitions for the actual transfer function for an analog to digital (A/D) converter.

The following transfer function for an ideal, three bit, unipolar A/D is:

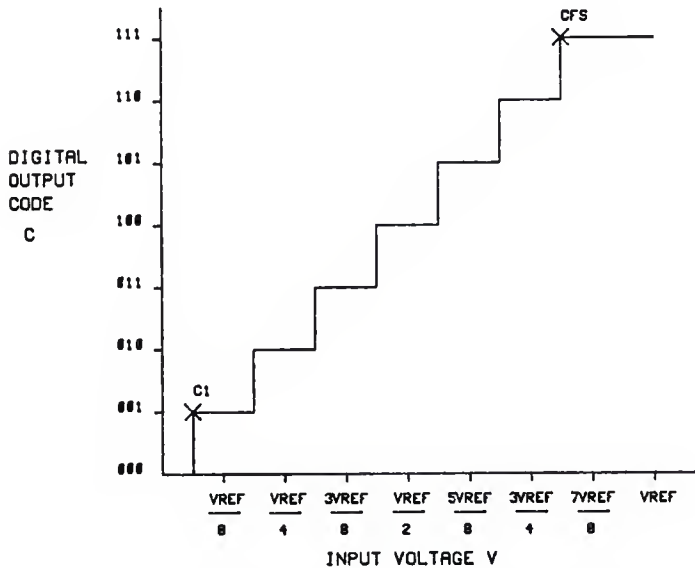


Figure C-1. Transfer function for an ideal 3-bit A/D.

where:

$$V_{LSB} = V_{ref}/2^n,$$

and two measurable points with the coordinates are:

$$C_1 - \text{first A/D transition} \\ = (001, V_{\text{ref}}/16) \text{ or } (001, V_{\text{ref}}/2^{n+1})$$

$$C_{\text{FS}} - \text{last A/D transition} \\ = (111, 13V_{\text{ref}}/16) \text{ or } (2^n - 1, V_{\text{ref}} - 3V_{\text{ref}}/2^{n+1})$$

Transition voltages occur at

$$V_{\text{tran}} = (V_{\text{ref}}/2^{n+1}) (2i - 1) \text{ for } i = 1, 2, \dots, 2^{n-1}$$

The equation of the line through C_1 and C_{FS} for an ideal A/D with some point (C, V) on the transfer function is:

$$\frac{C - C_{\text{FS}}}{C_{\text{FS}} - C_1} = \frac{V - V_{\text{FS}}}{V_{\text{FS}} - V_1}$$

or

$$\frac{C - 2^n + 1}{2^n - 2} = \frac{V - V_{\text{ref}} + (3/2^{n+1}) V_{\text{ref}}}{V_{\text{ref}} - (3/2^{n+1}) V_{\text{ref}} - V_{\text{ref}}/2^{n+1}}$$

manipulating, if true endpoints, we can obtain:

$$\frac{C - 2^n + 1}{2(2^{n-1} - 1)} = \frac{V - 2^{n+1} - V_{\text{ref}}2^{n+1} + 3V_{\text{ref}}}{V_{\text{ref}}2^{n+1} - 3V_{\text{ref}} - V_{\text{ref}}} \\ = \frac{V2^{n+1}/V_{\text{ref}} - 2^{n+1} + 3}{2^{n+1} - 4}$$

$$\frac{C - 2^n + 1}{2(2^{n-1} - 1)} = \frac{V2^{n+1}/V_{\text{ref}} - 2^{n+1} + 3}{4(2^{n-1} - 1)}$$

$$C - 2^n + 1 = V2^{n+1}/2V_{\text{ref}} - 2^{n+1}/2 + 3/2$$

This must equal the non-ideal equation. Therefore,

$$\frac{a}{V_{\text{LSB}}} = \frac{C_{\text{FS}} - C_{\text{F}}}{V_{\text{FS}} - V_{\text{F}}} \quad \text{---->} \quad a = V_{\text{LSB}} \frac{C_{\text{FS}} - C_{\text{F}}}{V_{\text{FS}} - V_{\text{F}}}$$

and

$$\frac{B}{V_{\text{LSB}}} + \frac{1}{2} = \frac{V_{\text{FS}}C_{\text{F}} - V_{\text{F}}C_{\text{FS}}}{V_{\text{FS}} - V_{\text{F}}}$$

yields:

$$B = \frac{V_{\text{FS}}C_{\text{F}} - V_{\text{F}}C_{\text{FS}}}{V_{\text{FS}} - V_{\text{F}}} - \frac{1}{2} V_{\text{LSB}}$$

Thus, all voltages obtained in taking ramp data must be multiplied by a and have B added to them. This adjustment of the voltage removes gain and offset errors to from the data to then be used to calculate integral non-linearity errors at the transition points by the following equation:

$$\text{IN}(i) = \frac{V_{\text{t}}(i) - [V_{\text{t}}(1) + (i-1)(\text{LSB})]}{\text{LSB}} \quad \text{LSB}$$

where:

$$i = 0, 1, 2, \dots, 2^n - 1$$

$$\text{and } \text{LSB} = V_{\text{ref}}/2^n$$

The voltages corresponding to the transition points are found by searching the A/D conversion results for a transition and then integral non-linearity errors are calculated. These voltages cannot be found if the A/D conversion results have areas of non-monotonic behavior. The simple search for a transition will not yield a true transition point because of the non-monotonic behavior.

References

1. Motorola Technical Data Advance Information: MC68HC11A8 HCMOS Single-Chip Microcomputer, (Phoenix, AZ: Motorola Literature Distribution, 1985).
2. Douglas W. Doerfler, "Techniques for Testing a 15-Bit Data Acquisition System," (MS Thesis, Department of Computer and Electrical Engineering, Kansas State University, 1985).
3. Analog Devices, Analog-Digital Conversion Handbook, (Englewood Cliffs, NJ: Prentice-Hall, Inc., 1986).
4. Steven Douglas Draving, "An Evaluation of the MC68HC11A8 Single-Chip Microcomputer as a Controller for Low-Power, Precision A/D Converters," (MS Thesis, Department of Computer and Electrical Engineering, Kansas State University, 1987).
5. Motorola, "M68HC11EVB Evaluation Board User`s Manual", (First Edition, Copyright 1986 by Motorola, Inc.).
6. Dave Holdeman, "Precision Voltage Reference," (Research Report, Kansas State University, Department of Computer and Electrical Engineering, Project No. 2845, December 14, 1984).
7. Dr. Donald H. Lenhart, "Personal Research Notes for Motorola Project", (Nov. 7,1987, pp. 13-16).

The Static and Dynamic Characterization
of the MC68HC11A8's Analog to Digital Converter

by

Jeffrey Charles Daniels

B.S., Kansas State University, 1984

AN ABSTRACT OF A MASTER'S THESIS

submitted in partial fulfillment of the
requirements for the degree

MASTER OF SCIENCE

Department of Electrical and Computer Engineering

KANSAS STATE UNIVERSITY
Manhattan, Kansas

1988

Abstract

The Motorola MC68HC11A8 (HC11) is a high speed, low power microcomputer with an onboard eight channel, multiplexed input, successive approximation analog to digital converter (A/D) with sample and hold. This A/D system is clocked by the HC11's E clock or by an internal RC timer. This thesis presents three static and two dynamic testing methods used to test the A/D in different configurations with the RC timer enabled and disabled and at different E clock frequencies.

Several different lots of HC11s from the mask of B96D were tested and three problems were discovered. These problems include isolated cases of errors induced by pattern sensitivity, consistent constant offsets when the A/D is operated in various operational modes, and the problem of large errors being induced when the A/D is clocked by its internal RC timer. All of the errors discovered in dynamic tests had been previously found using static tests indicating that no large scale dynamic sensitivities exist for this mask.